Safety Manual for RM57x Hercules ARM Safety MCUs

User's Guide



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Safety Manual for RM57x Hercules ARM Safety MCUs

1 Introduction

You, a system and equipment manufacturer or designer, are responsible to ensure that your systems (and any TI hardware or software components incorporated in your systems) meet all applicable safety, regulatory, and system-level performance requirements. All application and safety related information in this document (including application descriptions, suggested safety measures, suggested TI products, and other materials) is provided for reference only. You understand and agree that your use of TI components in safety critical applications is entirely at your risk, and that you (as buyer) agree to defend, indemnify, and hold harmless TI from any and all damages, claims, suits, or expense resulting from such use.

This document is a safety manual for the Texas Instruments Hercules safety critical microcontroller product family. The product family utilizes a common safety architecture that is implemented in multiple application focused products. Product configurations supported by this safety manual include silicon revisions A and B of the following products: (Note that the part numbers listed below are for revision B; other revisions are slightly different. The device revision can be determined by the symbols marked on the top of the device as seen in Figure 1 below this list).

- RM4xx Safety Critical Microcontrollers
  - RM57L843-ZWT (Orderable Part #: RM57L843BZWTT)
  - RM57L843-ZWT (Orderable Part #: RM57L843BZWTTR)

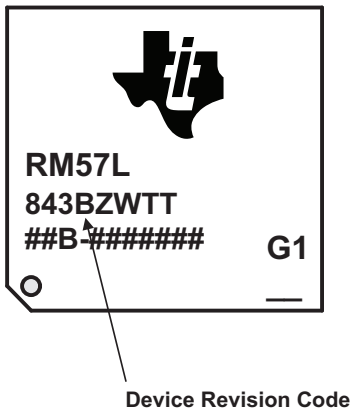


Figure 1. Device Revision Code Identification

This Safety Manual provides information needed by system developers to assist in the creation of a safety critical system using a supported Hercules microcontroller. This document contains:

- An overview of the superset product architecture
- An overview of the development process utilized to reduce systematic failures
- An overview of the safety architecture for management of random failures
- The details of architecture partitions, implemented safety mechanisms

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The following information is documented in the *Safety Analysis Report Summary for RM57x ARM®-Based Safety Critical Microcontrollers* (SPNU578) and is not repeated in this document:

- Summary of failure rates of the MCU estimated at the chip level
- Assumptions of use utilized in calculation of safety metrics
- Summary of targeted standard (IEC 61508, ISO 26262, and so forth) safety metrics at the chip level

The following information is documented in the *Detailed Safety Analysis Report for RM57x ARM®-Based Safety Critical Microcontrollers* (SPNU579) and is not repeated in this document:

- Fault model used to estimate device failure rates suitable to enable calculation of customized failure rates
- Quantitative FMEA (also known as FMEDA, Failure Modes, Effects, and Diagnostics Analysis) with detail to the sub-module level of the device, suitable to enable calculation based on customized application of diagnostics

The following information is documented in the *Safety Report*, and will not be repeated in this document:

- Results of assessments of compliance to targeted standards

The user of this document should have a general familiarity with the Hercules product families. For more information, see http://www.ti.com/hercules. This document is intended to be used in conjunction with the pertinent data sheets, technical reference manuals, and other documentation for the products under development.

For information which is beyond the scope of the listed deliverables, please contact your TI sales representative or http://www.ti.com.

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2 Hercules RM57x Product Overview

The RM57x 65 nm Hercules product family is an evolution of the proven TMS570LS Hercules products in the 65 nm manufacturing process. A simplified graphical view of the product superset architecture can be seen in Figure 2. This is a basic representation of the architecture and is not all inclusive. For example, products in the family may scale based on the number of peripherals, number of bus master peripherals, or amount of memory - but the programmer's model remains consistent.

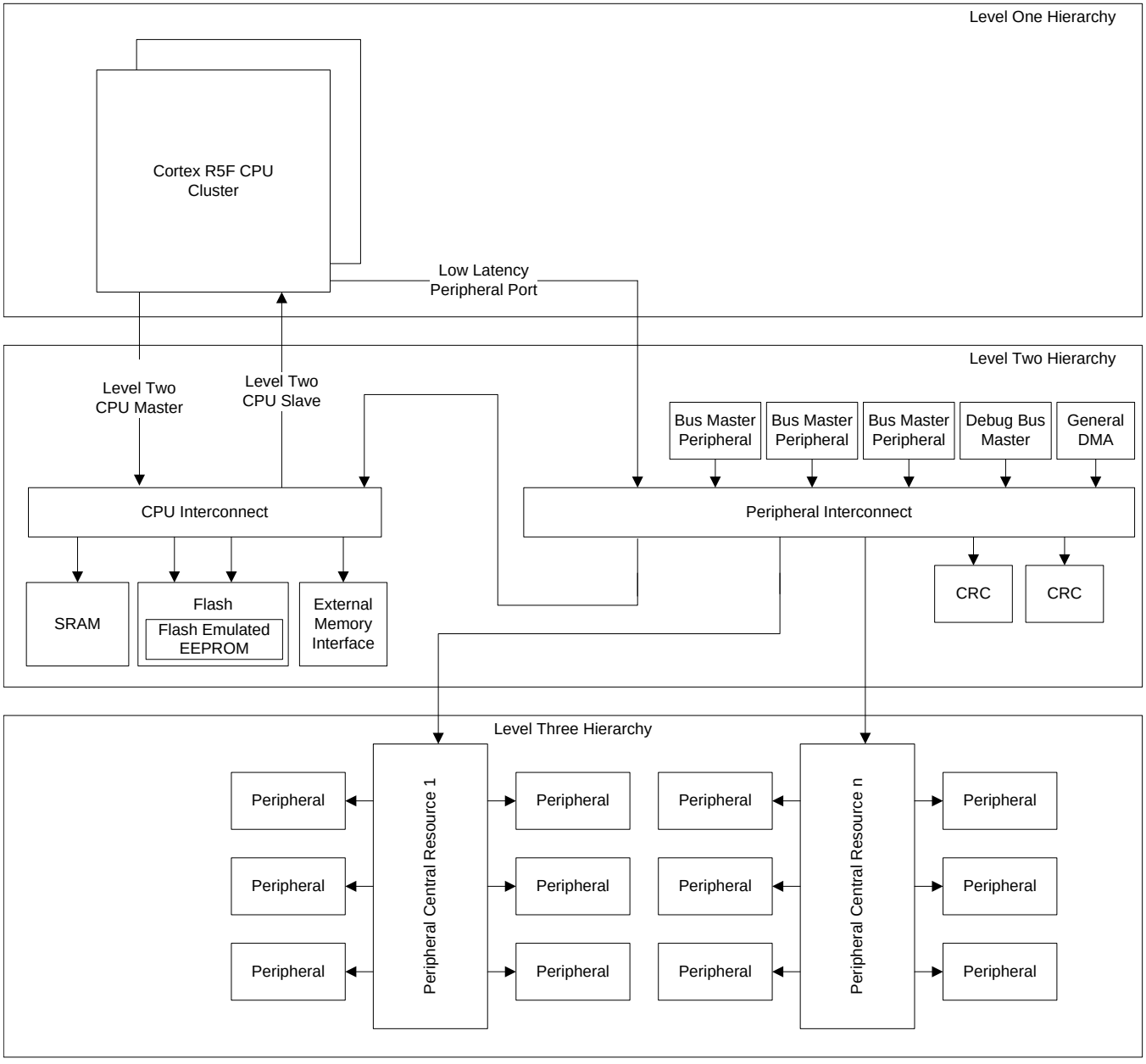


Figure 2. Hercules Product Architecture Overview

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The Hercules product architecture utilizes the ARM Cortex®-R5F CPU in a cached memory configuration with both instruction and data caches. The Cortex-R5F CPU is implemented with a checker Cortex-R5F CPU in a lockstep configuration. This provides cycle by cycle checking of correct CPU operation while keeping a simple, easy to use, single core programmer's model. The Cortex R5F CPU has a multi-threaded level two bus master interface, which provides access to the level two memory hierarchy, supporting up to seven concurrent CPU accesses in flight. A level two slave interface allows bus masters access to the level one cache memories for test, debug, and fault insertion purposes. A separate low latency peripheral port provides access to peripherals. In addition, a Snoop Control Unit (SCU) module is present to snoop non-CPU bus master accesses for the purpose of I/O cache coherency.

The level two device hierarchy is dominated by two switched central resource interconnect modules (also known as bus matrices or crossbars): CPU Interconnect Subsystem and Peripheral Interconnect Subsystem. These device level interconnect modules allow multiple bus masters to access multiple bus slaves. Prioritization, routing, decode, and arbitration functions are provided. Access to the memory subsystem (Flash, FEE, SRAM, and EMIF) is provided via the CPU Interconnect Subsystem. Peripherals are accessed via the Peripheral Interconnect Subsystem and multiple level three peripheral interconnect segments (PCR1, PCR2, and PCR3). Bus masters to the level two device hierarchy include CPUs, bus master peripherals, debug bus masters, and general purpose direct memory access (DMA) controllers. Bus slaves on the level two hierarchy include the primary Flash memory, primary SRAM, Flash EEPROM emulation memory, and external memory interface (EMIF), one or more peripheral bus segments (PCRs), and Cortex-R5F slave port access..

The level three hierarchy is primarily composed of peripherals. Peripherals are grouped into one or more peripheral bus segments (PCRs), managed by a peripheral central resource. The peripheral central resource provides address decode functionality for bus transactions targeting peripherals.

2.1 Targeted Applications

The Hercules MCU family is targeted at general purpose safety applications. Multiple safety applications were analyzed during the concept phase. Example target applications include:

- Automotive braking systems, including anti-lock braking (ABS), anti-lock braking with traction control (ABS+ TC), and electronic stability control (ESC)
- Motor control systems, particularly electronic power steering (EPS) systems and electric vehicle (EV) power train
- General purpose safety computation, such as integrated sensor cluster processing and vehicle strategy generation in an active safety system
- Industrial automation such as programmable logic controllers (PLCs) and programmable automation controllers (PACs) for safety critical process control

In the case of overlapping requirements between target systems, TI has attempted to design the device respecting the most stringent requirements. For example, the fault tolerant time intervals for timer logic in an ESC application are typically on the order of 100 ms. In an EPS application, the fault tolerant time interval is typically on the order of 10 ms. In such case, TI has performed timer subsystem analysis respecting <10 ms fault tolerant time interval.

While TI considered certain applications during the development of these devices, this should not restrict a customer who wishes to implement other systems. With all safety critical components, rationalization of the component safety concept to the system safety concept should be executed by the system integrator.

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2.2 Product Safety Constraints

This device is a Type B device, as defined in IEC 61508:2010

This device claims no hardware fault tolerance (HFT = 0), as defined in IEC 61508:2010

For safety components developed according to many safety standards, it is expected that the component safety manual will provide a list of product safety constraints. For a simple component, or more complex components developed for a single application, this is a reasonable response. However, the Hercules product family is both a complex design and is not developed targeting a single, specific application. Therefore, a single set of product safety constraints cannot govern all viable uses of the product. The *Detailed Safety Analysis Report for RM57x ARM®-Based Safety Critical Microcontrollers* (SPNU579) provides a reference implementation of the Hercules product in a common system with relevant product safety constraints.

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3 Hercules Development Process for Management of Systematic Faults

For a safety critical development, it is necessary to manage both systematic and random faults. Texas Instruments has created a unique development process for safety critical semiconductors that greatly reduces probability of systematic failure. This process builds on a standard Quality Managed (QM) development process as the foundation for safety critical development. This process is then augmented by a second layer of development activities that are specific to safety critical developments targeting IEC 61508.

In 2007, TI first saw the need to augment this standard development process in order to develop products according to IEC 61508. TI engaged with safety industry leader exida consulting to ensure the development was compliant to the standard. During 2008, a process for safety critical development according to IEC 61508 1st edition was implemented. This process has been executed on multiple microcontroller developments that are currently shipping into safety critical systems. The Hercules family product and safety architectures described in this document began development under the IEC 61508 development flow.

By mid 2009, it became clear that the emerging IEC 61508 2nd edition functional safety standards would require enhanced process flow capabilities. Due to the lack of maturity of these draft standards, it was not possible to implement a development process that ensured compliance before final drafts were available.

In mid 2010, TI started development of a process flow compliant to IEC 61508 2nd edition. TI worked in detail with Yogitech and found that the companies have complementary capabilities. A partnership was established for engineering services and safety consulting services to accelerate new safety-related product development. Yogitech's existing fRMethodology development process and TI's IEC 61508 development process were merged and enhanced to create a new process addressing IEC 61508 2nd edition.

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3.1 TI Standard MCU Automotive Development Process

Texas Instruments has been developing automotive microcontrollers for safety critical and non-safety critical automotive applications for over twenty years. Automotive markets have strong requirements on quality management and high reliability of product. Though not explicitly developed for compliance to a functional safety standard, the TI standard MCU Automotive development process already features many elements necessary to manage systematic faults. This development process can be considered to be Quality Managed (QM), but does not achieve an IEC 61058 Safety Integrity Level (SIL). For up-to-date information on TI quality process certifications, see http://www.ti.com/quality.

The standard process breaks development into phases:

- Business opportunity pre-screen
- Program planning
- Create
- Validate, sample, and characterize
- Qualify
- Ramp to production and sustaining production

The standard process is illustrated in Figure 3.

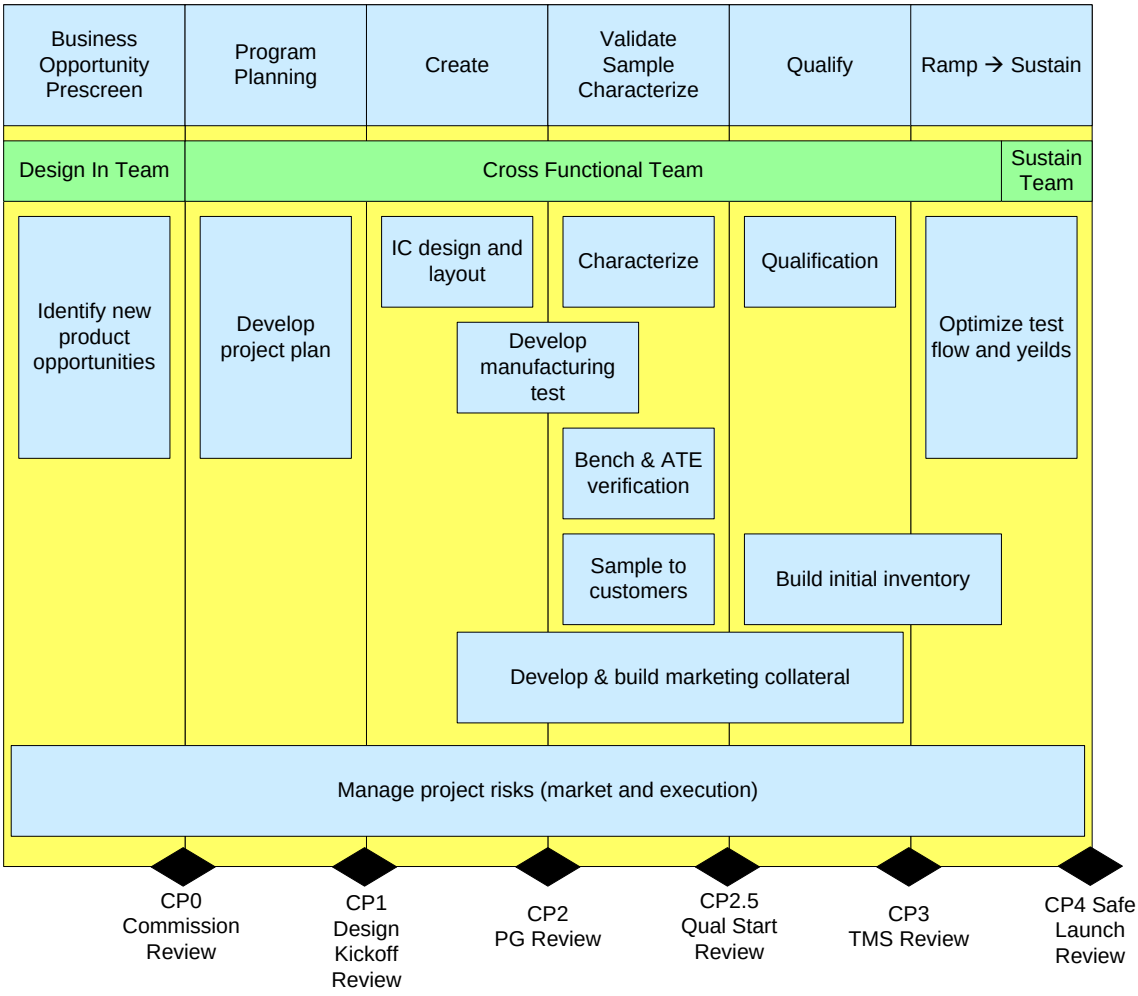


Figure 3. TI Standard MCU Automotive QM Development Process

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3.2 TI MCU Automotive Legacy IEC 61508 Development Process

Texas Instruments developed an initial process for developing safety critical automotive microcontrollers in 2008. This process was developed targeting the IEC 61508 1st edition standard, as augmented with available committee drafts of the 2nd edition. The process is developed as an additional layer of activities that should be carried out in addition to the standard MCU Automotive QM development process. This process as applied on the TMS570LS20216S product development has been assessed suitable for use in IEC 61508 SIL 3 applications by exida Certification S.A. (certificate TI 071227 C001). In July 2012 the development process and the TMS570LS20x/10x product family was assessed to the IEC 61508:2010 standard and certified suitable for use in IEC 61508 SIL 3 applications by exida Certification Services (certificate TI 1204073 C001).

Key new activities in this process included:

- Nomination of a safety manager with ownership of all safety related activities
- Development of a safety plan to track safety related activities
- Generation, application, and validation of safety requirements
- Execution of qualitative (FMEA) and quantitative (FMEDA) safety analysis
- Authoring of safety manual and safety analysis report to support customer development

3.3 Yogitech fRMethodology Development Process

fRMethodology is the “white-box” approach for safety design exploration proprietary of YOGITECH, including:

- fRFMEA, a methodology to perform the FMEA of an integrated circuit in accordance to IEC 61508
- fRFI, a tool to perform fault injection of an integrated circuit based on inputs derived from fRFMEA

YOGITECH’s fRMethodology mainly consists of:

- Splitting the component or system in elementary parts (“sensitive zones”)
- Computing their failure rates
- Using those failure rates to compute safety metrics
- Validating the results with fault injection
- Allowing sensitivity analyses of those metrics by changing architectural or technological parameters
- Delivering to the customer numbers to compare different architectures

3.4 Hercules Enhanced Safety Development Process

The Hercules enhanced safety development process is a merger of the existing TI and Yogitech flows for functional safety development. The goal of the process development is to take the best aspects of each flow and collaborate, resulting in the best in class capabilities to reduce systematic faults.

The process flow is targeted for compliance to IEC 61508, and is under a process of continuous improvement to incorporate new features of emerging functional safety standards. These functional safety standards are targeted because TI and Yogitech believe they best represent the state of the art in functional safety development for semiconductors. While not directly targeted at other functional safety standards, it is expected that products developed to industry state-of-the-art can be readily utilized in other functional safety systems.

The resulting flow was subsequently assessed by TUEV SUED for compliance to IEC 61508 and ISO 26262 and further enhanced based on technical findings. The development flow is certified by TUEV SUED under certificate Q4B 13 03 84071 001.

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Key elements of the combined process flow are:

- Assumptions on system level design, safety concept, and requirements based on TI's expertise in safety critical systems development
- Combined qualitative and quantitative or similar safety analysis techniques comprehending the sum of silicon failure modes and diagnostic techniques known to both TI and Yogitech
- Fault estimation based on multiple industry standards as well as TI manufacturing data
- Application of Yogitech's state-of-the-art fault injection techniques for validation of claimed diagnostic coverage
- Integration of lessons learned by both companies through multiple safety critical developments to IEC 61508

The Figure 4 is shown below in a simplified graphic.

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Phase 0 Business Opportunity Prescreen	Phase 1 Program Planning	Phase 2 Create	Phase 2.5 Validate, Sample, and Characterize	Phase 3 Qualify	Phase 4 Ramp/Sustain
Determine if safety process execution is necessary	Define SIL/ASIL capability	Execute safety design	Validate safety design in silicon	Qualification of safety design	Implement plans to support operation and production
Execute development interface agreement (DIA) with lead customers and suppliers	Generate safety plan	Qualitative analysis of design (FMEA and FTA)	Release safety manual	Release safety case report	Update safety case report (if needed)
	Initiate safety case	Incorporate findings into safety design	Release safety analysis report	Update safety manual (if needed)	Periodic confirmation measure reviews
	Analyze system to generate system level safety assumptions and requirements	Develop safety product preview	Characterization of safety design	Update safety analysis report (if needed)	
	Develop component level safety requirements	Validation of safety design at RTL level	Confirmation measure review	Confirmation measure review	
	Validate component safety requirements meet system safety requirements	Quantitative analysis of design (FMEDA)			
	Implement safety requirements in design specification	Incorporate findings into safety design			
	Validate design specification meets component safety requirements	Validation of safety design at gate/layout level			
	Confirmation measure review	Confirmation measure review			

Figure 4. Hercules Enhanced Functional Safety Development Process

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4 Hercules Product Architecture for Management of Random Faults

For a safety critical development it is necessary to manage both systematic and random faults. The Hercules product architecture includes many safety mechanisms, which can detect and respond to random faults when used correctly. This section of the document describes the architectural safety concept for the MCU.

4.1 Safe Island Philosophy and Architecture Partition to Support Safety Analysis (FMEA/FMEDA)

The RM4x Hercules processors share a common safety architecture concept called a “safe island” philosophy. The basic concept involves a balance between application of hardware diagnostics and software diagnostics to manage functional safety, while balancing cost concerns. In the “safe island” approach, a core set of elements are allocated continuously operating hardware safety mechanisms. This core set of elements, including power and clock and reset, CPU, Flash memory, SRAM and associated interconnect to Flash and SRAM, is needed to assure any functionally correct execution of software. Once correct operation of these elements is confirmed, software can be executed on these elements in order to provide software-based diagnostics on other device elements, such as peripherals. This concept has been proven viable through multiple generations of safety-critical products in the automotive passenger vehicle space.

Figure 5 illustrates the safe island approach overlaid to a superset configuration of the Hercules product architecture.

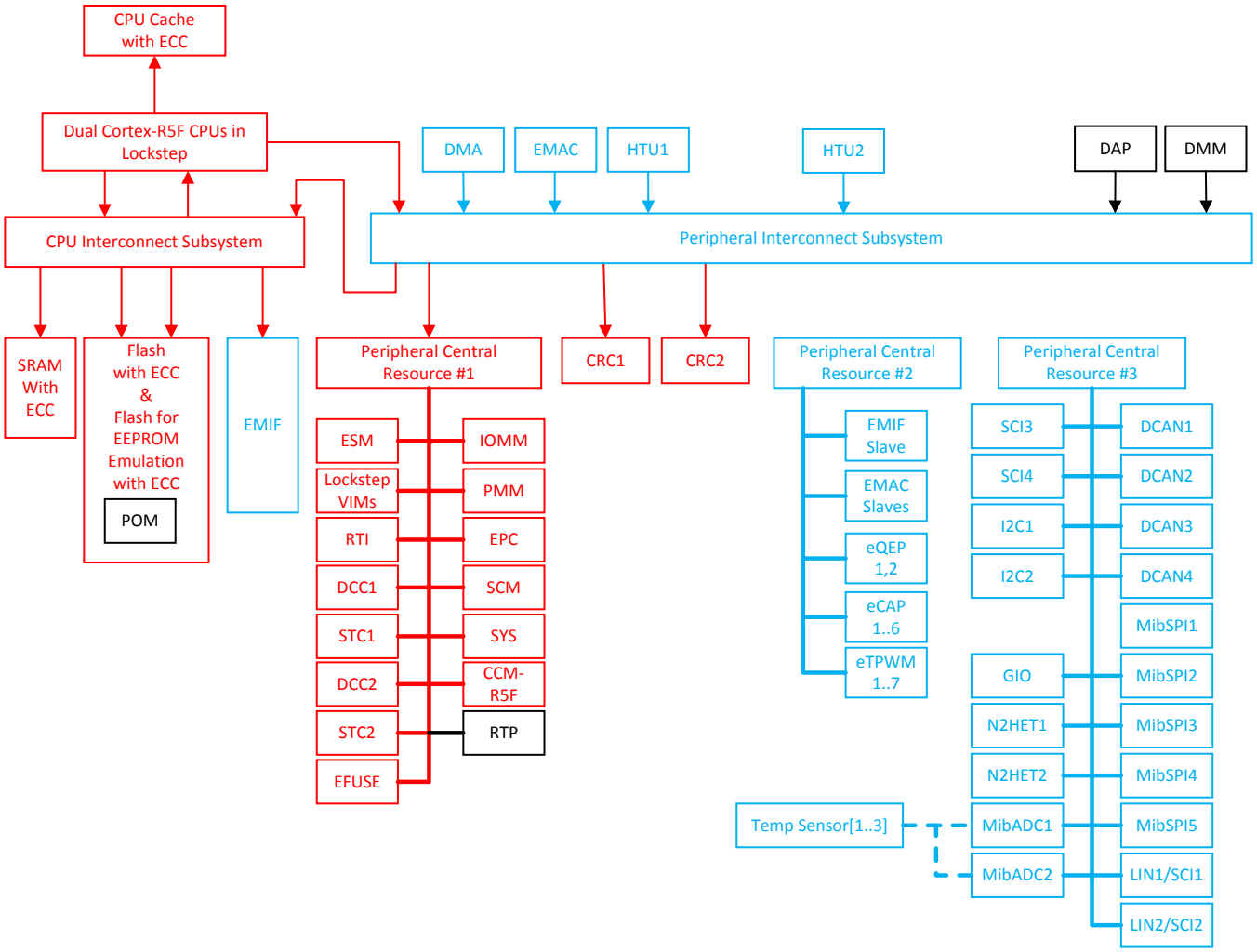


Figure 5. Partition of Hercules MCU for Safety Analysis

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Figure 5 illustrates three architectural partitions:

- “Safe Island Layer” (RED) – This is the region of logic that is needed for all processing operations. This logic is protected heavily by on board hardware diagnostics and specific assumptions of use to assure a high level of confidence in safe operation. Once this region is safed, it can be used to provide comprehensive software diagnostics on other design elements.
- “Blended Layer” (BLUE) – This is the region of logic that includes most safety critical peripherals. This region has less reliance on hardware diagnostics. Software diagnostics and application protocols are overlaid to provide the remainder of needed diagnostic coverage.
- “Offline Layer” (BLACK) – This region of logic has minimal or no integrated hardware diagnostics. Many features in this layer are used only for debug, test, and calibration functions; they are not active during safety critical operation. Logic in this region could be utilized for safety critical operation assuming appropriate software diagnostics or system level measures are added by the system integrator.

4.2 Identification of Parts/Elements

For the purposes of a safety analysis, each module on this device can be considered to be a part or element. Each part or element has been assigned a three letter unique identifier, which is used uniformly in the Safety Manual, Safety Analysis Report, and FMEDA Documents to identify the element and it's diagnostics. Table 1 lists each element present on this device and the unique identifier for this element. The overall IEC 61508 systematic capability of the MCU is SC3. TI does not make claims of systematic capability for specific IP modules on the device.

Table 1. Identification of Parts/Elements

Part / Element Name	Unique Identifier
Clock	CLK
Cortex-R5F Central Processing Unit (CPU)	CPU
Controller Area Network (DCAN)	CAN
Cortex-R5F Central Processing Unit (CPU) Debug and Trace	DBG
CPU Interconnect Subsystem	MEM
Data Modification Unit	DMM
Direct Memory Access (DMA)	DMA
Enhanced Capture (eCAP)	CAP
EFuse Static Configuration	EFU
External Memory Interface (EMIF)	EMF
Enhanced Pulse Width Modulators (ePWM)	PWM
Enhanced Quadrature Encoder Pulse (eQEP)	QEP
Error Profiling Controller	EPC
Error Signaling Module (ESM)	ESM
Ethernet	ETH
Flash EEPROM Emulation (FEE)	FEE
Primary Flash	FLA
General Purpose Input/Output (GIO)	GIO
Inter-Integrated Circuit (I2C)	IIC
Input/Output (I/O) Multiplexing Module (IOMM)	IOM
Joint Technical Action Group (JTAG) Debug/Trace/Calibration Access	JTG
Local Interconnect Network (LIN)	LIN
Multi-Buffered Analog to Digital Converter (MibADC)	ADC
Multi-Buffered Serial Peripheral Interface (MibSPI)	MSP
High-End Timer (N2HET) Including HET Transfer Unit (HTU)	HET
One Time Programmable (OTP) Flash Static Configuration	OTP
Peripheral Interconnect Subsystem	PER

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Table 1. Identification of Parts/Elements (continued)

Part / Element Name	Unique Identifier
Peripheral Central Resource 1	P1T
Peripheral Central Resource 2	P2T
Peripheral Central Resource 3	P3T
Power Management Module (PMM)	PMM
Parameter Overlay Module	POM
Power Supply	PWR
RAM Trace Port	RTP
Reset	RST
Real Time Interrupt (RTI) Operating System Timer	RTI
Serial Communications Interface (SCI)	SCI
SRAM	RAM
System Control Module	SYS
Temperature Sensors	TSN
Vectored Interrupt Module (VIM)	VIM

NOTE: The terms "element" and "part" may have specific meaning and imply specific requirements dependent on the targeted functional safety standard. The terms are used here in a general sense.

TheHercules Architecture Brief Description of Elements section contains a brief description of the elements listed above. For a full functional description of any of these modules, see the device-specific technical reference manual.

4.3 Management of Family Variants

The Hercules family architecture supports multiple product variants. These products could be implemented as unique silicon designs or they can be shared silicon designs that have elements disabled or not assured by specification, even if present in silicon. Only the elements of the superset architecture that are specifically detailed in the device-specific data sheet and technical reference manual are assured to be present and operate. When developing for the Hercules platform, it is recommended that the safety concept be based on the superset product architecture to enable maximum scalability across family variants. The superset architecture shown in the previous section is valid for all device part numbers noted in the introduction of the safety manual.

4.4 Operating States

The Hercules MCU products have a common architectural definition of operating states. These operating states should be observed by the system developer in their software and system level design concepts. The operating states state machine is shown in Figure 6 and described below.

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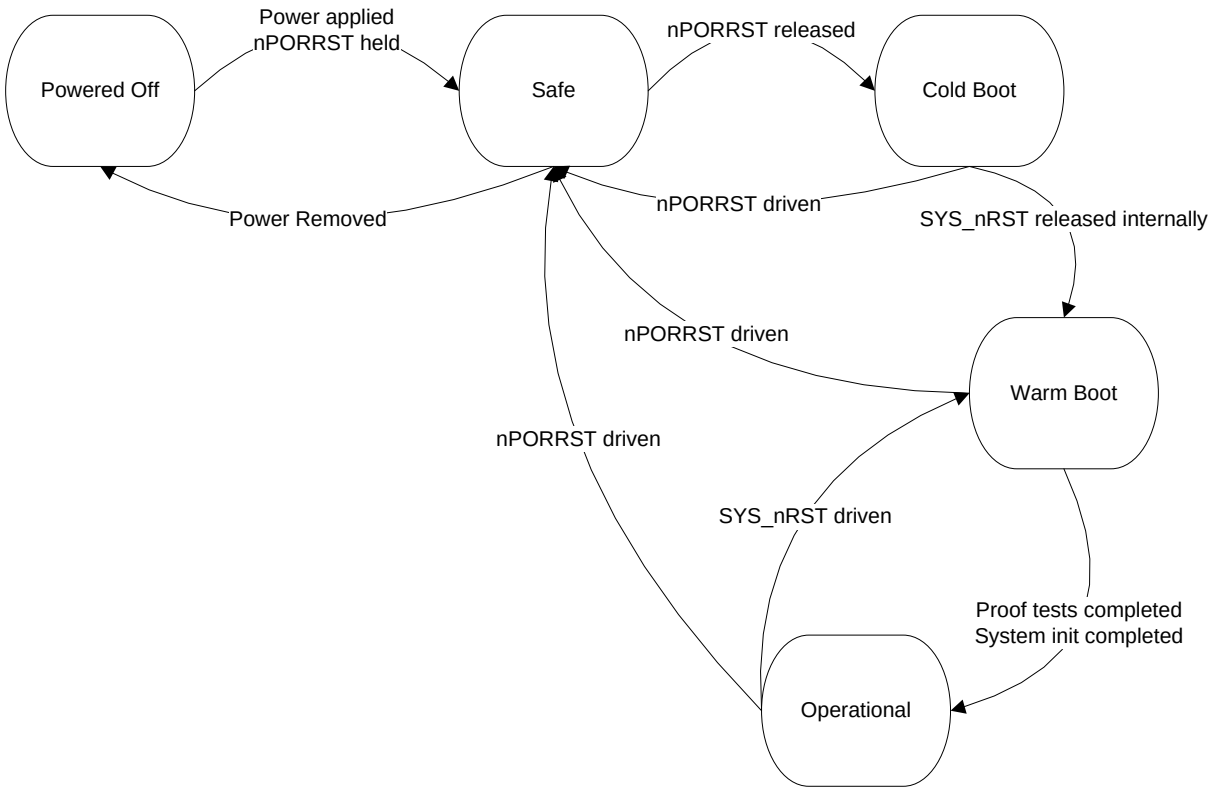


Figure 6. Operating States of the Hercules MCU

- "Powered Off" - This is the initial operating state of the Hercules MCU. No power is applied to either core or I/O power supply and the device is non-functional. This state can only transition to the safe state, and can only be reached from the safe state.
- "Safe" - In the safe state, the Hercules MCU is powered but non-operational. The nPORRST (power-on reset, also known as cold reset) is asserted by the system but is not released until power supplies have ramped to a stable state. The internal voltage monitor (VMON) safety mechanism also continues to assert the nPORRST internal to the device if power supplies are not within a minimum operational range. When the product is in the safe state, the CPU and peripherals are non-functional. Output drivers are tri-stated and input/output pins are kept in an input only state.
- "Cold Boot" - In the cold boot state, key analog elements, digital control logic, and debug logic are initialized for future use. The CPU remains powered but non-operational. When the cold boot process is completed, the SYS_nRST signal is internally released, leading to the warm boot stage. The SYS_nRST signal transition change can be monitored externally on the SYS_nRST I/O pin.
- "Warm Boot" - The warm boot mode resets digital logic and enables the CPU. The CPU begins executing software from Flash memory and software initialization of the device can begin. There is no hardware interlock to say that warm boot is completed; this is a software decision.
- "Operational" - During the operational mode, the device is capable of supporting safety critical functionality.

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4.5 Management of Errors

When a diagnostic detects a fault, the error must be indicated. The Hercules product architecture provides aggregation of fault indication from internal safety mechanisms using a peripheral logic known as the error signaling module (ESM). The ESM provides mechanisms to classify errors by severity and to provide programmable error response. The ESM does not, in and of itself, impact the overall function of the device and serves the limited purpose of fault aggregation and classification. The error classifications in the ESM are summarized in Table 2.

Table 2. Summary of ESM Error Indication

Error Group	Interrupt Response	Error Pin Response	Notes
1	Programmable interrupt and programmable interrupt priority	Programmable response	For errors that are generally not of critical severity
2	Non maskable interrupt generated	Error pin activated	For errors that are generally of critical severity
3	No interrupt response	Error pin activated	For critical errors that are seen by diagnostic implemented in CPU

The error response is action that is taken by the MCU or system when an error is indicated. There are multiple potential of error response possible for the Hercules product. The system integrator is responsible to determine what error response should be taken and to ensure that this is consistent with the system safety concept.

- CPU abort - This response is implemented directly in the CPU, for diagnostics implemented in the CPU. During an abort, the program sequence transfers context to an abort handler and software has an opportunity to manage the fault.
- CPU interrupt - This response can be implemented for diagnostics outside the CPU. An interrupt allows events external to the CPU to generate a program sequence context transfer to an interrupt handler where software has an opportunity to manage the fault.
- Generation of SYS_nRST - This response allows the device to change states to warm boot from operational state. The SYS_nRST could be generated from an external monitor or internally by the software reset or watchdog. Re-entry to the warm reset state allows possibility for software recovery when recovery in the operational state was not possible.
- Generation of nPORRST - This response allows the device to change state to safe state from cold boot, warm boot, or operational states. From this state, it is possible to re-enter cold boot to attempt recovery when recovery via warm boot is not possible. It is also possible to move to the powered-down state, if desired, to implement a system level safe state. This response can be generated from the internal voltage monitor, but is primarily driven by monitors external to the MCU.

The ESM provides multiple registers that can be read by the CPU to determine the current status of diagnostics and the state of the nERROR pin. For the severe group 2 errors, a shadow register is provided that is not reset by SYS_nRST. This allows the possibility of warm reset reinitialization to identify that a group 2 error initiated the external reset.

It is possible for the CPU to trigger the nERROR pin response manually to test system behavior or to notify external logic of an internal fault not automatically indicated to ESM. The CPU is responsible to clear indicated errors in the ESM, including clearing of the nERROR pin response.

The EPC is used as a complement to the ESM for error profiling . The primary goal of this module is to provide a unified correctable ECC error (single bit ECC fault) profiling capability and error address cache on ECC failures in system bus memory slaves like Flash, FEE, and SRAM. The secondary goal of this module is to provide an ECC error reporting capability for bus masters, which do not natively have ECC logic built in like the DMA and TUs. The ECC generation and evaluation logic for bus masters such as DMA and the TUs are built into the CPU Interconnect Subsystem.

System level management of the external error response can be simplified through the use of a TI TPS6538x power supply and safety companion device developed for use with the Hercules family.

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5 System Integrator Recommendations

You, as a system and equipment manufacturer or designer, are responsible to ensure that your systems (and any TI hardware or software components incorporated in your systems) meet all applicable safety, regulatory, and system-level performance requirements. All application and safety related information in this document (including application descriptions, suggested safety measures, suggested TI products, and other materials) is provided for reference only. You understand and agree that your use of TI components in safety critical applications is entirely at your risk, and that you (as buyer) agree to defend, indemnify, and hold TI harmless from any and all damages, claims, suits, or expense resulting from such use.

A brief description of each element on this device and the general assumptions of use are provided in Section 6.

A list of diagnostic mechanisms for this device and a brief description for each diagnostic are provided in Section 7.

The effectiveness of the hardware safety mechanisms is noted in the *Detailed Safety Analysis Report for RM57x ARM®-Based Safety Critical Microcontrollers* (SPNU579).

This information should be used to determine the strategy for utilizing safety mechanisms. The details of each safety mechanism can be found in the device-specific technical reference manual.

Depending on the safety standard and end equipment targeted, it may be necessary to manage not only single point faults, but also latent faults. Many of the safety mechanisms described in this section can be used as primary diagnostics, diagnostics for latent fault, or both. When considering system design for management of latent faults, take care to include failure of execution resources when considering latent faults with software diagnostics, such as failure of CPU and memories.

5.1 System Integrator Activities

The system integrator is responsible for carrying out a number of product development activities. These activities carried out may include but are not limited to the following:

- Operational and Environmental Constraints
  - Verify that the implementation of the TI component in the system design is compliant to requirements in TI documentation. This includes but is not limited to the requirements found in technical reference manuals, data sheets, errata documents, safety manuals, and safety analysis reports
  - Verify that the system operational lifetime (power-on hours) does not exceed lifetime specifications for the TI component, as specified in the device data sheet. If the operational lifetime (power-on hours) is not specified in the data sheet, the use case does not match published conditions, or there are questions regarding device lifetime, please contact a TI quality/reliability engineering representative or http://www.ti.com.
  - Define system maintenance requirements. The Hercules MCU does not require maintenance.
  - Define system repair requirements. The Hercules MCU is non-repairable with respect to permanent faults. A power-on reset of the Hercules MCU may be considered a repair activity for transient faults per some definitions of system repair requirements.
  - Define system decommissioning requirements. The Hercules MCU has no specific decommisioning requirements.
  - Define system disposal requirements. The Hercules MCU has no specific disposal requirements.
- Avoidance of Systematic Errors
  - Verify the application of appropriate best practices at all stages of hardware and system development (including development of hardware and system diagnostics external to the MCU) to avoid systematic failure and to control random failures. This may include but is not limited to compliance to the requirements documented in IEC61508-2;Annex A Tables A.15 through A.18, as well as Annex B Tables B.1 through B.6
  - Verify that any software implemented (including software diagnostics) is developed with an appropriate set of measures to avoid systematic errors
- Safety Concept Definition
  - Define the supported safety functions and verify that the microcontroller behaves properly to

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support execution of the defined safety function. This microcontroller is a generic product, which is capable of supporting a variety of safety functions but does not have fixed support for any specific safety function.

- Define the system-level safe state concept considering safe-state entry, maintenance of safe state, and safe-state exit as appropriate to the application and verify correct implementation
- Define the system-level error-handling concept and verify correct implementation.
- Define appropriate overall timing requirements for safety metrics to be calculated for the application
- Define appropriate safety metric targets for the application

- Safety Concept Implementation
  - Select and implement an appropriate set of diagnostics and safety mechanisms from the MCU safety manual as necessary to satisfy the requirements of the targeted standards and the high level safety concept. Dependent on the results of the system level safety analysis, it may not be necessary to implement all diagnostic measures which TI has identified.
  - For the device diagnostics listed as "system" in Table 4, implement the diagnostic in a manner that meets functional safety requirements of the system, particularly monitoring of the external clock, monitoring of voltage, and MCU state monitoring via external watchdog logic. TI's recommendations are based on analysis of what faults might be detected external to the MCU when considering fault models/failure modes described in IEC 61508 -2 Annex A as to be considered for any claims of high diagnostic coverage, including both permanent and transient failure modes.
  - Implement appropriate mechanisms to detect shorts between pins on the device. Tests may include I/O loopback tests, information redundancy, or system-level mechanisms designed to detect shorts.
  - Any end-to-end communications diagnostics implemented should consider the failure modes and potential mitigating safety measures described in IEC 61784-3:2010 and summarized in IEC 61784-3:2010 in Table 1.
  - Ensure that any additional system level hardware or software diagnostics created or implemented by the system integrator are developed with an appropriate process to avoid systematic errors.
  - Define an appropriate diagnostic test interval per diagnostic to be implemented.
- Verification of Safety Concept including Safety Metric Calculation
  - Verify the behavior of the MCU outputs in the system when the MCU is in a faulted condition.
  - Evaluate the system design for specific failure modes of functional logic and diagnostic logic which are detectable based on the specific application usage and the specific diagnostics applied. TI's safety analysis for the MCU considers all fault models noted in IEC 61508-2 Annex A as to be considered for any claims of high diagnostic coverage, including both permanent and transient failure modes. Refer to the Safety Analysis Report for more details.
  - Evaluate the system design for specific failure modes of functional logic and diagnostic logic which are not detectable based on the specific application usage and the specific diagnostics applied. TI's safety analysis for the MCU considers all fault models noted in IEC 61508-2 Annex A as to be considered for any claims of high diagnostic coverage, including both permanent and transient failure modes. Refer to the Safety Analysis Report for more details and ensure that the system design considers system level diagnostics recommended by TI, such as external voltage supervision, external watchdog, and so forth.
  - Verify that the implemented diagnostics meet the target diagnostic test interval per diagnostic.
  - Estimate failure rates and diagnostic coverage per failure mode with respect to specific application usage. TI provides tools to support this activity in the Safety Analysis Report (SAR).
  - Verify that environmental and operational constraints are properly modeled in the FMEDA to provide failure rate estimates.
  - Verify that appropriate on-chip design elements are selected in the FMEDA for the specific safety function under analysis.
  - Verify that targeted safety metrics are calculated and achieved
  - Verify the diagnostic coverage achieved by the implemented system and software based diagnostics.
  - Verify that the safety analysis considers MCU elements which are necessary to support the primary function, such as clock, power, OTP configuration, and similar. Many times the focus of analysis is

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the functional datapath but the elements necessary to support proper operation should also be considered.

– Execute a co-existence/freedom from interference analysis per the targeted standard to confirm that implemented functionality can co-exist without interference.
– Execute a dependent failure/common cause analysis to consider possible dependent/common cause failures on the sub-elements of the MCU, including pin level connections.

5.2 Hints for Performing Dependent/Common Cause Failure Analysis Including the Hercules MCU

The following steps may be useful for performing dependent/common cause failure analysis when using the Hercules MCU:

- Consider a relevant list of dependent fault/common cause fault initiators, such as the lists found in the draft ISO/PAS 19451 document, “Application of ISO 26262 to Semiconductors”
- Verify that the dependent failure analysis considers the impact of the software tasks running on the MCU, including hardware and software interactions and task/operating system interactions.
- Verify that the dependent failure analysis considers the impact of pin/ball level interactions on the MCU package, including aspects related to the selected I/O multiplexing

5.3 Hints for Improving Independence of Function/Co-Existence of Function When Using the Hercules MCU

The following steps may be useful for improving independence of function when using the Hercules MCU:

- Verify that unused interrupt channels are disabled in the VIM
- Verify that unused interrupt sources are disabled in the source peripherals
- Hold peripheral chip selects in reset with the PCR if the peripherals are unused
- Leave peripherals in default reset state if not controlled via PCR
- Power down power domains if all logic in power domain is not used
- Disable event triggers if unused
- Power down the ADC cores if MibADCs are unused
- Utilize peripheral bus master memory protection units (MPUs) to only allow access to needed transmit and receive buffers
- Utilize the CPU MPU to support isolation of separate software tasks running on the CPU
- Utilize privileged access modes as a secondary level of task isolation
- Utilize bus master ID filtering when available to limit allocation of peripherals to bus masters
- When possible, separate critical I/O functions by using non adjacent I/O pins/balls. Consider using the pin muxing logic to support such separation.
- Power down unused clock sources.
- Disable unused clock domains.
- Power down the flash pump logic if flash memory is not used after boot.

5.4 Support for System Integrator Activities

If you have any questions regarding usage of the TI documentation for system integration, or if you have questions regarding MCU level functional safety standard work products not provided as part of the TI documentation package, please contact TI support. The preferred and fastest method to contact TI support is via the E2E forum at http://e2e.ti.com/support/microcontrollers/hercules/default.aspx.

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6 Brief Description of Elements

This section contains a brief description of the elements identified on this device in Table 1. For a full functional description of any of these modules, see the device-specific technical reference manual.

6.1 Power Supply

The Hercules device family products require an external device to supply the necessary voltages and currents for proper operation. Separate voltage rails are available for core logic and I/O logic (including multi-buffered analog-to-digital converter (MibADC), Flash pump and oscillator).

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Internal Voltage Monitor (VMON)
- External Voltage Supervisor
- MibADC Converter Calibration
- External Watchdog

6.1.1 Notes

- Management of voltage supervision at system level can be simplified by using a TI TPS6538x power supply and safety companion device developed for use with the Hercules family.
- Devices can be implemented with multiple power rails that are intended to be ganged together on the system PCB. For proper operation of power diagnostics, it is recommended to implement one voltage supervisor per ganged rail.
- Common mode failure analysis of the external voltage supervisor may be useful to determine dependencies in the voltage generation and supervision circuitry

6.2 Power Management Module (PMM)

The power management module (PMM) is responsible for control of switchable power domains. Dependent on the family variant used, one or more power domains can be implemented. Power domains can be permanently configured at manufacturing time by TI or they can be user programmable. To determine the power domains supported on your MCU, see the device-specific data sheet. For programming information, see the device-specific technical reference manual.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Internal Voltage Monitor (VMON)
- External Voltage Supervisor
- Lockstep PSCON
- Power Domain Inactivity Monitor
- Privileged Mode Access and Multi-Bit Keys for Control Registers
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- PSCON Lockstep Comparator Self Test
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

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6.2.1 Notes

- PSCONs continue to function normally during lockstep compare self-test, but no comparison function is present.
- When the CPU is in a halting debug state, no comparison of PSCON outputs is performed.

6.3 Clocks

The Hercules device family products are primarily synchronous logic devices and as such require clock signals for proper operation. The clock management logic includes clock sources, clock generation logic including clock multiplication by phase lock loops (PLLs), clock dividers, and clock distribution logic. The registers that are used to program the clock management logic are located in the system control module.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- LPOCLKDET
- PLL Slip Detector
- Dual Clock Comparator (DCC)
- External Monitoring via ECLK
- Internal Watchdog - DWD
- Internal Watchdog - DWWD
- External Watchdog
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration

The following tests can be applied as test-for-diagnostics on this module to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Software Test of DCC Functionality
- Software Test of DWD Functionality
- Software Test of DWWD Functionality
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.3.1 Notes

- Management of the external watchdog functionality at system level can be simplified by using a TI TPS6538x power supply and safety companion device developed for use with the Hercules family.
- User can improve the accuracy of the LPOCLKDET diagnostic via programming the trim values in the HF LPO. This would require the customer to determine the LPO trim value during their manufacturing test via comparison to a calibrated clock source.
- There are many possible implementations of watchdogs for use in providing clock and CPU diagnostics. In general, TI advises the use of an external watchdog over an internal watchdog for reasons of reduced common mode failure. TI also advises the use of a program sequence, windowed, or question and answer watchdog as opposed to a single threshold watchdog due to the additional failure modes that can be detected by a more advanced watchdog.
- Driving a high-frequency clock output on the ECLK pin may have EMI implications.

6.4 Reset

The Hercules device family products require an external reset at cold and power-on (nPORRST) to place all asynchronous and synchronous logic into a known state. The power-on reset generates an internal warm reset (nRST) signal to reset the majority of digital logic as part of the boot process. The nRST signal is provided at device level as an I/O pin; it will toggle when asserted internally and can be driven externally to generate a warm reset. For more information on the reset functionality, see the device-specific data sheet.

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The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- External Monitoring of Warm Reset (nRST)
- Software Check of Cause of Last Reset
- Software Warm Reset Generation
- Glitch Filtering on Reset Pins
- Use of Status Shadow Registers
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Software Test for Reset
- External Watchdog

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (In combination with other diagnostics on the primary function)

- Internal Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.4.1 Notes

- Management of reset at system level can be simplified by using a TI TPS6538x power supply and safety companion device developed for use with the Hercules family.
- Internal watchdogs are not a viable option for reset diagnostics as the monitored reset signals interact with the internal watchdogs.

6.5 System Control Module

The system control module contains the memory-mapped registers to interface clock, reset, and other system related control and status logic. The system control module is also responsible for generating the synchronization of system resets and delivering the warm system reset nRST.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Privileged Mode Access and Multi-Bit Enable Keys for Control Registers
- Software Readback of Written Configuration
- Periodic Software Readback of Static Configuration Registers
- Multi-Bit Keyed Self-Correctable High-Integrity Bits

The following tests can be applied as test-for-diagnostics on this module to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.5.1 Notes

- Depending on targeted metrics, a user can elect to implement a periodic software test of static configuration registers in the system control module. Such a test can provide additional diagnostic coverage for disruption by soft error.
- Review the clock and reset sections as these features are closely controlled by the system control

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module.

6.6 Error Signaling Module (ESM)

The ESM provides unified aggregation and prioritization of on-board hardware diagnostic errors. For more information, see Management of Errors.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Periodic Software Readback of Static Configuration Registers
- Boot Time Software Test of Error Path Reporting
- Periodic Software Test of Error Path Reporting
- Use of Status Shadow Registers
- Software Readback of Written Configuration

The following tests can be applied as test-for-diagnostics on this module to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.6.1 Notes

- Software testing of the ESM error path can be combined with boot time latent tests of hardware diagnostics to reduce startup time.
- Testing of ESM error path may result in assertion of the nERROR diagnostic output. System integrator should ensure that the system can manage or recover gracefully from the nERROR event.

6.7 CPU Subsystem

The Hercules product family relies on the ARM® Cortex-R5F CPU to provide general-purpose processing. The Cortex-R5F is a high performance CPU with embedded safety diagnostics. The R5F is also designed for easy integration into a 1oo1D lockstep configuration. These aspects make the Cortex-R5F an outstanding CPU for functional safety products.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- CPU Lockstep Compare
- Boot Time Execution of LBIST STC
- Periodic Execution of LBIST STC
- Memory Protection Unit (MPU)
- Online Profiling Using PMU
- Illegal Operation and Instruction Trapping
- Periodic Software Readback of Static Configuration Registers
- Software Read Back of CPU Registers
- Boot Time PBIST Check of CPU cache Memories
- Periodic Time PBIST Check of CPU cache Memories
- ECC on Cache Memories
- Hardware Disable of JTAG Port
- Internal Watchdog
- External Watchdog

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The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Lockstep Compare Self-Test
- LBIST Auto-Coverage
- Software Test of PBIST
- PBIST Auto-Coverage
- Software Readback of Written Configuration (PBIST)
- Flash Data ECC
- Data ECC

6.7.1 Measures to Mitigate Common Mode Failure in CPU Subsystem

The Hercules lockstep CPU subsystem design includes multiple best practices to mitigate common mode failure:

- Physical diversity:
  - Physical core hard macros are spaced at least 100 µm apart.
  - Each CPU is uniquely diversified in terms of the cell placements .
- Temporal diversity:
  - Timing delay blocks are inserted to delay the operation of the CPUs by two cycles as shown in Figure 7.

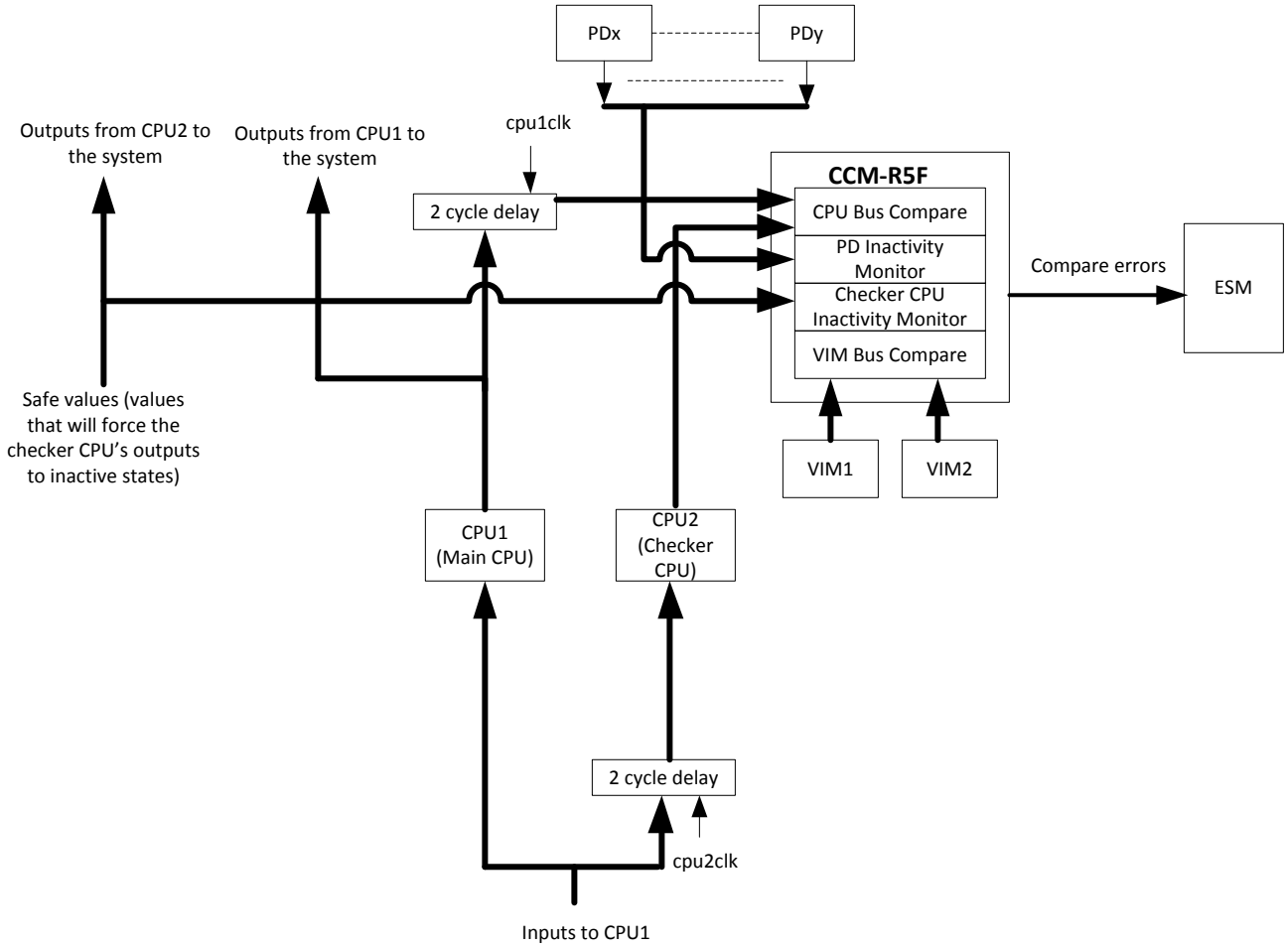


Figure 7. Lockstep Temporal Diversity

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  - The CPU clock domain is split into two clock trees such that clocks are delivered to the two CPUs by separate paths.
- Power diversity:
  - Each core has a dedicated 40 µm power ring.

6.7.2 Notes

- Many safety critical microcontrollers utilize a software-based test of CPU functionality as opposed to a hardware scheme such as the TI LBIST STC. TI does not recommend such tests for a CPU of medium to high complexity, such as the Cortex-R5F. Software-based options have higher memory cost, lower detection capability, and longer execution times than the equivalent LBIST STC solution.
- Due to the lockstep diagnostic, it is not necessary to execute a periodic test of CPU control register configuration. A control register disturb in one CPU should not impact the second CPU.
- Cache controller logic is included in the lockstep CPU and as such is checked on a cycle by cycle basis.

6.8 Primary Embedded Flash

The primary embedded flash memory is a non-volatile memory residing on the CPU Interconnect Subsystem. The primary flash memory is mainly used for CPU instruction access, though data access is also possible. Access to the Flash memory can take multiple CPU cycles. A flash wrapper logic provides multiple pipelined read buffers to improve CPU access time on sequential address fetches.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Flash Data ECC
- Hard Error Cache and Livelock
- Flash Wrapper Address ECC
- Address and Control Parity
- Boot Time Check of Flash Memory Contents by Hardware CRC
- Periodic Check of Flash Memory Contents by Hardware CRC
- Bit Multiplexing in Flash Memory Array
- Flash Sector Protection
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Flash Wrapper Diag Mode 5 Test
- Flash Wrapper Diag Mode 7 Test
- Software Test of Parity Logic
- Software Test of Flash Sector Protection Logic
- Software Test of Hardware CRC
- CRC Auto-Coverage
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- SRAM Data ECC
- CPU Interconnect Hardware Checker
- Timeout Monitoring on Bus Transactions

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6.8.1 Notes

- When exporting ECC error events from the Flash wrapper to ESM, care should be taken that the error is not due to discarded prefetch or other branch discontinuity.
- By executing a CRC read back of Flash contents while ECC is enabled on the Flash, it is possible to perform two diagnostics of the Flash in parallel.
- The Flash module may have unique power supply pins depending on the product configuration. Implementation of external voltage supervision on these pins can be considered to improve system safety integrity measures as described in the power supply section.
- The Flash module may have unique test signal pins depending on the product configuration. For proper board level management of these signals, see the device-specific data sheet.
- To take advantage of error profiling features and to propagate error events from bus masters, the EPC module must be initialized.

6.9 Flash EEPROM Emulation (FEE)

The Hercules platform architecture includes the capability for a separate bank of Flash memory to be used as Flash EEPROM Emulation (FEE). FEE is used for data storage only, and cannot be used as a CPU instruction memory. FEE is a level two memory that is accessed by the CPU over the AXI master port. The emulation of EEPROM in the FEE memory is managed by specific FEE drivers running on the CPU.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- FEE Data ECC
- Boot Time Check of FEE Memory Contents by Hardware CRC
- Periodic Check of FEE Memory Contents by Hardware CRC
- Bit Multiplexing in FEE Array
- FEE Sector Protection
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Flash Wrapper Address ECC

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Flash Wrapper Diag Mode 5 Test
- Flash Wrapper Diag Mode 7 Test
- Software Test of Flash Sector Protection Logic
- Software Test of Hardware CRC
- CRC Auto-Coverage
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC
- CPU Interconnect Hardware Checker
- Timeout Monitoring on Bus Transactions

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6.9.1 Notes

- As all application FEE accesses are run through a software driver to manage EEPROM emulation, any diagnostics must respect the functionality of the FEE driver.
- The FEE module may have unique power supply pins depending on the product configuration. Implementation of external voltage supervision on these pins can be considered to improve system safety integrity measures as described in the power supply section.
- The FEE module may have unique test signal pins depending on the product configuration. For proper board level management of these signals, see the device-specific data sheet.
- To take advantage of error profiling features and to propagate error events from bus masters, the EPC module must be initialized.

6.10 Primary Embedded SRAM

The primary embedded SRAM is a volatile memory that is accessed via the level two CPU Interconnect Subsystem. The SRAMs are primarily used for CPU data access, though instruction access is also possible as is access via other bus masters.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Data ECC
- Hard Error Cache and Livelock
- Correctable ECC Profiling
- Address and Control Bus Parity
- Redundant Address Decode
- Data and ECC Storage in Multiple Physical Banks
- Boot Time PBIST Check of Primary SRAM
- Periodic PBIST Check of Primary SRAM
- Bit Multiplexing in Primary SRAM Array
- Periodic Hardware CRC Check of Primary SRAM Contents
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Scrubbing of SRAM to Correct Detected Single Bit Errors

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Software Test of SRAM Wrapper Redundant Address Decode and ECC
- Software Test of Parity Logic
- Software Test of PBIST
- PBIST Auto-Coverage
- Software Test of ECC Profiler
- Redundant Address Decode Self Test
- Software Test of Hardware CRC
- CRC Auto-Coverage
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC

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6.10.1 Notes

- By executing a CRC read back of SRAM contents while ECC is enabled on the SRAM, it is possible to perform two diagnostics of the SRAM in parallel.
- The SRAM module may have unique power supply pins depending on the product configuration. Implementation of external voltage supervision on these pins can be considered to improve system safety integrity measures as described in the power supply section.
- The redundant address decode does not provide hardware fault tolerance. As such, the logic may not be considered fully redundant per the definition of redundancy in some safety standards.
- To take advantage of error profiling features and to propagate error events from bus masters, the EPC module must be initialized.

6.11 CPU Interconnect Subsystem

The CPU Interconnect Subsystem is composed of a number of bridges, gaskets, communications crossbars, and routing logic, which connects the bus masters (DMA, CPU, TUs, and so forth) to L2 memory slaves.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Error Trapping (Including Peripheral Slave Error Trapping)
- Information Redundancy
- Periodic Software Readback of Static Configuration Registers
- Boot Time Software Test of Basic Functionality Including Error Tests
- Periodic Software Test of Basic Functionality Including Error Tests
- Software Readback of Written Configuration
- Transmission Redundancy
- Execution of Interconnect Self-Test
- CPU Interconnect Hardware Checker
- Timeout Monitoring on Bus Transactions
- Transaction ECC (Date Lines)
- Transaction Parity (Address and Control Lines)
- Internal Watchdog
- External Watchdog

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.11.1 Notes

- An end to end communications safety mechanism implemented on a networked peripheral provides an indirect form of information redundancy diagnostic on the L2 and L3 interconnects.
- The only module in the L2 and L3 interconnect subsystem that has memory-mapped registers is the PCR.

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6.12 Peripheral Interconnect Subsystem

The Peripheral Interconnect Subsystem is composed of a number of bridges, gaskets, communications crossbars, and routing logic, which connects the bus masters (DMA, CPU, TUs, and so forth) to device peripherals. This logic, while having no explicit safety critical purpose, is an intermediary in the transfer of safety critical communications. The peripherals are further distributed among the three peripheral segments that are mentioned below.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Error Trapping (Including Peripheral Slave Error Trapping)
- Peripheral Interconnect New Memory Protection Unit (NMPU)
- Information Redundancy
- Periodic Software Readback of Static Configuration Registers
- Boot Time Software Test of Basic Functionality Including Error Tests
- Periodic Software Test of Basic Functionality Including Error Tests
- Software Readback of Written Configuration
- Transmission Redundancy
- Internal Watchdog
- External Watchdog

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.13 Peripheral Central Resource 1 (PCR1)

The Peripheral Central Resource 1 refers to the interconnect that connects the bus masters (CPU , DMA and so forth) to selected system peripherals, debug, test, emulation and instrumentation logic on the first segment located beneath the Peripheral Interconnect Subsystem.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Error Trapping (Including Peripheral Slave Error Trapping)
- PCR Access Management: Protection Mode and MasterID Filtering
- Information Redundancy
- Periodic Software Readback of Static Configuration Registers
- Boot Time Software Test of Basic Functionality Including Error Tests
- Periodic Software Test of Basic Functionality Including Error Tests
- Software Readback of Written Configuration
- Transmission Redundancy
- Internal Watchdog
- External Watchdog

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

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6.14 Peripheral Central Resource 2 (PCR2)

The Peripheral Central Resource 2 refers to the interconnect that connects the bus masters (CPU , DMA and so forth) to selected high speed and motor control peripherals on the second segment located beneath the Peripheral Interconnect Subsystem.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Error Trapping (Including Peripheral Slave Error Trapping)
- PCR Access Management: Protection Mode and MasterID Filtering
- Information Redundancy
- Periodic Software Readback of Static Configuration Registers
- Boot Time Software Test of Basic Functionality Including Error Tests
- Periodic Software Test of Basic Functionality Including Error Tests
- Software Readback of Written Configuration
- Transmission Redundancy
- Internal Watchdog
- External Watchdog

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.15 Peripheral Central Resource 3 (PCR3)

The Peripheral Central Resource 3 refers to the interconnect that connects the bus masters (DMA, CPU, and so forth) to user peripherals on the third segment located beneath the Peripheral Interconnect Subsystem.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Error Trapping (Including Peripheral Slave Error Trapping)
- PCR Access Management: Protection Mode and MasterID Filtering
- Information Redundancy
- Periodic Software Readback of Static Configuration Registers
- Boot Time Software Test of Basic Functionality Including Error Tests
- Periodic Software Test of Basic Functionality Including Error Tests
- Software Readback of Written Configuration
- Transmission Redundancy
- Internal Watchdog
- External Watchdog

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

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6.16 EFuse Static Configuration

The Hercules platform devices support a manufacturing time configuration of certain functionality (such as trim values for analog macros) via one time programmable (OTP) EFuse structures. The EFuses are read automatically after power-on reset by an autoload function.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Autoload Self Test
- E-Fuse ECC
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Autoload Self Test Auto-Coverage
- EFuse ECC Logic Self Test
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.17 OTP Static Configuration

The Hercules platform devices support a manufacturing time configuration of certain functionality (such as endianness and the initial configuration of power domains after reset) via one time programmable Flash memory. The OTP configuration values are read automatically after warm reset by an autoload function.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Autoload Self Test
- OTP ECC
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Boot Time Hardware CRC Check of OTP Contents
- Periodic Hardware CRC Check of OTP Contents
- Bit Multiplexing in Flash Memory Array
- Flash Sector Protection

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Software Test of Flash Sector Protection Logic
- Software Test of Hardware CRC
- CRC Auto-Coverage
- Flash Wrapper Diag Mode 5 Test
- Flash Wrapper Diag Mode 7 Test
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC

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- SRAM Data ECC

6.17.1 Notes

The OTP Flash memory used for storage of the configuration words can be read by the CPU.

6.18 I/O Multiplexing Module (IOMM)

The I/O multiplexing module (IOMM) provides software configurable mapping of internal module I/O functionality to device pins.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Locking Mechanism For Control Registers
- Master ID Filtering
- Error Trapping
- Periodic Software Readback of Static Configuration Registers
- Boot Time Software Test of Function Using I/O Loopback Including Error Tests
- Periodic Software Test of Function Using I/O Loopback Including Error Tests
- Software Readback of Written Configuration

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.18.1 Notes

Software testing of the IOMM can be combined with peripheral loopback testing.

6.19 Vectored Interrupt Module (VIM)

The vectored interrupt module (VIM) is used to interface peripheral interrupts to the Cortex-R5F CPU. The VIM provides programmable interrupt prioritization, masking, and sleep mode wake up functionality. The VIM includes a local SRAM that is used to hold the address of the interrupt handler per channel. Two VIMs (VIM1 and VIM2) are implemented on this device. For safety diagnostics purposes the VIMs (VIM1 and VIM2) are implemented and run in lock step pairs .

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- VIM SRAM Data ECC
- Boot Time PBIST Check of VIM SRAM
- Periodic PBIST Check of VIM SRAM
- Bit Multiplexing in VIM SRAM Array
- Periodic Hardware CRC Check of VIM SRAM Contents
- Boot Time Software Test of VIM Functionality Including Error Tests
- Periodic Software Test of VIM Functionality Including Error Tests
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- VIM Lockstep Compare

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- Internal Watchdog
- External Watchdog
- CPU Memory Protection Unit (MPU)
- Online Profiling Using PMU

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Software test of ECC Logic
- PBIST Test of ECC Bit Memory
- Software Test of Hardware CRC
- CRC Auto-Coverage
- Software Test of PBIST
- PBIST Auto-Coverage
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC
- Lockstep Compare Self-Test

6.19.1 Notes

Care should be taken to optimize any VIM software diagnostics for the mode of operation - legacy IRQ and FIQ, legacy vectored, or fully hardware vectored.

6.20 Real Time Interrupt (RTI)

The real time interrupt (RTI) module provides the operating system timer for the device. The OS timer function is used to generate internal event triggers or interrupts as needed to provide periodic operation of safety critical functions.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- 1oo2 Software Voting Using Secondary Free Running Counter
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.20.1 Notes

When using one counter to the operating system time base counter, a diverse configuration of clock source, scaling factor, and so forth can be used to reduce probability of common mode failure.

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6.21 Direct Memory Access (DMA)

The direct memory access (DMA) module is used to move data from one location to another inside the system. This is typically used for peripheral configuration (Flash and SRAM to peripheral transfer) and peripheral data update (peripheral buffer memory transfer to CPU SRAM for processing). The DMA is typically used by the operating system to offload bus transactions from the CPU in order to improve overall system performance. The DMA has a local SRAM that is used for channel control information.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Memory Protection Unit for Bus Master Accesses
- Non-Privileged Bus Master Access
- Information Redundancy Techniques
- DMA SRAM Data ECC
- Boot Time PBIST Check of DMA SRAM
- Periodic PBIST Check of DMA SRAM
- Bit Multiplexing in DMA SRAM Array
- Periodic Hardware CRC Check of DMA SRAM Contents
- Periodic Software Readback of Static Configuration Registers
- Boot Time Software Test of Basic Functinality Including Error Tests
- Periodic Software Test of Basic Functinality Including Error Tests
- Software Readback of Written Configuration
- Transmission Redundancy
- Peripheral Interconnect New Memory Protection Unit (NMPU)
- Hardware Disable of JTAG Port

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Software test of ECC Logic
- PBIST Test of ECC Bit Memory
- Software Test of Hardware CRC
- CRC Auto-Coverage
- Software Test of PBIST
- PBIST Auto-Coverage
- Software Test of MPU Functionality
- Multi-Bit Keyed Self-Correctable High-Integrity Bits
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.22 High-End Timer (N2HET), HET Transfer Unit (HTU)

The N2HET module is a programmable timer with input/output capabilities. The N2HET is implemented as a simple RISC processor with instruction set dedicated for timing operations. Complex inputs can be captured and pre-processed by the N2HET for later processing by the CPU. Output generation is typically pulse width modulation (PWM), but may also be simple general-purpose input/output (GIO) type signals.

Each N2HET has a dedicated micro DMA controller called HTU. The HTU provides a high bandwidth connection for data transfer to and from N2HET from and to CPU memories.

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The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Memory Protection Unit for HTU Bus Master Accesses
- Information Redundancy Techniques
- Use of DCC as Program Sequence Watchdog
- Monitoring by Second N2HET
- Boot Time Software Test of Function Using I/O Loopback
- Periodic Software Test of Function Using I/O Loopback
- N2HET/HTU SRAM Data Parity
- Boot Time PBIST Check of N2HET/HTU SRAM
- Periodic PBIST Check of N2HET/HTU SRAM
- Bit Multiplexing in N2HET/HTU SRAM Array
- Periodic Hardware CRC Check of N2HET/HTU SRAM Contents
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Transmission Redundancy for Transfer Unit
- Boot Time Software test of Function Using I/O Checking In GIO Mode
- Periodic Software test of Function Using I/O Checking In GIO Mode
- Information Redundancy Techniques (while in GIO Mode)
- Hardware Disable of JTAG Port

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Software test of Parity Logic
- PBIST Test of Parity Bit Memory
- Software Test of Hardware CRC
- CRC Auto-Coverage
- Software Test of PBIST
- PBIST Auto-Coverage
- Software Test of MPU Functionality
- Software Test of DCC Functionality
- Boot Time Execution of LBIST STC
- Periodic Execution of LBIST STC
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC
- LBIST Auto-Coverage

6.22.1 Notes

- Information redundancy techniques used on N2HET can be extended to also cover the HTU bus master operation.
- To reduce probability of common mode failure, user should consider implementing multiple channels (information redundancy) using non adjacent pins.

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6.23 Multi-Buffered Analog-to-Digital Converter (MibADC)

The MibADC module is used to convert analog inputs into digital values. Results are stored in internal SRAM buffers for later transfer by DMA or CPU. The Hercules device family products implement two modules with shared channels used for fast conversion (ping-pong method). Systems implementing two channels using the dual ADC converters may be able to claim fault tolerance in application.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Hardware Disable of JTAG Port
- Boot Time Input Self Test
- Boot Time MibADC Calibration
- Periodic MibADC Calibration
- MibADC Information Redundancy Techniques
- MibADC SRAM Data Parity
- Boot Time PBIST Check of MibADC SRAM
- Periodic PBIST Check of MibADC SRAM
- Bit Multiplexing in MibADC SRAM Array
- Periodic Hardware CRC Check of MibADC SRAM Contents
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Boot Time Software Test of Function Using I/O Checking In GIO Mode
- Periodic Software Test of Function Using I/O Checking In GIO Mode
- Information Redundancy Techniques (while in GIO Mode)

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Software test of Parity Logic
- PBIST Test of Parity Bit Memory
- Software Test of Hardware CRC
- CRC Auto-Coverage
- Software Test of PBIST
- PBIST Auto-Coverage
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.23.1 Notes

- The MibADC module may be referred to as MibADC (Multi Buffered ADC) in some documents.
- ADC module voltages should be supervised as noted in Power Supply
- To reduce probability of common mode failure, user should consider implementing multiple channels (information redundancy) using non adjacent pins.

6.24 Enhanced Pulse Width Modulators (ePWM)

The enhanced pulse width modulator (ePWM) peripheral is a key element in controlling many of the power electronic systems found in both commercial and industrial equipments. The features supported by the ePWM make it especially suitable for digital motor control.

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The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Boot Time Software Test of Function Including Error Tests
- Periodic Software Test of Function Including Error Tests
- Information Redundancy Techniques
- Monitoring by eCAP or N2HET
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC
- Boot Time Software Test of eCAP Function
- Periodic Software Test of eCAP Function
- Boot Time Test of N2HET Function Including I/O Loopback
- Periodic Test of N2HET Function Including I/O Loopback

6.25 Enhanced Capture (eCAP)

The enhanced Capture (eCAP) module provides input capture functionality for systems where accurate timing of external events is important.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Boot Time Software Test of Function Including Error Tests
- Periodic Software Test of Function Including Error Tests
- Information Redundancy Techniques
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
  Information Redundancy Techniques (while in PWM Mode)
- Monitoring by eCAP or N2HET (while in PWM Mode)

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.25.1 Notes

- If using the eCAP in PWM output mode, see the guidance for the Section 6.24.
- N2HET channels can be used for input capture as a hardware diverse second channel to implement information redundancy with reduced probability of common mode failure.

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6.26 Enhanced Quadrature Encoder Pulse (eQEP)

The enhanced quadrature encoder pulse (eQEP) module is used for direct interface with a linear or rotary incremental encoder to get position, direction, and speed information from a rotating machine for use in a high-performance motion and position-control system.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Boot Time Software Test of Function Including Error Tests
- Periodic Software Test of Function Including Error Tests
- Information Redundancy Techniques
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Quadrature Watchdog

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The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Software Test of Quadrature Watchdog Functionality
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.26.1 Notes

Use of a sensorless positioning algorithm can provide information redundancy through plausibility checking of eQEP results.

6.27 Multi Buffered Serial Peripheral Interface (MibSPI)

The MibSPI modules provide serial I/O compliant to the MibSPI protocol. MibSPI communications are typically used for communication to smart sensors and actuators, serial memories, and external logic such as a watchdog device. The MibSPI modules contain internal SRAM buffers. If not used for MibSPI communication, the MibSPI modules support the usage of their I/O as general purpose I/O.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Boot Time Software Test of Function Using I/O Loopback
- Periodic Software Test of Function Using I/O Loopback
- Parity in Message
- Information Redundancy Techniques
- MibSPI SRAM ECC
- Boot Time PBIST Check of MibSPI SRAM
- Periodic PBIST Check of MibSPI SRAM
- Bit Multiplexing in MibSPI SRAM Array
- Periodic Hardware CRC Check of MibSPI SRAM Contents
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Transmission Redundancy
- Data Overrun Error Detection
- Bit Error Detection
- Slave Desync Detection
- Slave Timeout Detection
- Data Length Error Detection
- Hardware Disable of JTAG Port
- Boot Time Software Test of Function Using I/O Checking In GIO Mode
- Periodic Software Test of Function Using I/O Checking In GIO Mode
- Information Redundancy Techniques (while in GIO Mode)

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Software test of ECC Logic
- PBIST Test of ECC Bit Memory

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- Software Test of Hardware CRC
- CRC Auto-Coverage
- Software Test of PBIST
- PBIST Auto-Coverage
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.27.1 Notes

It is possible to use the MIBSPI in standard SPI mode.

6.28 Inter-Integrated Circuit (I2C)

The I2C module provides a multi-master serial bus compliant to the I2C protocol.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Boot Time Software Test of Function Using I/O Loopback
- Periodic Software Test of Function Using I/O Loopback
- Information Redundancy Techniques
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Transmission Redundancy
- Hardware Disable of JTAG Port
- Boot Time Software Test of Function Using I/O Checking In GIO Mode
- Periodic Software Test of Function Using I/O Checking In GIO Mode
- Information Redundancy Techniques (while in GIO Mode)

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.29 Serial Communication Interface (SCI)

The SCI module provides serial I/O capability for typical asynchronous serial communication interface (SCI) protocols, such as UART. Depending on the serial protocol used, an external transceiver may be necessary.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Boot Time Software Test of Function Using I/O Loopback
- Periodic Software Test of Function Using I/O Loopback
- Information Redundancy Techniques
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration

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- Transmission Redundancy
- Overrun Error Detection
- Frame Error Detection
- Bit Error Detection
- Parity in Message
- Hardware Disable of JTAG Port
- Boot Time Software Test of Function Using I/O Checking In GIO Mode
- Periodic Software Test of Function Using I/O Checking In GIO Mode
- Information Redundancy Techniques (while in GIO Mode)

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.30 Local Interconnect Network (LIN)

The LIN module provides serial I/O compliant to the LIN protocol. LIN is a low throughput time triggered protocol. The module can also be configured in SCI mode and used as a general purpose serial port. An external transceiver is used for LIN communications.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Boot Time Software Test of Function Using I/O Loopback
- Periodic Software Test of Function Using I/O Loopback
- Information Redundancy Techniques
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Transmission Redundancy
- Overrun Error Detection
- Frame Error Detection
- Physical Bus Error Detection
- No-Response Error Detection
- Bit Error Detection
- Checksum Error Detection
- Parity in Message
- Hardware Disable of JTAG Port
- Boot Time Software Test of Function Using I/O Checking In GIO Mode
- Periodic Software Test of Function Using I/O Checking In GIO Mode
- Information Redundancy Techniques (while in GIO Mode)

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare

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- Flash Data ECC
- SRAM Data ECC

6.30.1 Notes

When using the LIN module in SCI mode, see Section 6.29.

6.31 Controller Area Network (DCAN)

The DCAN interface provides medium throughput networking with event based triggering, compliant to the CAN protocol. The DCAN modules requires an external transceiver to operate on the CAN network.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Boot Time Software Test of Function Using I/O Loopback
- Periodic Software Test of Function Using I/O Loopback
- Information Redundancy Techniques Including End to End Safing
- DCAN SRAM Data ECC
- Boot Time PBIST Check of DCAN SRAM
- Periodic PBIST Check of DCAN SRAM
- Bit Multiplexing in DCAN SRAM Array
- Periodic Hardware CRC Check of DCAN SRAM Contents
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Transmission Redundancy
- Stuff Error Detection
- Form Error Detection
- Acknowledge Error Detection
- Bit Error Detection
- CAN Protocol CRC in Message
- Hardware Disable of JTAG Port
- Boot Time Software Test of Function Using I/O Checking In GIO Mode
- Periodic Software Test of Function Using I/O Checking In GIO Mode
- Information Redundancy Techniques (while in GIO Mode)

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Software test of ECC Logic
- PBIST Test of ECC Bit Memory
- Software Test of Hardware CRC
- CRC Auto-Coverage
- Software Test of PBIST
- PBIST Auto-Coverage
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

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6.32 General-Purpose Input/Output (GIO)

The GIO module provides digital input capture and digital input/output. There is no processing function in this block. The GIO is typically used for static or rarely changed outputs, such as transceiver enable signals, warning lights, and so forth. The GIO can also be used to provide external interrupt input capabilities.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Boot Time Software Test of Function Using I/O Checking In GIO Mode
- Periodic Software Test of Function Using I/O Checking In GIO Mode
- Information Redundancy Techniques
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.32.1 Notes

To reduce probability of common mode failure, the user should consider implementing multiple channels using non adjacent pins.

6.33 Ethernet

The Hercules platform includes an Ethernet media access controller (EMAC) and physical layer (PHY) device management data input/output (MDIO) module. These modules allow connection of the Hercules MCU to a 10 and 100 Mb Ethernet network. The Ethernet network provides higher network throughput than LIN, CAN, or FlexRay.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Non-Privileged Bus Master Access
- Boot Time Software Test of Function Using I/O Loopback in PHY
- Periodic Software Test of Function Using I/O Loopback in PHY
- Information Redundancy Techniques
- Boot Time PBIST Check of Ethernet SRAM
- Periodic PBIST Check of Ethernet SRAM
- Bit Multiplexing in Ethernet SRAM Array
- Periodic Hardware CRC Check of Ethernet SRAM Contents
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Transmission Redundancy
- CRC in Message
- Ethernet Alignment Error Detection
- Ethernet Physical Layer Fault
- Peripheral Interconnect New Memory Protection Unit (NMPU)
- Hardware Disable of JTAG Port

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The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Software Test of Hardware CRC
- CRC Auto-Coverage
- Software Test of PBIST
- PBIST Auto-Coverage
- Software test of New Memory Protection Unit (NMPU) Function
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.34 External Memory Interface (EMIF)

The external memory interface is used to provide device access to off-chip memories or devices, which support a memory interface. Support is provided for both synchronous (SDRAM) and asynchronous (NOR Flash, SRAM) memories.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Information Redundancy Techniques
- Boot Time Hardware CRC Check of External Memory
- Periodic Hardware CRC Check of External Memory
- Periodic Software Readback of Static Configuration Registers
- Software Readback of Written Configuration
- Transmission Redundancy
- Hardware Disable of JTAG Port
- Timeout Monitoring on Bus Transactions
- CPU Interconnect Hardware Checker

The following tests can be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Software Test of Hardware CRC
- CRC Auto-Coverage
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

6.34.1 Notes

- Safety critical data from external memories can be transferred or copied to internal memory in the safe island region for higher integrity operations.
- The CPU Interconnect Subsystem evaluates bus master ECC at the boundary of the EMIF module and generates proper ECC data for responses to the bus masters.

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6.35 JTAG Debug, Trace, Calibration, and Test Access

The Hercules platform supports debug, test, and calibration implemented over an IEEE 1149.1 JTAG debug port. The physical debug interface is internally connected to a TI debug multiplexor logic (ICEPICK), which arbitrates access to test, debug, and calibration logic. Boundary scan is connected in parallel to the ICEPICK to support usage without preamble scan sequences for easiest manufacturing board test.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Hardware Disable of JTAG Port
- Lockout of JTAG Access Using AJSM
- Internal Watchdog
- External Watchdog

6.35.1 Notes

Boundary scan access remains possible even on systems locked by AJSM.

6.36 Cortex-R5F Central Processing Unit (CPU) Debug and Trace

The Hercules platform supports CPU debug and trace compliant to the ARM® CoreSight standard. Each CoreSight element is accessible over a memory-mapped debug bus, which can be accessed by the CPU or the JTAG port. The CPU debug and trace logic includes an independent debug bus master (AHB-AP), the debug unit inside the CPU, and the embedded trace macrocell (ETM-R5) among others (reference the device specific datasheet for details). These modules are not recommended to be used during safety critical operation and safety mechanisms are in place to disable this logic.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Use of MPUs to Block Access to Memory-Mapped Debug
- Use of CoreSight Debug Logic Key Enable Scheme
- Hardware Disable of JTAG Port
- Lockout of JTAG Access Using AJSM
- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare

6.37 Data Modification Module (DMM)

The Data Modification Module (DMM) provides a calibration bus master functionality. During calibration the DMM is used as a minimally intrusive DMA to copy calibration data to the device. Commands to the DMM are made via JTAG or via memory-mapped registers.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Use of MPUs to Block Access to Memory-Mapped Debug
- Disable the DMM Pin Interface
- Hardware Disable of JTAG Port
- Lockout of JTAG Access Using AJSM
- Internal Watchdog
- External Watchdog

6.38 RAM Trace Port Interface (RTP)

The RAM trace port (RTP) is used to log data writes to internal SRAM. This functionality is used in calibration to keep a remote mirror copy of device memory.

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The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Use of MPUs to Block Access to Memory-Mapped Debug
- Disable the RTP Pin Interface
- Hardware Disable of JTAG Port
- Lockout of JTAG Access Using AJSM
- Internal Watchdog
- External Watchdog

6.38.1 Notes

For the purposes of FIT estimations and safety use, this module is considered strictly as a Debug/Trace related module and active use during an application runtime is not considered even if used solely as GPIO.

6.39 Parameter Overlay Module (POM)

The parameter overlay module (POM) is used to redirect Flash access to a different internal or external memory. This functionality is used during calibration to test updated sections of code or data without the need to perform a time consuming erase and program of Flash or rebuild of code. The POM is implemented as a CoreSight compliant peripheral.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Hardware Disable of JTAG Port
- Lockout of JTAG Access Using AJSM
- Use of MPUs to Block Access to Memory Mapped Debug
- Use of Coresight Debug Logic Key Enable Scheme
- Internal Watchdog
- External Watchdog

6.40 Error Profiling Controller (EPC)

This device includes an Error Profiling Controller (EPC) module. The primary goal of this module is to provide a unified correctable ECC error (single bit ECC fault) profiling capability and error address cache on ECC failures in system bus memory slaves like Flash, FEE, and SRAM. The secondary goal of this module is to provide an ECC error reporting capability for bus masters, which do not natively have ECC logic built in like the DMA and TUs. The ECC generation and evaluation logic for bus masters such as DMA and the TUs are built into the CPU Interconnect Subsystem.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- Periodic Software Readback of Static Configuration Registers
- Boot Time Software Test of Error Path Reporting
- Periodic Software Test of Error Path Reporting
- Software Readback of Written Configuration

The following tests can be applied as test-for-diagnostics on this module to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- Internal Watchdog
- External Watchdog
- CPU Lockstep Compare
- Flash Data ECC
- SRAM Data ECC

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6.41 Temperature Sensor

This device includes three on-chip temperature sensors used for measurement of die temperature. One of the channels in MibADC1 and two of the channels in MibADC2 can be used to convert temperature measurements from the three on-chip temperature sensors.

The following tests can be applied as diagnostics for this module (to provide diagnostic coverage on a specific function):

- CPU Lockstep Compare
- Internal Watchdog
- External Watchdog
- Flash Data ECC
- SRAM Data ECC
- Redundant Temperature Sensors

The following tests can also be applied as a test-for-diagnostic on this module, and could be used to meet Latent Fault Metric Requirements of ISO26262 (in combination with other diagnostics on the primary function):

- CPU Lockstep Compare
- Internal Watchdog
- External Watchdog
- Flash Data ECC
- SRAM Data ECC

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7 Brief Description of Diagnostics

This section provides a brief summary of the diagnostic mechanisms available on this device. For a detailed description or implementation details for a diagnostic, see the device-specific technical reference manual. For information on safety-pertinent information such as test execution time, error reporting time, action on detected faults, and diagnostic operation modes, see Appendix A.

7.1 1oo2 Software Voting Using Secondary Free Running Counter

The RTI module contains at minimum two up-counters that can be used to provide an operating system time-tick. While one up-counter is used as the operating system timebase, it is possible to use the second up counter as a diagnostic on the first, via periodic check via software of the counter values in the two timers. The PMU CPU cycle counter inside the Cortex-R5F CPU can also be used to support such a diagnostic. Error response, diagnostic testability, and any necessary software requirements are defined by the software implemented by the system integrator.

7.2 Bit Error Detection

When this module transmits information onto it's bus, it can also monitor the bus to ensure that the transmitted information is appearing as expected on the bus. If the expected values are not read back from the bus, the hardware can flag the error and signal an interrupt to the CPU. This feature must be enabled and configured in software.

7.3 Bit Multiplexing in FEE Memory Array

The FEE modules implemented in the Hercules architecture have a bit multiplexing scheme implemented such that the bits accessed to generate a logical (CPU) word are not physically adjacent. This scheme helps to reduce the probability of physical multi-bit faults resulting in logical multi-bit faults; rather they manifest as multiple single bit faults. As the SECDED FEE ECC can correct a single bit fault in a logical word, this scheme improves the usefulness of the FEE ECC diagnostic. Bit multiplexing is a feature of the architecture and cannot be modified by the software.

7.4 Bit Multiplexing in Flash Memory Array

The Flash modules implemented in the Hercules architecture have a bit multiplexing scheme implemented such that the bits accessed to generate a logical (CPU) word are not physically adjacent. This scheme helps to reduce the probability of physical multi-bit faults resulting in logical multi-bit faults; rather they manifest as multiple single bit faults. As the SECDED Flash ECC can correct a single bit fault in a logical word, this scheme improves the usefulness of the Flash ECC diagnostic. Bit multiplexing is a feature of the architecture and cannot be modified by the software.

7.5 Bit Multiplexing in Primary SRAM Memory Array

The SRAM modules implemented in the Hercules architecture have a bit multiplexing scheme implemented such that the bits accessed to generate a logical (CPU) word are not physically adjacent. This scheme helps to reduce the probability of physical multi-bit faults resulting in logical multi-bit faults; rather they manifest as multiple single bit faults. As the SECDED SRAM ECC can correct a single bit fault in a logical word, this scheme improves the usefulness of the SRAM ECC diagnostic. Bit multiplexing is a feature of the architecture and cannot be modified by the software.

7.6 Bit Multiplexing in Peripheral SRAM Memory Array

This module's SRAM is implemented with a bit multiplexing scheme such that the bits accessed to generate a logical (CPU) word are not physically adjacent. This scheme helps to reduce the probability of physical multi-bit faults resulting in logical multi-bit faults; rather they manifest as multiple single bit faults.

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7.7 CPU Illegal Operation and Instruction Trapping

The Cortex-R5F CPU includes diagnostics for illegal operations and instructions that can serve as safety mechanisms. Many of these traps are not enabled after reset and must be configured by the software. For more information on enabling traps, see the *Cortex-R5 and Cortex-R5F Technical Reference Manuall* located at http://infocenter.arm.com/help/topic/com.arm.doc.ddi0460d/index.html. Examples of CPU illegal operation and instruction traps include:

- Illegal instruction
- Floating-point underflow and overflow
- Floating point divide by zero
- Privilege violation

7.8 Logic Built In Self-Test (LBIST)

The Hercules family architecture supports the use of a hardware logic BIST (LBIST) engine self-test controller (STC). This logic is used to provide a very high diagnostic coverage on the lockstep CPUs or N2HET at a transistor level. This logic utilizes the same design for test (DFT) structures inserted into the device for rapid execution of high quality manufacturing tests, but with an internal test engine rather than external automated test equipment (ATE). This technique has proven to be drastically more effective than software-based tests of logic, particularly for the complex logic structures seen in a modern CPU.

The LBIST tests must be triggered by the software. User may elect to run all tests, or only a subset of the tests based on the execution time, which can be allocated to the LBIST diagnostic. This time sliced test feature enables the LBIST to be used effectively as a runtime diagnostic with execution of test time slices per safety critical loop as well as a comprehensive test for CPU or N2HET Logic fault during MCU initialization.

Execution of the LBIST STC results in a much higher level of transistor switching per clock cycle than during normal software execution due to the high efficiency of the test. A software control is implemented in the STC that allows the user to reduce the CPU clock for the duration of the test. This feature allows the user to make a compromise between fast execution with higher current consumption or slower execution with reduced current consumption.

The CPU LBIST mechanism requires isolation of the CPU from the remainder of device logic while under test. It is also necessary to perform a complete context save before the LBIST. When test execution is complete, the CPU will be reset. The remainder of device logic continues normal operation. After CPU reset, software should read the system control module SYSESR to identify the reason for the reset and can then restore the CPU context.

The N2HET LBIST mechanism requires the module be placed in reset while under test. Since the module is brought through reset at the completion of the test, the module must be re-initialized and timer application re-started at the completion of the test. The remainder of device logic continues normal operation.

LBIST logic includes capabilities for testing proper operation of the diagnostic. As the test time for the diagnostic is deterministic, a timeout counter has been included that can detect a failure to complete the test within expected time. In addition, there is the possibility to force an input error to check error detection and propagation of the error response at system level. This test is performed as follows:

1. Enable the self_check_key and fault_ins bits in the STCSTSCR register.
2. Enable STC test interval zero and execute the test
3. Upon completion of test, the fail bit should be set to 1 in the STC global status register.
4. Disable either or both the self_check_key and fault_ins bits in the STCSTSCR register.
5. Restart the self-test by programming bit 0 of the STCGCR, causing self-test restart.
6. Upon completion of the test, the fail bit should be set to 0 in the STC global status register.

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7.9 Logic Built In Self-Test (LBIST) Auto-Coverage

The LBIST diagnostic is based on a 128-bit signature capture. For a given test, only one code is valid out of 2^128 possibilities. Therefore, if there is a fault in the LBIST logic, it is extremely unlikely that the correct passing code will be generated via the fault. The cyclical check applied by the LBIST module provides an inherent level of self checking (auto-coverage), which can be considered for application in latent fault diagnostics.

7.10 CPU Lockstep Compare

The Hercules product family includes a lockstep processor diagnostic. This feature includes the addition of a diagnostic Cortex-R5F CPU that is combined into a 1oo1D (single channel with diagnostic channel) configuration with the application CPU. Both the application CPU and the diagnostic CPU are fed the same input signals, which results in both CPUs running the same software. The diagnostic and application CPUs should generate the same output. The core compare module (CCM) compares the CPU outputs and flags all mis-compares to the ESM.

The lockstep diagnostic is continually operating from power-on reset. The lockstep checking is disabled when the CPU is placed into a halting debug state and can only be restored to operation after a subsequent reset. Lockstep functionality can also be disabled temporarily when executing the self-test checking functionality of the CCM.

During the first cycles of CPU operation after reset, it is necessary to execute a short initialization code that sets all CPU registers to a known state. This code sequence can be found in the device-specific data sheet. Execution of this code sequence as the first instructions out of reset is mandatory.

The CCM logic provides self-test and error forcing capability via software triggered hardware. The self-test ensures that the CCM compare logic is working properly. The error forcing capability allows you to test the system level response to a lockstep mis-compare.

7.11 VIM Lockstep Compare

There are two VIMs (VIM1 and VIM2) that run in lockstep. Each will output the interrupt signals such as nIRQ/nFIQ/IRQVECADDR. These signals are continuously compared by the CCM-R5. A mismatch detected will result in an ESM error.

7.12 Lockstep Comparator Self-Test

The lockstep comparator (CCM) diagnostic includes self-test features to check for proper operation of the lockstep comparator (CPU, PSCON, and VIM Lockstep features).

7.13 CPU Online Profiling Using the Performance Monitoring Unit

The Cortex-R5F CPU includes a performance monitoring unit (PMU). This logic is intended to be used for debug and code profiling purposes, but it can also be utilized as a safety mechanism. The PMU includes a CPU cycle counter as well as three additional counters, which can be programmed to count a number of different CPU events. For a complete list of CPU events that can be monitored, see the *Cortex-R5 and Cortex-R5F Technical Reference Manuall* located at http://infocenter.arm.com/help/topic/com.arm.doc.ddi0460d/index.html. Examples of the CPU events that can be monitored include:

- Number of cycles in which an ECC or parity error is detected by diagnostics in CPU
- Number of cycles in which the CPU is in the livelock state
- Number of instructions executed
- Number of cycles in which an exception is taken

With such information available, it is possible to generate a software routine that periodically checks the PMU counter values and compares these values to the profile expected during normal operation. The PMU is not enabled by default and must be configured via software. As the PMU is implemented internal to the CPU, it is checked for proper operation on a cycle by cycle basis by the lockstep diagnostic and can also be checked via execution of the LBIST STC diagnostic.

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7.14 CPU Memory Protection Unit (MPU)

The Hercules implementation of the Cortex-R5F CPU includes an MPU. The MPU logic can be used to provide spatial separation of software tasks in the device memory. It is expected that the operating system controls the MPU and changes the MPU settings based on the needs of each task. A violation of a configured memory protection policy results in a CPU abort.

The MPU can also be used to configure the memory ordering policies of the memory system. By default, all peripheral accesses are strongly ordered type - meaning that all transactions complete in the sequence they are issued and no write transactions are buffered. If desired, the operating system can configure accesses to be device type - meaning that writes are buffered. This can improve performance over a strongly ordered model, at the cost of some determinism. The system control module and other modules deemed to have critical configurations can be set to a strongly ordered access model to facilitate a deterministic performance when performing reads/writes of these registers. As the MPU is internal to the CPU core, proper operation is checked via the lockstep CPU mechanism. In addition, the LBIST STC diagnostic provides a check of the MPU when it performs a test of the CPU.

As the MPU is internal to the CPU core, proper operation is checked via the lockstep CPU mechanism. In addition, the LBIST STC diagnostic provides a check of the MPU when it performs a test of the CPU.

7.15 CRC Auto-coverage

The CRC diagnostic is based on a 64-bit polynomial. For a given test, only one code is valid out of 2^64 possibilities. Therefore, if there is a fault in the CRC logic, it is extremely unlikely that the correct passing code will be generated via the fault.

7.16 CRC in Message

This module includes a CRC in Message safety mechanism. The CRC values are calculated and transmitted by the transmitter, and then re-calculated by the receiver. If the CRC value calculated by the receiver does not match the transmitted CRC value, a CRC error will be flagged. Error response and any necessary software requirements are defined by the system integrator.

7.17 DCAN Acknowledge Error Detection

When a node on the CAN network receives a transmitted message, it sends an acknowledgment that it received the message successfully. When a transmitted message is not acknowledged by the recipient node, the transmitting DCAN will flag an Acknowledge Error. Error response and any necessary software requirements are defined by the system integrator.

7.18 DCAN Form Error Detection

Certain types of frames in the DCAN have a fixed format per the CAN protocol. When a receiver receives a bit in one of these frames that violates the protocol, the module will flag a Form Error. Error response and any necessary software requirements are defined by the system integrator.

7.19 DCAN Stuff Error Detection

In the CAN message protocol, several of the frame segments are coded through bit stuffing. Whenever a transmitter detects five consecutive bits of identical value in the bitstream to be transmitted, it automatically inserts a complementary bit into the actual transmitted bit stream. If a 6th consecutive equal bit is detected in a received segment that should have been coded by bit stuffing, the DCAN module will flag a Stuff Error. Error response and any necessary software requirements are defined by the system integrator.

7.20 DCAN Protocol CRC in Message

The CAN Protocol includes a CRC in Message. The CRC values are calculated and transmitted by the transmitter, and then re-calculated by the receiver. If the CRC value calculated by the receiver does not match the transmitted CRC value, a CRC error will be flagged. Error response and any necessary software requirements are defined by the system integrator.

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7.21 Disable the DMM Pin Interface

The DMM peripheral has a device level parallel input port, which is typically driven by an external tool or the ram trace port (RTP). For production usage, the DMM pin interface can be disabled to block data input. One possible method is to drive the DMM clock input low and to drive the active low DMM enable input high.

7.22 Disable the RTP Pin Interface

The RTP peripheral has a device level parallel output port that is typically connected to an external tool or used to drive the input of a DMM. For production usage, the RTP pin interface can be disabled to block data output. One possible method is to drive the RTP clock input low and to drive the active low RTP enable input high.

7.23 Dual Clock Comparator (DCC)

One or more dual clock comparators (DCCs) are implemented as multi-purpose safety diagnostics. The DCC can be used to detect incorrect frequencies and drift between clock sources. The DCC is composed of two counter blocks: one is used as a reference timebase and a second is used for the clock under test. Both reference clock and clock under test may be selected via software, as can the expected ratio of clock frequencies. Deviation from the expected ratio generates an error indication to the ESM. For more information on the clock selection options implemented, see the device-specific data sheet. For DCC programming details, see the device-specific technical reference manual.

The DCC diagnostic is not enabled by default and must be enabled via software. It is possible to disable and configure this diagnostic via software. The cyclical check applied by the DCC module provides an inherent level of self checking (auto-coverage), which can be considered for application in latent fault diagnostics.

7.24 Autoload Self-Test

The EFuse and OTP autoload controllers have self-test logic that executes automatically after autoload completion. This is not a diagnostic that can be run separately, but is a given when Autoload self-test executes. The test can be subsequently triggered by the software. Error is indicated via ESM.

7.25 Efuse Autoload Self-Test Auto-Coverage

As a test-for-diagnostic the Autoload self-test logic implementation provides test coverage for its logic. This is not a diagnostic that can be run separately, but is a given when Autoload self-test executes.

7.26 EFuse ECC

The EFuses utilize a SECDED ECC diagnostic to detect (and correct) incorrect configuration values. Errors are indicated via ESM. The cyclical check applied by the ECC logic provides an inherent level of self checking (auto-coverage), which can be considered for application in latent fault diagnostics.

7.27 EFuse ECC Logic Self-Test

As a test-for-diagnostic, it is possible to test the functionality of the Efuse ECC logic by performing a self-test supported by hardware and checking for errors

7.28 eQEP Quadrature Watchdog

The eQEP peripheral contains a 16-bit watchdog timer that monitors the quadrature-clock to indicate proper operation of the motion-control system. The eQEP watchdog timer is clocked from VCLK/64 and the quadrate clock event (pulse) resets the watchdog timer. If no quadrature-clock event is detected until a period match, then the watchdog timer will time out and the watchdog interrupt flag will be set. The time-out value is programmable through the watchdog period register.

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7.29 eQEP Software Test of Quadrature Watchdog Functionality

A software test can be used to test for basic functionality of the quadrature watchdog as well as to insert diagnostic errors and check for proper error response. Such a test can be executed at boot or periodically. Software requirements necessary are defined by the software implemented by the system integrator.

7.30 Error Trapping - IOMM

The IOMM can trap address and privilege errors on received transactions. Transactions that attempt to access un-implemented locations in the IOMM chip select result in an ESM response. Transactions that are not in privileged mode also generate an ESM response.

This feature is enabled after reset. Software cannot disable this feature.

7.31 Error Trapping (including Peripheral Slave Error Trapping) - L2/L3 Interconnect

The L2 and L3 interconnect subsystems (L2: CPU Interconnect Subsystem and Peripheral Interconnect Subsystem, L3: PCR1, PCR2, PCR3) includes a number of mechanisms to detect and trap errors. Address decoders in the diagnostic respond with a bus error to the initiator if a bus transaction does not decode to a valid target. Logic is also present that can detect the timeout of certain transactions and respond with a bus error to the transaction initiator. In addition to testing for slaves directly connected to the L2 interconnect, peripheral slaves which are connected to L3 (PCR) interconnect can support error trapping.

The interconnect error trapping functionality is enabled by default and cannot be disabled by the software. These features can be tested via software through the insertion of invalid bus transactions.

7.32 Ethernet Alignment Error Detection

If a received Ethernet message frame contains an uneven byte count (not a multiple of 8), an Alignment Error will be flagged by the Ethernet hardware. Error response and any necessary software requirements are defined by the system integrator.

7.33 Ethernet Physical Layer Fault

If the EMAC module fails to read back the values that it is attempting to write to the physical layer (PHY), the hardware will indicate a Physical Layer Fault. Error response and any necessary software requirements are defined by the system integrator.

7.34 External Monitoring of Warm Reset (nRST)

The nRST warm reset signal is implemented as an I/O. An external monitor can be utilized to detect expected or unexpected changes to the state of the internal warm reset control signal. Error response, diagnostic testability, and any necessary software requirements are defined by the external monitor selected by the system integrator.

7.35 External Monitoring via ECLK

The Hercules platform provides the capability to export select internal clocking signals for external monitoring. This feature can be configured via software by programming registers in the system control module. To determine the number of external clock outputs implemented and the register mapping of internal clocks that can be exported, see the device-specific data sheet.

Export of internal clocks on the ECLK outputs is not enabled by default and must be enabled via software. It is possible to disable and configure this diagnostic via software.

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7.36 External Voltage Supervisor

The Hercules platform encourages the use of an external voltage supervisor to monitor all voltage rails given that the use of an external voltage supervisor improves overall system safety by means of improved diversity and reduction of dependent fault potential. The voltage supervisor should be configured with overvoltage and undervoltage thresholds matching the voltage ranges supported by the target device (as noted in the device-specific data sheet). Error response, diagnostic testability, and any necessary software requirements are defined by the external voltage supervisor selected by the system integrator.

7.37 External Watchdog

When using an external watchdog, there is a possibility to reduce common mode failure with the MCU clocking system, as the watchdog can utilize clock, reset, and power that are separate from the system being monitored. Error response, diagnostic testability, and any necessary software requirements are defined by the external watchdog selected by the system integrator. The use of an external watchdog over the internally provided watchdogs is suggested to ensure optimization of diversity of hardware and elimination of potential dependent faults. This inclusion of the external watchdog at the system level is dependent on the needs of the end application and the specific requirements of the overall system.

An internal or external watchdog can provide an indication of inadvertent activation of logic which results in impact to safety critical execution. Any watchdog added externally should include a combination of temporal and logical monitoring of program sequence or other appropriate methods such that high diagnostic effectiveness can be claimed.

7.38 FEE Contents Check by Hardware CRC

The platform includes a hardware CRC implementing the ISO CRC-64 standard polynomial. The CRC module can be used to test the integrity of FEE contents by calculating a CRC for all FEE contents and comparing this value to a previously generated "golden" CRC. The read of FEE contents to the CRC can be done by the CPU or the DMA. The comparison of results, indication of fault, and fault response are the responsibility of the software managing the test. Depending on the software driver scheme used to support FEE, it may be necessary to execute this check driven by the CPU FEE driver. It is common to perform a CRC integrity check of FEE contents at boot time.

The cyclical check applied by the hardware CRC module provides an inherent level of self checking (auto-coverage), which can be considered for application in latent fault diagnostics.

7.39 FEE Data ECC

The on-chip FEE memory is supported by SECDED ECC diagnostic. The FEE SECDED ECC controller utilizes the same ECC algorithm as used in the main Flash memory; 8-bit of code are implemented per 64-bit of data. Detected uncorrectable errors result in a ESM error. In the case of a single bit error the CPU export the error detection events to the EPC module, in case of a double bit error the CPU exports the error event to the ESM module. The Cortex-R5F PMU must first be set to export events to an external monitor. The address of the memory, for an single bit ECC error, is logged in the EPC module.

The address ECC feature is always enabled. Use of this feature is mandatory. The cyclical check applied by the FEE ECC logic provides an inherent level of self checking (autocoverage), which can be considered for application in latent fault diagnostics.

7.40 FEE Sector Protection

It is possible to prevent a write operation on an FEE sector by the software configuration of the Flash wrapper. The sector protection registers, BSE, contain a bit for each sector in the FEE bank, which enables or disables a sector for write operation. The BSE register can only be written in privilege mode while the software PROTLIDIS protection bit is set high. This mechanism can reduce probability of unintended programming of FEE memory.

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7.41 Flash Address and Control Bus Parity

The CPU bus interconnect to Flash memory (CPU Interconnect Subsystem) is supported by a parity diagnostic on the address and control signals. The parity is generated by the CPU and evaluated by the Flash wrapper. Detected errors are signaled to the ESM by the Flash wrapper and the error address is captured in the Flash wrapper.

This diagnostic is enabled at reset. The diagnostic can be disabled by programmation of the BUS_PAR_DIS key in the FPAR_OVR register of the Flash wrapper.

7.42 Flash Contents Check by Hardware CRC

The platform includes a hardware cyclic redundancy check (CRC) implementing the ISO CRC-64 standard polynomial. The CRC module can be used to test the integrity of Flash contents by calculating a CRC for all Flash contents and comparing this value to a previously generated "golden" CRC. The read of Flash contents to the CRC can be done by CPU or the DMA. The comparison of results, indication of fault, and fault response are the responsibility of the software managing the test. It is a common approach to perform a CRC integrity check of Flash contents at boot time.

The cyclical check applied by the hardware CRC module provides an inherent level of self checking (auto-coverage), which can be considered for application in latent fault diagnostics.

7.43 Flash ECC

The on-chip Flash memory is supported by single error correction, dual error detection (SECDED) errorcorrecting code (ECC) diagnostic. It is connected by a 64-bit-wide data bus interface to the CPU Interconnect Subsystem. In this SECDED scheme, an 8-bit code word is used to store the ECC data as calculated over the 64-bit data bus.

The ECC logic for the Flash access is located in the bus masters in case of the CPU or the in the CPU Interconnect Subsystem for other master such as the DMA and the TU's. All Flash transactions have ECC on the data payload. ECC evaluation is done by the ECC control logic inside the bus master or the CPU Interconnect Subsystem. This scheme provides end-to-end diagnostics on the transmissions between the bus master and Flash memory. Detected uncorrectable errors result in a ESM error. In the case of a single bit error the CPU export the error detection events to the EPC module, in case of a double bit error the CPU exports the error event to the ESM module. The Cortex-R5F PMU must first be set to export events to an exhttp://infocenter.arm.com/help/topic/com.arm.doc.ddi0460d/index.htmlternal monitor. The address of the memory, for a single bit ECC error, is logged in the EPC module. For more details on the ECC implementation in the CPU bus master, see the Cortex-R5 and Cortex-R5F Technical Reference Manual located at .

The ECC is always enabled for the Flash. The cyclical check applied by the ECC logic provides an inherent level of self checking (autocoverage), which can be considered for application in latent fault diagnostics.

7.44 Flash Hard Error Cache and Livelock

If ECC correction is enabled, corrected data values are stored in an internal one entry hard error cache. It is not possible to automatically re-write the corrected data values back to the Flash, as the Flash is a non-volatile memory that has special programming requirements.

A single instruction and its data may not have more than one correctable error. In case more than one correctable error is detected, it is possible to overrun the hard error cache and put the processor into an inoperable livelock state. Cases that can generate a livelock include:

- Two single bit errors in a 64-bit unaligned 32-bit Thumb-2 instruction fetch
- A single bit error in a load instruction (LDR or LDM) followed by a single bit error in the instruction's data payload

Livelock is indicated via the ESM and typically requires a reset for recovery to be attempted. Livelock on a Flash interface transaction can be an indication of severe permanent fault in the Flash memory.

This feature is enabled at reset and cannot be disabled by the software.

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7.45 Flash Sector Protection

It is possible to prevent a write operation on a sector by the software configuration of the Flash wrapper. The sector protection registers, Bank Sector Enable Register (BSE), contain a bit for each sector in the Flash bank, which enables or disables a sector for write operation. The BSE register can only be written in privilege mode while the software PROTLIDIS protection bit is set high. This mechanism can reduce probability of unintended programming of Flash memory.

7.46 Flash Wrapper Address ECC

In addition to the ECC functionality in the CPU, the flash wrapper extends the ECC capability to include address. The standard SECDED ECC scheme utilized has 8-bit of code for 64-bit of data. Extensions of the Hamming equations allow additional bits of data beyond 64 bits to be encoded into 8 bits of code with the same Hamming distance. The flash wrapper design takes advantage of this by incorporating the address of the transaction into the Flash memory ECC data. All values stored in the Flash memory have the address added into the Flash ECC. Upon read of data from Flash, the flash wrapper will strip the address component from the ECC and provide the regenerated ECC code to the bus master. Errors in the address can result in a multi-bit ECC failure as seen by the bus master.

The address ECC feature is always enabled. The cyclical check applied by the flash wrapper address ECC module provides an inherent level of self checking (autocoverage), which can be considered for application in latent fault diagnostics.

7.47 Flash Wrapper Diag Mode 5 Test

An error can be inserted into the lockstep address tag registers to cause a mismatch between primary and duplicate registers. This diag mode can be used to test the Primary Flash interface.

7.48 Flash Wrapper Diag Mode 7 Test

In order to test the ECC logic of the CPU incorrect ECC can be fed into the CPU. In this diagnostic mode one or more specific bits can be flipped. This diag mode can be used to test the Primary Flash interface.

7.49 Glitch Filtering on nRST and nPORRST

Glitch filters are implemented on the cold and warm reset pins of the device. These structures filter out noise and transient signal spikes on the input reset pins in order to reduce unintended activation of the reset circuitry. The glitch filters are continuously operating and their behavior cannot be changed by the software.

7.50 Hardware CRC Check of External Memory

The contents of external memories connected to the EMIF can be tested periodically using the hardware CRC-64 diagnostic. This diagnostic is especially useful for static memory contents, but is less useful if the memory contents change dynamically in application. For more details on this diagnostic, see SRAM Hardware CRC-64.

7.51 Hardware CRC Check of OTP Contents

The platform includes a hardware cyclic redundancy check (CRC) implementing the ISO CRC-64 standard polynomial. The CRC module can be used to test the integrity of OTP contents by calculating a CRC for all Flash contents and comparing this value to a previously generated "golden" CRC. The read of Flash contents to the CRC can be done by the CPU or the DMA. The comparison of results, indication of fault, and fault response are the responsibility of the software managing the test. OTP is loaded at boot time and a CRC check of OTP at boot time is an effective method of ensuring proper device configuration at boot up.

7.52 Hardware Disable of JTAG Port

The JTAG debug port can be physically disabled to prevent JTAG access in deployed systems. The most prevalent scheme is to hold test clock (TCK) to ground and hold test mode select (TMS) high, though alternate schemes are possible.

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Disabling of the JTAG port also provides coverage for inadvertent activation of many debug activities, since these are often initiated via an external debug tool which writes commands to the device using the JTAG port.

7.53 Information Redundancy Techniques

Information redundancy techniques can be applied via software as an additional runtime diagnostic for this module. There are many techniques that can be applied, such as read back of written values and multiple output of the same data with comparison of results. Error response, diagnostic testability, and any necessary software requirements are defined by the software implemented by the system integrator.

7.54 Information Redundancy Techniques - CPU Specific

Information redundancy techniques can be applied via software as an additional runtime diagnostic on the CPU execution. There are many techniques that can be applied, such as redundant execution using diverse algorithms with comparison of results. Error response, diagnostic testability, and any necessary software requirements are defined by the software implemented by the system integrator.

7.55 Information Redundancy Techniques - DCAN Specific

Information redundancy techniques can be applied via software as an additional runtime diagnostic for CAN communication. There are many techniques that can be applied, such as read back of written values and multiple reads of the same target data with comparison of results.

In order to provide diagnostic coverage for network elements outside the MCU (wiring harness, connectors, transceiver) end-to-end safing mechanisms are applied. These mechanisms can also provide diagnostic coverage inside the MCU. There are many different schemes applied, such as additional message checksums, redundant transmissions, time diversity in transmissions, and so forth. Most commonly checksums are added to the payload section of a transmission to ensure the correctness of a transmission. These checksums are applied in addition to any protocol level parity and checksums. As the checksum is generated and evaluated by the software at either end of the communication, the whole communication path is safed, resulting in end-to-end safing.

Error response, diagnostic testability, and any necessary software requirements are defined by the system integrator.

7.56 Information Redundancy Techniques - DMA Specific

Information redundancy techniques can be applied using the DMA module. There are many techniques that can be applied, such as read back of written values and multiple reads of the same target data with comparison of results.

Error response, diagnostic testability, and any necessary software requirements are defined by the software implemented by the system integrator.

7.57 Information Redundancy Techniques - N2HET Specific

Information redundancy techniques can be applied via software or system as an additional runtime diagnostic on N2HET operations. There are many techniques that can be applied, such as multiple sampling of a single input channel, sampling of two or more input channels, and read back of written output. Splitting functionality between the two implemented N2HET modules can provide reduced probability of common mode failure as opposed to implementing a function and its diagnostic on a single N2HET.

Error response, diagnostic testability, and any necessary software requirements are defined by the software implemented by the system integrator.

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7.58 Internal Voltage Monitor (VMON)

The Hercules platform incorporates a simple embedded voltage monitor (VMON) that can detect grossly out of range supply voltages. The VMON operates continuously and requires no software configuration or CPU overhead. VMON monitors the core and I/O supplies. When the supplies are grossly over or under specified voltages (for product specific values, see the device-specific data sheet), the VMON drives the nPORRST (power-on reset) signal internally. This response holds the device in the safe operating state. When power supplies are in range, the VMON will not interfere with the nPORRST signal. For more information on VMON operation, see the device-specific data sheet.

The VMON is a continuously operating diagnostic. It is not possible to disable the VMON diagnostic. In-system test of the VMON diagnostic is generally not feasible as tight control of external voltages is needed to trigger the VMON error response. If improperly applied, such voltage could result in permanent damage to the MCU.

7.59 Internal Watchdog

The Hercules platform supports the use of an internal watchdog that is implemented in the real time interrupt (RTI) module. The internal watchdog has two modes of operation: digital watchdog (DWD) and digital windowed watchdog (DWWD). The modes of operation are mutually exclusive, the designer can elect to use one mode or the other but not both at the same time. For details of programming the internal watchdogs, see the device-specific technical reference manual.

The DWD is a traditional single threshold watchdog. The user programs a timeout value to the watchdog and must provide a predetermined "pet" response to the watchdog before the timeout counter expires. Expiration of the timeout counter or an incorrect "pet" response triggers an error response. The DWD can issue either an internal (warm) system reset or a CPU non-maskable interrupt upon detection of a failure. The DWD is not enabled after reset. Once enabled by the software, the DWD cannot be disabled except by system reset or power-on reset. Users should take care not to change the DWD clock source after enabling the module, else behavior is unpredictable.

The DWWD is a traditional windowed watchdog. The user programs an upper bound and lower bound to create a time window during which the software must provide a predetermined "pet" response to the watchdog. Failure to receive the correct response within the time window or an incorrect "pet" response triggers an error response. The DWWD can issue either an internal (warm) system reset or a CPU non-maskable interrupt upon detection of a failure. The DWWD is not enabled after reset. Once enabled by the software, the DWWD cannot be disabled except by system reset or power-on reset. The use of the time window allows detection of additional clocking failure modes as compared to the DWD implementation.

An internal or external watchdog can provide an indication of inadvertent activation of logic which results in impact to safety critical execution, such as an inadvertent activation of JTAG logic.

7.60 IOMM Master ID Filtering

The IOMM checks the master ID of all incoming bus transactions. Only transactions from the CPU are allowed. Illegal transactions result in a bus error response to the offending bus master and the write to IOMM will be discarded. This feature is enabled after reset. Software cannot disable this feature.

7.61 LIN Checksum Error Detection

After message reception, the LIN performs a CRC check on all received data bytes. This data is then compared to the checksum for the message that was transmitted by the sender. If there is a mismatch, the LIN hardware can flag a Checksum Error and generate an interrupt to the CPU. This feature must be enabled and configured in software.

7.62 LIN No-Response Error Detection

If no response is received within a configurable time period after the LIN master completes a header transmission, the LIN hardware can flag a No-Response Error and generate an interrupt to the CPU. This feature must be enabled and configured in software.

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7.63 LIN Physical Bus Error Detection

If no message can be generated on the LIN Bus, the LIN hardware can flag the error and generate a physical bus error and generate an interrupt to the CPU. This feature must be enabled and configured in software.

7.64 LIN / SCI Bit Error Detection

When this module transmits information on the LIN Bus, it also monitors the LIN Bus to ensure that the transmitted information is appearing as expected on the LIN Bus. If the expected values are not read back from the LIN Bus, the hardware can flag the error and signal an interrupt to the CPU. This feature must be enabled and configured in software.

7.65 LIN / SCI Frame Error Detection

When receiving serial data, each byte of information on the SCI has an expected format. If the received message does not match this error, the SCI hardware can flag an error and generate an interrupt to the CPU. This feature must be enabled and configured in software.

7.66 LIN / SCI Overrun Error Detection

If the SCI RX buffer receives new data before the previous data has been read, the existing data will be overwritten and lost. If this occurs, the SCI hardware can flag the error and generate an interrupt to the CPU. This feature must be enabled and configured in software.

7.67 Locking Mechanism for Control Registers

The IOMM contains a two stage lock mechanism for protection of critical control registers. To change the configuration of the pin multiplexing, the user must write two specific 32-bit values to the "kicker" registers in a defined sequence. When complete, the lock function must be reset. Write accesses, when the registers are locked, will not update the registers, nor will they generate an error response. This feature is enabled after reset. Software can disable the lock by unlocking and never re-locking.

7.68 Lockout of JTAG Access Using AJSM

The Hercules platform includes the Advanced JTAG Security Module (AJSM) as support for managing debug access on deployed devices. AJSM can be used to program a unique access key to the OTP Flash memory. Subsequent debug accesses must unlock the AJSM with the correct key sequence in order to gain access to the JTAG-based debug, trace, and calibration logic. An error in unlocking the AJSM results in no error response and no access to the debug logic.

7.69 Low Power Oscillator Clock Detector (LPOCLKDET)

The low-power oscillator clock detector (LPOCLKDET) is a safety diagnostic that can be used to detect failure of the primary clock oscillator. LPOCLKDET utilizes the embedded high-frequency, low-power oscillator (HF LPO). The clock detect circuit works by checking for a rising edge on one clock (oscillator or HF LPO) between rising edges of the other clock. The result is that in addition to flagging incorrect, repeating frequencies, the circuit also fails due to transient conditions. The low end of the clock detect window ignores a transient low phase of at least 12 HF LPO cycles. Note that this filtering of the transient response does not change the input frequency range. The LPOCLKDET circuitry is enabled by default during the power-on reset state. The diagnostic can be disabled via software.

7.70 Memory Protection Unit (MPU) for Non-CPU Bus Masters

Many non-CPU bus masters include an MPU. The MPU logic can be used to provide spatial separation of software tasks in the device memory. It is expected that the module's software driver controls the MPU and changes the MPU settings based on the needs of system implementation. A violation of a configured memory protection policy will result in an ESM error. The MPU is not enabled at reset. Software must enable, configure and test the MPU.

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7.71 MibADC Calibration

The Hercules MibADC module implements calibration logic normally used to improve converter accuracy. This logic can also be used as a safety mechanism. Software comparison of the conversion of known reference values from the calibration logic can provide a diagnostic on converter functionality. Repeated execution of the calibration routine can be used to detect drift during application. Software must configure and enable and evaluate the result of this diagnostic. Error response, diagnostic testability, and any necessary software requirements are defined by the software implemented by the system integrator.

7.72 MibADC Information Redundancy Techniques

Information redundancy techniques can be applied via software as an additional runtime diagnostic on ADC conversions. There are many techniques that can be applied, such as multiple conversions using shared channels and using both converters, using multiple channels on the same converter or by doing multiple conversions on the same channel followed with comparison of results. Filtering or a plausibility check for the converted values are in expected range can also improve diagnostic coverage. Error response, diagnostic testability, and any necessary software requirements are defined by the software implemented by the system integrator.

7.73 MibADC Input Self-Test

The Hercules MibADC module implements an input self-test engine that can detect short to ADREFLO, ADREFHI or open input. Software must configure and enable and evaluate the result of this diagnostic. Error response, diagnostic testability, and any necessary software requirements are defined by the software implemented by the system integrator.

7.74 MibSPI/SPI Data Length Error Detection

The MibSPI or SPI can detect an error in the length of either a received or a transmitted message. If the transmitted or received message does not match the expected length as specified in the character counter, the MibSPI or SPI module can flag a Data Length error and signal an interrupt to the CPU. This feature must be enabled and configured in software.

7.75 MibSPI/SPI Data Overrun Detection

If the MibSPI or SPI RX buffer receives new data before the previous data has been read, the existing data will be overwritten and lost. If this occurs, the MibSPI or SPI hardware can flag the error and generate an interrupt to the CPU. This feature must be enabled and configured in software.

7.76 MibSPI/SPI Slave Desync Detection

When a slave module supports the generation of an enable signal (ENA), slave de-synchronization can be detected. De-synchronization occurs when the slave misses one or more MibSPI or SPI clock edges coming from the master during transmission. In this case the slave would continue to wait for the remaining clock edges, while holding the ENA signal active. The MibSPI can detect this condition through the use of a configurable counter which starts after message transmission is complete. If the ENA signal coming from the slave does not become inactive by the time the counter overflows, the MibSPI or SPI module can flag a slave desynch error and signal an interrupt to the CPU. This feature must be enabled and configured in software.

7.77 MibSPI/SPI Slave Timeout Detection

When a slave supports the generation of an enable signal (ENA), slave timeout can be detection. Slave timeout occurs when the SPI Master generates a handshake signal to indicate the beginning of a transmission, but the slave does not respond. The MibSPI or SPI can detect this condition through the use of a configurable counter which starts after the handshake transmission. If the slave does not respond by activating the ENA signal by the time the counter expires, the MibSPI or SPI module can flag a Slave Timeout error and signal an interrupt to the CPU. This feature must be enabled and configured in software.

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7.78 Monitoring by Second N2HET

The N2HET supports an internal channel connection between the two N2HET modules to facilitate easy monitoring of one N2HET by a second N2HET. This feature is supported as a convenience to limit the number of functional channels at device level, which must be utilized for diagnostic purposes. Alternatively external connections can be used. Error response, diagnostic testability, and any necessary software requirements are defined by the software implemented by the system integrator.

7.79 Monitoring by eCAP or N2HET

The ePWM outputs can be monitored for proper operation by an input capture peripheral, such as the eCAP or an N2HET channel configured as an input capture. In most cases the connection between ePWM output and monitoring input capture peripheral must be made externally. In some products it may be possible to enable an internal connection using the I/O pin multiplexing logic. Error response, diagnostic testability, and any necessary software requirements are defined by the software implemented by the system integrator.

7.80 Non-Privileged Bus Master Access

This module is a non-privileged bus master. Since writes to critical configuration registers across the MCU is limited to privileged mode transactions only, this mechanism prevents inadvertent configuring of these registers by this module. The operation of this safety mechanism is continuous and cannot be altered by the software. This mechanism can be tested by generating software transactions and reviewing the device response.

7.81 OTP Autoload ECC

The OTP autoload controller utilizes a SECDED ECC diagnostic to detect (and correct) incorrect configuration values. The OTP autoload is executed after every power-on reset. Errors are indicated via ESM. The cyclical check applied by the ECC logic provides an inherent level of self checking (auto-coverage), which can be considered for application in latent fault diagnostics.

7.82 Parity in Message

This module supports insertion of a parity bit into the data payload of every outgoing MIBSPI message by hardware. Evaluation of incoming message parity is also supported by hardware. Detected errors generate an interrupt to the CPU.

7.83 Periodic Hardware CRC Check of OTP Contents

The platform includes a hardware cyclic redundancy check (CRC) implementing the ISO CRC-64 standard polynomial. The CRC module can be used to test the integrity of OTP contents by calculating a CRC for all Flash contents and comparing this value to a previously generated "golden" CRC. The read of Flash contents to the CRC can be done by CPU or the DMA. The comparison of results, indication of fault, and fault response are the responsibility of the software managing the test. The cyclical check applied by the hardware CRC module provides an inherent level of self checking (auto-coverage), which can be considered for application in latent fault diagnostics.

7.84 PCR Access Management: Protection Mode and MasterID Filtering

The peripheral central resource (PCR) provides three safety mechanisms that can limit access to peripherals: clock gating, access privileges, and master ID filtering.

In the case of clock gating the peripheral central resource can be used for clock gated per peripheral chip select in the PCR. This can be utilized to disable unused features such that they cannot interfere with active safety functions.

In addition, each peripheral chip select can be programmed to limit access based on privilege level of transaction. This feature can be used to limit access to entire peripherals to privileged operating system code only.

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Finally, the PCR can be used to limit access to selected peripherals by specific bus masters using masterID filtering. This mechanism provides each PCR segment with the capability to filter transactions from each one of its bus masters to each one of its peripheral selects. This is to provide an additional level of protection for the slaves at a peripheral segment level (PCR1, PCR2, PCR3).

These safety mechanisms are disabled after reset. Software must configure and enable these mechanisms.

7.85 Periodic Hardware CRC Check of SRAM Contents

The platform includes a hardware CRC implementing the ISO CRC-64 standard polynomial. The CRC module can be used to test the integrity of static contents in the SRAM by calculating a CRC for all static contents and comparing this value to a previously generated "golden" CRC. The read of SRAM contents to the CRC can be done by CPU or by DMA. The comparison of results, indication of fault, and fault response are the responsibility of the software managing the test. The cyclical check applied by the CRC logic provides an inherent level of self checking (auto-coverage), which can be considered for application in latent fault diagnostics.

7.86 Periodic Software Read Back of Static Configuration Registers

Periodic read back of configuration registers can provide a diagnostic for inadvertent writes or disturb of these registers. Error response, diagnostic testability, and any necessary software requirements are defined by the software implemented by the system integrator.

7.87 Peripheral SRAM Parity

This module's SRAM includes a parity diagnostic that can detect single bit errors in the memory. When a parity error is detected, the ESM is notified. This feature is disabled after reset. Software must configure and enable this feature.

7.88 Peripheral Memory ECC

This module's memory includes an ECC diagnostic that can correct single bit and detect double bit errors in the memory. When an ECC error is detected the ESM is notified. This feature is disabled after reset. Software must configure and enable this feature.

7.89 PLL Slip Detector

The PLL logic includes an embedded diagnostic that can detect a slip of the PLL output clock. The slip is a result of a loss of phase lock between reference clock and feedback clock. Error response and indication is dependent on the programming of the PLL control registers that are located in the system control module. ESM error indication can be generated or masked. In addition, it is possible to generate an internal reset or to revert to operation from the oscillator clock in case of a detected error. For more information on programming this diagnostic, see the device-specific technical reference manual.

The PLL slip detection diagnostic is active whenever the PLL is enabled and has locked on a target frequency. The diagnostic cannot be disabled by the software, but the error indication and error response can be modified by the software.

7.90 Primary SRAM Address and Control Bus Parity

The on-chip transactions to SRAM are supported by a parity diagnostic on the address and control signals. The parity is generated by the bus master and evaluated by the SRAM. Detected errors are signaled to the ESM by the SRAM. This diagnostic is enabled at reset. The diagnostic can be disabled by asserting the address parity disable key in the RAMCTRL register of the SRAM wrapper.

This diagnostic is enabled at reset. The diagnostic can be disabled by assertion of the address parity disable key in the RAMCTRL register of the SRAM wrapper.

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7.91 Primary SRAM Data and ECC Storage in Multiple Physical Banks per Logical Address

Each logical SRAM word and its associated ECC code is split and stored in two physical SRAM banks. Each access comprises 72 total bits - 64 bits of data and 8 bits of ECC code. This is split in half, with each physical SRAM storing 32 bits of data and 4 bits of ECC code.

This scheme provides an inherent safety mechanism for address decode failures in the physical SRAM banks. Faults in the bank addressing are detected by the CPU as an ECC fault. This feature is enabled at reset and cannot be disabled by the software.

7.92 Primary SRAM Correctable ECC Profiling

An SRAM ECC profiling feature is provided by the EPC. The EPC provides a unified correctable ECC error (single bit ECC fault) profiling capability and error address cache on ECC failures in SRAM. This mechanism is disabled by default and must be enabled by the software. Cortex-R5F PMU export of events must also be enabled for this function to operate.

7.93 ECC on Cache RAM

ECC on Cache Memories - The ARM Cortex R5F processor supports ECC on L1 cache SRAMs for both instruction and data caches. For more information, see the Cortex-R5 and Cortex-R5F Technical Reference Manual located at http://infocenter.arm.com/help/topic/com.arm.doc.ddi0460d/index.html.

7.94 Primary SRAM Data ECC

The on-chip SRAM is supported by SECDED ECC diagnostics. It is connected by a 64-bit-wide data bus interface. In this SECDED scheme, an 8-bit code word is used to store the ECC data as calculated over the 64-bit data bus.

The ECC logic for the SRAM access is located in the bus masters as well as in the SRAM wrapper for sub-word accesses. All memory interconnect (CPU Interconnect Subsystem) transactions have ECC on the data payload. The ECC generation and evaluation logic is located in the bus masters in case of the CPU or in the CPU Interconnect Subsystem for other masters such as the DMA and the TUs. This scheme provides end-to-end diagnostics on the transmissions between bus master and SRAM on the CPU Interconnect Subsystem. Detected uncorrectable errors result in a ESM error. In the case of a single bit error the CPU exports the error detection events to the EPC module, in case of a double bit error the CPU exports the error event to the ESM module. The Cortex-R5F PMU must first be set to export events to an external monitor. The address of the memory, for any single bit ECC error, is logged in the EPC module. For more details on the ECC controller inside the CPU, see the *Cortex-R5 and Cortex-R5F Technical Reference Manuall* located at http://infocenter.arm.com/help/topic/com.arm.doc.ddi0460d/index.html.

The ECC logic for the SRAM is always enabled in both bus masters and the wrapper. In case of sub-64 bit word accesses the RAM wrapper will evaluate and check the ECC on the data payload. This is controlled via software in the SRAM wrapper. The cyclical check applied by the ECC logic provides an inherent level of self checking (autocoverage), which can be considered for application in latent fault diagnostics.

7.95 Primary SRAM Wrapper Redundant Address Decode

The SRAM wrapper includes a diagnostic to check for errors in the address decode logic. The diagnostic implements a checker copy of the address decode logic in lockstep to the functional address decode logic. The SRAM wrapper includes comparator logic to detect differences in the output from the two address decoders. Any detected mismatch will be signaled to the ESM and the address will be captured to a local register.

The redundant address decode logic diagnostic is active after reset. The diagnostic is supported by a hardware self-test that is triggered via software. The compare function is disabled during self-test operation.

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7.96 Primary SRAM Hard Error Cache and Livelock

If correction is enabled, corrected data values are stored in an internal one entry hard error cache, rewritten to the SRAM, and re-fetched from the SRAM.

A single instruction and its data may not have more than one correctable error. In case more than one correctable error is detected, it is possible to overrun the hard error cache and put the processor into an inoperable livelock state. Cases that can generate a livelock include:

- Two single bit errors in a 64-bit unaligned 32-bit Thumb-2 instruction fetch
- A single bit error in a load instruction (LDR or LDM) followed by a single bit error in the instruction's data payload

Livelock is indicated via the ESM and typically requires a reset for recovery to be attempted. Livelock on a SRAM interface transaction can be an indication of severe permanent fault in the SRAM. This feature is enabled at reset and cannot be disabled by the software.

7.97 Privileged Mode Access and Multi-Bit Enable Keys for Control Registers

This module includes features to support avoidance of unintentional control register programming. These features include limitation of write commands to privilege bus master transactions and the implementation of multi-bit keys for critical controls. The multi-bit keys are particularly effective for avoiding unintentional activation. For more details on the register safety mechanisms and error response, see the device-specific technical reference manual.

The operation of this safety mechanism is continuous and cannot be altered by the software. This mechanism can be tested by generating software transactions and reviewing the device response.

7.98 PBIST Check of Primary or Module SRAM

The Hercules family architecture supports the use of a hardware programmable memory BIST (PBIST) engine. This logic is used to provide a very high diagnostic coverage on the implemented SRAMs at a transistor level. This logic utilizes the same design for test (DFT) logic and algorithms used by TI to provide rapid execution of high quality manufacturing tests. This technique has proven to be drastically more effective than software-based tests of SRAM, particularly for the devices with complex CPUs whose addressing modes do not enable an optimal software-based test.

The PBIST tests must be triggered by the software. A developer can elect to run all algorithms, or only a subset of the algorithms based on the execution time that can be allocated to the PBIST diagnostic. Similarly, the user can elect to run the PBIST on one SRAM or on groups of SRAMs based on the execution time, which can be allocated to the PBIST diagnostic. The PBIST tests are destructive to memory contents, and as such are typically run only at MCU initialization. However, the user has the freedom to initiate the tests at any time when the CPU is operable.

Execution of the PBIST results in a much higher level of transistor switching per clock cycle than during normal software execution due to the high efficiency of the test. A software control is implemented in the PBIST that allows the user to reduce the SRAM clock for the duration of the test. This feature allows the user to make a compromise between fast execution with higher current consumption or slower execution with reduced current consumption.

The most effective SRAM tests known to TI require test across a full physical memory module and are destructive to previous memory contents. If PBIST is to be implemented during operation, it is possible to retain SRAM content by copying the data from the SRAM to be tested to a non-tested memory before test execution and to restore the data once the test is complete. When test execution is complete, the SRAM can be utilized for normal operation. The remainder of device logic continues normal operation during SRAM test. Any fault detected by the PBIST results in an error indicated in PBIST status registers. It is also possible to log faults in the PBIST logic.

PBIST logic includes capabilities for testing proper operation of the diagnostic. As the test time for the diagnostic is deterministic, a timeout counter can be implemented via software configuration of RTI module so that it can detect a failure to complete the test within an expected time. In addition, there is the possibility to test the contents of the ROM that contains the PBIST algorithms via running a checksum ROM test using the PBIST engine. Error forcing can be accomplished by executing a test not intended for a targeted memory, such as executing an SRAM read and write test on the PBIST ROM.

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7.99 PBIST Auto-coverage

The PBIST diagnostic is based on a 32-bit signature capture. For a given test, only one code is valid out of 2^32 possibilities. Therefore, if there is a fault in the PBIST logic, it is extremely unlikely that the correct passing code will be generated via the fault.

7.100 Power Domain Inactivity Monitor

When a power domain is turned off, its outputs are isolated from the rest of the system. The outputs are clamped to inactive safe values. Depending on the signals, the clamp value of a signal may be 0 or 1. Some bus masters may be residing in the turned off power domains. Key bus signals from the power domains which would have indicated that the bus master is generating a valid bus transaction are compared against their clamped values.

The Power Domain Inactivity Monitor Diagnostic can run in one of four user selectable operating modes: Active compare, Self-test , Error forcing, Self-test error forcing

7.101 PBIST Test of Parity Bit Memory

When a Programmable Memory Bist (PBIST) test is run on a selected memory, the corresponding parity bit memory will be tested as well. This provides latent coverage for the parity memory as part of the parity diagnostic.

7.102 PBIST Test of ECC Bit Memory

When a Programmable Memory BIST (PBIST) test is run on a selected memory, the corresponding ECC bit memory will be tested as well. This provides latent coverage for the ECC memory as part of the ECC diagnostic.

7.103 Lockstep PSCON

For each implemented power domain, a power state controller (PSCON) implements the control logic. In the Hercules platform, each PSCON is implemented with a diagnostic PSCON, running in lockstep, to check for current power state control settings on a cycle-by-cycle basis. Any error detected by lockstep compare is signaled to the ESM.

The PSCON lockstep compare is enabled by default during the power-on reset state. The PSCON lockstep compare can be disabled by the software in order to test the compare functionality. The test of the lockstep comparison feature is supported by a software triggered hardware self-test. The hardware self-test can initiate comparison tests for both match and mismatch inputs. Error forcing is also possible to test system level error response.

7.104 Redundant Address Decode Self-Test

The redundant address decode diagnostic includes hardware to support self-test. It is possible to force a pass and a fail to help diagnose proper operation of the redundant address decode diagnostic.

7.105 Redundant Temperature Sensors

This device contains three temperature sensors for sensing die temperature. 1 sensor is readable using MibADC1 and 2 are readable with MibADC2 to provide diverse and similar inputs for latent fault detection. As a diagnostic, software can use the 3 temperature sensors in a 2oo3 voting scheme to determine the validity of the temperature readings at any given time.

7.106 Scrubbing of SRAM to Correct Detected Single Bit Errors

The SRAM wrapper includes logic to enable local correction of detected single bit errors to support scrubbing operations to repair accumulated faults. The read transactions necessary for the scrubbing operations must be initiated by a bus master. When activated, this feature exercises the local ECC logic to correct single bit failures that may have accumulated in the SRAM.

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7.107 Shadow Registers

The use of a two stage cold and warm reset scheme on the device allows the implementation of shadow registers. Shadow registers are reset only by power-on reset. These registers can be used to store device status or other critical information that remain persistent after a warm reset changes the system state. This module includes shadow registers which can be used by software to provide additional information on the state of the device before the last warm reset operation.

7.108 Software Check of Cause of Last Reset

The system control module provides a status register (SYSESR) that latches the cause of the most recent reset event. A boot software that checks the status of this register to determine the cause of the last reset event is typically implemented by software developers. This information can be used by the software to manage failure recovery.

7.109 Software Read Back of CPU Registers

In order to ensure proper configuration of CPU coprocessor control registers, software can be used to implement a test to confirm proper operation of all control register writes. The CPU control registers are not memory mapped and must be accessed via the CPU coprocessor read and write commands.

7.110 Software Read Back of Written Configuration

In order to ensure proper configuration of memory-mapped registers, a software test can be implemented to confirm proper operation of all control register writes. To support this software test, the register memory space can be configured as a strongly ordered, non-bufferable memory region using the Cortex-R5F memory protection unit. Configuration in this manner ensures that the register write by the CPU will complete before additional CPU instructions are executed.

7.111 Software Test of DCC Functionality

A basic test of DCC functionality (including error generation) is possible via software by programming a sequence of good and bad expected clock ratios and executing DCC operations with software confirming expected results.

7.112 Software Test of DWD Functionality

A basic test of DWD operation can be performed via software including checking of error response by programming expected "pet" thresholds and servicing or not servicing the "pet" requests.

7.113 Software Test of DWWD Functionality

A basic test of DWWD operation can be performed via software including checking of error response by programming expected "pet" windows and servicing or not servicing the "pet" requests.

7.114 Software Test of ECC Profiler (EPC)

It is possible to test the functionality of the ECC profiler, (EPC) by performing reads on locations with ECC errors, and confirming proper operation of the error counters and threshold interrupt.

7.115 Software Test of Error Path Reporting

A software test can be utilized to insert diagnostic errors and check for proper reporting. Such a test can be executed at boot or periodically. Necessary software requirements are defined by the software implemented by the system integrator.

7.116 Software Test of Flash Sector Protection Logic

By attempting to write to a protected flash sector, the operation of flash sector protection logic can be tested

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7.117 Software Test of Function Including Error Tests

A software test can be utilized to test basic functionality as well as to insert diagnostic errors and check for proper error response. Such a test can be executed at boot or periodically. Software requirements necessary are defined by the software implemented by the system integrator.

7.118 Software Test of Function Using I/O Loopback

A software test can be utilized to test basic functionality as well as to insert diagnostic errors and check for proper error response. Such a test can be executed at boot or periodically. Software requirements necessary are defined by the software implemented by the system integrator.

Most modules support digital and analog loopback capabilities for the I/Os. Refer to the device technical reference manual to confirm the implemented loopback capabilities of the module. Digital loopback tests the signal path to the module boundary. Analog loopback tests the signal path from the module to the I/O cell with output driver enabled. For best results any tests of the functionality should include the I/O loopback.

7.119 Software Test of Function Using I/O Checking In GIO Mode

A software test can be utilized to test basic functionality of the I/O in GIO Mode to perform an analog loopback diagnostic on an I/O pin. Such a test can be executed at boot or periodically. Software requirements necessary are defined by the software implemented by the system integrator.

The GIO buffer architecture supports an analog loopback between the input and output buffers of a given I/O structure. The content of the data in and data out registers will directly reflect the state of the pin whether the I/O direction is configured as an input or an output. This configuration allows the software test to detect inconsistencies between known input states or known output states with the pin state.

7.120 Software Test of Function Using I/O Loopback in Transceiver/PHY

A software test can be utilized to test basic functionality as well as to insert diagnostic errors and check for proper error response. Such a test can be executed at boot or periodically. Software requirements necessary are defined by the software implemented by the system integrator.

Most Ethernet PHYs include a loopback mode that allows testing of the signal path including the PHY. Error response, diagnostic testability, and any necessary software requirements are defined by the system integrator. For best results, any tests of the networking functionality should include I/O loopback.

7.121 Software Test of Function Using I/O Loopback Including Error Tests - IOMM Only

Analog loopback testing from peripherals results in signals traversing the I/O pin mux logic to the I/O pad and can provide diagnostic coverage on the I/O pin mux configuration. Analog loopback tests the signal path from the module to the I/O cell with the output driver enabled.

I/O loopback is not enabled at reset. Software is necessary to configure and execute the diagnostic. IO configuration error response is managed by the software.

IOMM Error Trapping can also be realized during this testing by providing consideration of user access privileges and access to un-implemented register addresses. Permission and address violations are reported in the ESM.

7.122 Software Test of Hardware CRC

It is possible to test the functionality of hardware CRC by checking for correct calculation of expected CRC values as well as intentionally forcing a mismatch between the data and expected CRC signature. The Software Test of Hardware CRC will validate proper calculation of the CRC as well as correct error reporting of a mismatch of the calculated CRC by the CRC logic.

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7.123 Software Test of MPU Functionality

It is possible to test the functionality of the non-CPU bus master MPUs by checking for correct memory access to a programmed region as well as by marking a memory region as invalid and then attempting to write to it in order to generate an error. If the MPU features discrimination by read/write then the testing should also consider checking for correct operation and errors related to read/write permissions.

7.124 Software Test of Parity Logic

It is possible to test the functionality of parity error detection logic by forcing a parity error into the data or parity memory bits, and observing whether the parity error detection logic reports an error. Parity can also be calculated manually and compared to the hardware calculated value stored in the parity memory bits.

7.125 Software Test of PBIST

It is possible to configure the PBIST logic by selecting an algorithm that should fail, and seeing if the PBIST Logic reports an error under this condition. For example, a read-write test could be performed on a read-only memory to ensure that a failure is reported. An alternative scheme is to run a test for memory with more bits than are actually present on the device memory.

7.126 Software Test of SRAM Wrapper Address Decode Diagnostic and ECC

A software based test of the redundant address decode diagnostic and ECC error reporting logic in the SRAM wrapper can be performed at boot time as a latent diagnostic.

7.127 Software Test for Reset

A software test for detecting basic functionality as well as errors for reset sources and reset logic can be implemented.

7.128 Software Warm Reset Generation

The system control module provides the ability to the software to generate an internal warm reset (nRST). This is accomplished by writing appropriate control bits in the SYSECR control register. Software can utilize this feature to attempt failure recovery.

7.129 Transmission Redundancy

Using transmission redundancy, information is transferred several times in sequence and compared. If the same data path is used for the duplicate transmissions, then transmission redundancy will only by useful for detecting transient faults. Error response, diagnostic testability, and any necessary software requirements are defined by the system integrator.

7.130 Use of CoreSight Debug Logic Key Enable Scheme

To enable operation of the memory-mapped CoreSight debug components, it is necessary to write a defined 32-bit key to an unlock register in each debug module. This debug lock protection provides an additional safety mechanism to limit undesired activation.

7.131 Use of DCC as Program Sequence Watchdog

The design of the N2HET is such that the instruction memory is contiguously executed in a circular loop with deterministic duration. A clocked output of known frequency can be generated on the N2HET with minimum software overhead. Each N2HET has a dedicated channel internally connected to one of the two DCC modules. Comparison of the N2HET clocking output to a known clock reference by DCC can effectively implement a program sequence watchdog on the N2HET. Error response, diagnostic testability, and any necessary software requirements are defined by the software implemented by the system integrator.

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7.132 Use of MPUs to Block Access to Memory Mapped Debug

The CoreSight and other debug related peripherals are accessible over a memory-mapped debug bus. Access to this region can be blocked via the use of bus master based memory protection. For more information on memory protection, see CPU Memory Protection Unit (MPU).

7.133 Execution of Interconnect Self-Test

The CPU Interconnect Subsystem can be put into self-test. During self-test, the self-test logic applies test stimulus to each master and slave interface of the CPU interconnect Subsystem . If an error is detected, the type of error for the corresponding interface is logged in the CPU Interconnect Subsystem memory mapped register and an error is asserted to ESM. The interconnect is not available for functional use when the self-test is applied. This test can be ran at boot time or periodically within the application.

7.134 CPU Interconnect Hardware Checker

For each master and slave interface in the CPU interconnect Subsystem, there is a runtime hardware safety diagnostic checker. The hardware checker continuously monitors the transactions flowing through the interconnect and ensures that they are not corrupted . If a mismatch is detected between an ongoing transaction and the expected transaction flow then an error is asserted to the ESM. This diagnostic can detect issues with arbitration, routing, and timeout of transactions. The type of error is recorded in the interconnect memory mapped registers

7.135 Timeout Monitoring on The Bus Transaction

The CPU Interconnect Subsystem contains timeout counters to count the amount of time it is taking for a master request to be accepted by the slave and also to count the amount of time it takes from an accepted request to the slave response. There are two separate counters per master interface. When either the request-to-accept counter or the accept-to-response counter expires by the slave, a timeout error is asserted to the ESM.

7.136 Transaction ECC (Data Lines)

The CPU core contains the built-in ECC generation and evaluation logic for its AXI interface. Therefore, the CPU will generate the ECC checksum for the data lines along with its write data. The write data and the corresponding ECC checksum are transported by the interconnect to the selected slave such as L2 (primary) SRAM. When the CPU core performs a read from a slave, the slave returns the data and the corresponding Data ECC checksum. Upon receiving the data and the ECC checksum, the CPU will evaluate the integrity of the data by performing the Data ECC check. Data ECC errors detected on the CPU's AXI interface are exported by the CPU to its event bus output. The error signals, if enabled, and the corresponding error addresses are first routed to the Error Profiling Controller (EPC) module. EPC is used to record different single bit error addresses in a Content Addressable Memory (CAM). The main purpose of the EPC module is to enable the system to tolerate a certain amount of ECC correctable errors on the same address repeated in the memory system with minimal runtime overhead. If an ECC error is generated on a repeating address, the EPC will not raise an error to the ESM module. This tolerance allows the application to avoid the handling of the same error when the code is in a repeating loop.

DMA PortA and Peripheral Interconnect Subsystem masters do not have built-in ECC generation and evaluation logic. Therefore, the CPU Interconnect Subsystem contain a standalone ECC generation and evaluation logic for each DMA PortA and Peripheral Interconnect Subsystem master. Write transactions initiated by the DMA PortA and Peripheral Interconnect Subsystem masters are first treated by the ECC block to generate the ECC checksum before transporting to the final destination. For read transactions, the data and ECC checksum returned by the slaves will pass through the ECC block for data integrity evaluation. ECC errors detected are also routed to the Error Profiling Controller (EPC) module. In order for the standalone ECC block to assert the error signals to the EPC, the error enable key must be first set in the IP1ECCERREN register of the SYS2 module.

ECC errors detected are also routed to the Error Profiling Controller (EPC) module. In order for the standalone ECC block to assert the error signals to the EPC, the error enable key must be first set in the IP1ECCERREN register of the SYS2 module.

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7.137 Transaction Parity (Address and Control Lines)

The CPU core contains the built-in parity generation and evaluation logic for its AXI interface. Therefore, the CPU will generate the Parity for the Address and Control Lines along with its write data. The write data and the corresponding Address and Control Line Parity are transported by the interconnect to the selected slave such as L2 (primary) SRAM. When the CPU core performs a read from a slave, the slave returns the data and the corresponding Address and Control Line Parity. Upon receiving the data and the Address and Control Line Parity information, the CPU will evaluate the integrity of the data by performing the Address and Control Line Parity check. Parity errors detected on the CPU's AXI interface are exported by the CPU to its event bus output.

7.138 Peripheral Interconnect New Memory Protection Unit (NMPU)

An NMPU module is implemented to provide memory protection for transactions that are initiated by masters on the Peripheral Interconnect Subsystem which target slaves on the CPU Interconnect Subsystem. This module is disabled by default and must be enabled by software.

7.139 Software Test of The New Memory Protection Unit (NMPU) Functionality

It is possible to initiate a software test of the NMPU functionality. Similar to, but a subset of the CPU MPU, the NMPU offers up 8 protection regions ranging in size from 32-bytes to 4GB in size. The actual number of protection regions vary by IP with DMA having 8, Peripheral Interconnect Subsystem having 8, and EMIF having 2. Each region can have programmable access permissions such as full access, read access, or write access. In addition, different access permissions can be assigned by user and privilege modes of operation. Software tests can be made to exercise these access regions using the various masters and defined access permissions. In practice, it is most effective to initiate both positive and negative testing where a master is tested to insure proper access to allowed regions with the appropriate type of access and also tested for areas of illegal access and illegal access types. This type of boundary level testing provides the most comprehensive test of the functionality.

7.140 Software Test of ECC Logic

It is possible to test the functionality of ECC error detection logic by forcing an ECC error into the data or ECC memory bits, and observing whether the ECC error detection logic reports an error. ECC can also be calculated and compared to the hardware calculated value stored in the ECC memory bits.

7.141 Multi-Bit Keyed Self-Correctable High-Integrity Bits

There are a limited number of registers in the device that have been identified as having a critical role in device operation integrity with respect to a safety system. These register bits are designated as high-integrity bits and have been implemented with error correcting logic such that each bit, although read and written as a single bit, is actually a multi-bit key with ECC capability. As such, single bit flips within the “key” can be corrected allowing protection of the system as a whole. Double bit flips within these structures are flagged as an error and signaled through the ESM. For more information on specific registers and bits that utilize this bit structure, please reference the device TRM.

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8 Next Steps in Your Safety Development

TI's support for your safety development does not stop with the delivery of this safety document. Customers have a wide range of support options, such as:

- Access safety collateral for Hercules and other SafeTI™ products at: http://www.ti.com/safeti
- Access Hercules documentation including safety docs and app notes any time on the web: http://www.ti.com/hercules
- Discuss questions and concerns with TI experts and other Hercules developers using the TI Connected Community (E2E forums): http://www.ti.com/hercules-support
- Discuss questions and concerns regarding TI's safety documents that are provided under NDA with TI safety experts at: https://e2eprivate.ti.com/safeti_functional_safety_support/default.aspx. By requesting a copy of this document, access will be granted to the support forum as well here: http://www.ti.com/safetyanalysis
- The Hercules Wiki page provides answers to many commonly asked questions: http://www.ti.com/hercules-wiki
- Attend a training class delivered by TI's Hercules experts: http://www.ti.com/herculestraining

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Summary of Safety Feature Usage

Table 4 provides a summary of the safety features and diagnostics present in hardware or available for implementation in software or at system level.

Table 3. Key to Summary of Safety Features and Diagnostics

Device Partition	This field provides the element (device partition) which has safety features and diagnostics
Unique Identifier	This field provides a short unique identifier to aid in traceability of each safety features and diagnostics
Safety Feature or Diagnostic	This field provides the name of the safety feature or diagnostic.
Possible Tests for Diagnostics	This column lists mechanisms that can be applied to verify that the diagnostic itself is functioning correctly.
Usage	Each test listed in this chart can be one of two types. A "diagnostic" test, or a "test-for-diagnostic only" test Diagnostic: Provides coverage for faults on a primary function of the device. It may, in addition, provide fault coverage on other diagnostics, and can therefore be also used as a test-for-diagnostic in certain cases Test-for-Diagnostic Only: Does NOT provide coverage for faults on a primary function of the device. It's only purpose is to provide fault coverage on other diagnostics
Diagnostic Type	Hardware: A diagnostic or test-for-diagnostic which is implemented by TI in silicon. It may require software activation Software: A diagnostic or test-for-diagnostic which is performed in software and which must be created by the software implementor Software-Hardware: A diagnostic or test-for-diagnostic which requires both hardware in the device and software created by the software implementor System: A diagnostic or test-for-diagnostic which must be implemented at the system level by the system implementor
Diagnostic Operation	Continuous or Periodic/On-Demand
Text Execution Time	This column lists the time that is required for this diagnostic to complete
Action on Detected Fault	The response that this diagnostic takes when an error is detected. For software-driven tests, this action if often software implementation-dependent
Error Reporting Time	Typical time required for diagnostic to indicate a detected fault to the system. For software-driven tests, this time is often software implementation-dependent

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Table 4. Summary of Safety Features and Diagnostics

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Power Supply	PWR1	Internal Voltage Monitor (VMON)	PWR2: External Voltage Supervisor CLK5C: External Watchdog	Diagnostic	Hardware	Continuous	1 µs (Glitch filter logic filters transient glitches of <1 µs)	Assert component power-on reset until fault condition not detection system control module Reset Request Register will log the cause of reset	Reset action <1 µS after detection Software indication of reset cause available on first CPU active clock
	PWR2	External Voltage Supervisor	PWR1: Internal Voltage Monitor (VMON) CLK5C: External Watchdog	Diagnostic	System	System Defined (Typically Continuous)	System Defined	System Defined (Typically the powered device is disabled via reset or power cut)	System Defined
Power Mgt Module (PMM)	PMM1	Lockstep PSCON	PMM5: PSCON Lockstep Comparator Self Testt	Diagnostic	Hardware	Continuous	No Hardware Overhead	Trigger to ESM group1 and set local error flag	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	PMM2	Privileged-Mode Access and Multi-Bit Keys for Control Registers	N/A	Diagnostic	Hardware	Continuous	No Hardware Overhead	Control registers will not be updated	N/A (Fault Avoidance)
	PMM3	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	PMM4	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	PMM5	PSCON Lockstep Comparator Self Testt	NA - This is a test of the PSCON diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	24 Clock cycles	Trigger to ESM group1 and set local error flag	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	PMM6	Power Domain Inactivity Monitor	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare	Diagnostic	Hardware	Continuous	No Hardware Overhead	Trigger to ESM group 12 and set local error flag in the CCM-R5 module	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Clock	CLK1	LPOCLKDET	CLK5C: External Watchdog CLK4: External Monitoring via ECLK	Diagnostic	Hardware	Continuous	No Hardware Overhead	Error event provided to ESM Optional MCU soft (warm) reset generation Optional clock source switch to LPO	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	CLK2	PLL Slip Detector	CLK5C: External Watchdog CLK4: External Monitoring via ECLK	Diagnostic	Hardware	Continuous	No Hardware Overhead	Error Event Provided to ESM Optional MCU Soft (warm) Reset Generation Optional Clock Source Switch to LPO	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	CLK3	Dual Clock Comparator (DCC)	CLK6: Periodic Software Readback of Static Configuration Registers CLK5C: External Watchdog CLK4: External Monitoring via ECLK	Diagnostic	Software-Hardware	Continuous	Software Dependent	Error Event Provided to ESM	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	CLK4	External Monitoring via ECLK	System Dependent	Diagnostic	System	Continuous	No Hardware Overhead	System Defined	System Defined
	CLK5A	Internal Watchdog - DWD	CLK9: Software Test of DWD Operation CLK5C: External Watchdog CLK4: External Monitoring via ECLK	Diagnostic	Software-Hardware	Continuous	No Hardware Overhead - Software Dependent	Internal MCU Soft (warm) Reset	Reset reason available in SYS module on first clock after reset
	CLK5B	Internal Watchdog - DWWD	CLK9: Software Test of DWD Operation CLK5C: External Watchdog CLK4: External Monitoring via ECLK	Diagnostic	Software-Hardware	Continuous	No Hardware Overhead - Software Dependent	Internal MCU Soft (warm) Reset or Non-Maskable Interrupt	Reset reason available in SYS module on first clock after reset Typically <1 µS to notify CPU of NMI* *(Interrupt handling time is system load and software dependent)
	CLK5C	External Watchdog	System Dependent	Diagnostic	Software-Hardware	Continuous	System Dependent	System Defined	System Defined
	CLK6	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	CLK7	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	CLK8	Software Test of DCC Operation	NA - This is a test of the DCC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	CLK9	Software Test of DWD Operation	NA - This is a test of the DWD diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	CLK10	Software Test of DWWD Operation	NA - This is a test of the DWWD diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Reset	RST1	External Monitoring of Warm Reset (nRST)	System Dependent	Diagnostic	System	System Defined (Typically Continuous)	System Defined	System Defined (Typically the powered device is disabled via reset or power cut)	System Defined
	RST2	Software Check of Cause of Last Reset	N/A	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent	N/A (Fault Avoidance)	N/A (Fault Avoidance)
	RST3	Software Warm Reset Generation	N/A	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent	N/A (Fault Avoidance)	N/A (Fault Avoidance)
	RST4	Glitch Filtering on Reset Pins	N/A	Diagnostic	Hardware	Continuous	1 µs (Glitch filter logic filters transient glitches of <1 µs	N/A (Fault Avoidance)	N/A (Fault Avoidance)
	RST5	Use of Status Shadow Registers	N/A	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent	N/A (Fault Avoidance)	N/A (Fault Avoidance)
	RST6	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	RST7	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	RST8	Software Test for Reset	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software-Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
System Control Module	SYS1	Privileged Mode Access and Multi-Bit Enable Keys for Control Registers	N/A	Diagnostic	Hardware	Continuous	No Hardware Overhead	Control Register not Updated	N/A (Fault Avoidance)
	SYS2	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	SYS3	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	SYS4	Multi-Bit Keyed Self-Correctable High-Integrity Bits	N/A	Diagnostic	Hardware	Continuous	No Hardware Overhead	Control Register not Updated (Fault Avoidance)	Typically less than 5 cycles to ESM

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Error Signaling Module (ESM)	ESM1	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	ESM2A	Boot Time Software Test of Error Path Reporting	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software-Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	ESM2B	Periodic Software Test of Error Path Reporting	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software-Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	ESM3	Use of Status Shadow Registers	N/A	Diagnostic	Hardware	Continuous	N/A - Fault Avoidance	N/A - Fault Avoidance	N/A - Fault Avoidance
	ESM4	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
Cortex-R5F Central Processing Unit (CPU)	CPU1	CPU Lockstep Compare	CPU8: Lockstep Comparator (CCM) Self Test	Diagnostic	Hardware	Continuous	2 CPU Cycles	ESM Error	Typically <1 µs (implementation dependent)
	CPU2A	Boot Time Execution of LBIST STC	CPU1: CPU Lockstep Compare CLK5C: External Watchdog CPU9: LBIST Auto-Coverage	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Error Flag Asserted	Typically <1 µs (implementation dependent)
	CPU2B	Periodic Execution of LBIST STC	CPU1: CPU Lockstep Compare CLK5C: External Watchdog CPU9: LBIST Auto-Coverage	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Error Flag Asserted	Typically <1 µs (implementation dependent)
	CPU3	Memory Protection Unit (MPU)	CPU1: CPU Lockstep Compare CPU2A: Boot Time Execution of LBIST STC CPU2B: Periodic Execution of LBIST STC	Diagnostic	Hardware	Continuous	No Hardware Overhead	Instruction Abort/Data Abort	1 CPU Cycle After Detection
	CPU4	Online Profiling Using PMU	CPU1: CPU Lockstep Compare CPU2A: Boot Time Execution of LBIST STC CPU2B: Periodic Execution of LBIST STC	Diagnostic	Software-Hardware	Continuous	Software Dependent	Software Defined	Software-Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Cortex-R5F Central Processing Unit (CPU)	CPU5	CPU Illegal Operation and Instruction Trapping	CPU1: CPU Lockstep Compare CPU2A: Boot Time Execution of LBIST STC CPU2B: Periodic Execution of LBIST STC	Diagnostic	Hardware	Continuous	No Hardware Overhead	Instruction Abort/Data Abort	1 CPU Cycle After Detection
	CPU6	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	CPU7	Software Read Back of CPU Registers	CPU1: CPU Lockstep Compare CPU2A: Boot Time Execution of LBIST STC CPU2B: Periodic Execution of LBIST STC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	CPU8	Lockstep Comparator (CCM) Self Test	NA - This is a test of the CCM diagnostic,. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Error Flag Asserted	Typically <1 µs (implementation dependent)
	CPU9	LBIST Auto-Coverage	NA - This is a test of the LBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in LBIST operation	N/A	N/A
	CPU10	Boot Time PBIST Check of CPU cache Memories	RAM1: SRAM Data ECC CPU15: Software Readback of Written Configuration (PBIST) CPU13: Software Test of PBIST CPU14: PBIST Auto-Coverage CPU1: CPU Lockstep Compare CLK5C: External Watchdog FLA1: Flash Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	CPU11	Periodic PBIST Check of CPU cache Memories	RAM1: SRAM Data ECC CPU15: Software Readback of Written Configuration (PBIST) CPU13: Software Test of PBIST CPU14: PBIST Auto-Coverage CPU1: CPU Lockstep Compare CLK5C: External Watchdog FLA1: Flash Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	CPU12	ECC on Cache Memories	CPU1: CPU Lockstep Compare	Diagnostic	Hardware	Continuous	2 CPU Cycles	ESM Error	Typically <1 µs (implementation dependent)
	CPU13	Software Test of PBIST	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	CPU14	PBIST Auto-Coverage	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in PBIST operation	N/A	N/A
	CPU15	Software Readback of Written Configuration (PBIST)	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Primary Flash	FLA1	Flash Data ECC	CPU1: CPU Lockstep Compare FLA10: Flash Wrapper Diag Mode 5 Test FLA11: Flash Wrapper Diag Mode 7 Test	Diagnostic	Hardware	Continuous	No Hardware Overhead	CPU Abort / ESM Event	Same CPU clock cycles as data used
	FLA2	Hard Error Cache and Livelock	CPU1: CPU Lockstep Compare	Diagnostic	Hardware	Continuous	No Hardware Overhead	Live lock / ESM Event	Typically <1 µs
	FLA3	Flash Wrapper Address ECC	FLA10: Flash Wrapper Diag Mode 5 Test FLA11: Flash Wrapper Diag Mode 7 Test	Diagnostic	Hardware	Continuous	No Hardware Overhead	CPU Abort / ESM Event	Same CPU clock cycles as data used
	FLA4	Address and Control Parity	FLA9: Software Readback of Written Configuration FLA12: Software Test of Parity Logic	Diagnostic	Hardware	Continuous	No Hardware Overhead	CPU Bus Error	Same CPU clock cycles as data used
	FLA5A	Boot Time Check of Flash Memory Contents by Hardware CRC	CLK5C: External Watchdog FLA9: Software Readback of Written Configuration FLA14: Software Test of Hardware CRC FLA15: CRC Auto-Coverage	Diagnostic	Software - Hardware	On Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Defined	Software Dependent
	FLA5B	Periodic Check of Flash Memory Contents by Hardware CRC	CLK5C: External Watchdog FLA9: Software Readback of Written Configuration FLA14: Software Test of Hardware CRC FLA15: CRC Auto-Coverage	Diagnostic	Software - Hardware	On Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Defined	Software Dependent
	FLA6	Bit Multiplexing in Flash Memory Array	N/A - Fault Avoidance	Diagnostic	Hardware	Continuous	N/A - Fault Avoidance	N/A - Fault Avoidance	N/A - Fault Avoidance
	FLA7	Flash Sector Protection	FLA13: Software Test of Flash Sector Protection Logic	Diagnostic	Hardware	Continuous	No Hardware Overhead	Flash Programing Blocked	Software dependent based on readback of content
	FLA8	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	FLA9	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	FLA10	Flash Wrapper Diag Mode 5 Test	NA - this is a test of a diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software - Hardware	On Demand	Software Dependent Typically <1 µs overhead due to hardware	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Primary Flash	FLA11	Flash Wrapper Diag Mode 7 Test	NA - this is a test of a diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software - Hardware	On Demand	Software Dependent Typically <1 µs overhead due to hardware	Software Dependent	Software Dependent
	FLA12	Software Test of Parity Logic	NA - This is a test of the parity diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	On Demand	Software Dependent	Software Dependent	Software Dependent
	FLA13	Software Test of Flash Sector Protection Logic	NA - This is a test of the flash sector protection logic diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	On Demand	Software Dependent	Software Dependent	Software Dependent
	FLA14	Software Test of Hardware CRC	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent	Software Dependent	Software Dependent
	FLA15	CRC Auto-Coverage	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in CRC operation	N/A	N/A

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Flash EEPROM Emulation (FEE)	FEE1	FEE Data ECC	CPU1: CPU Lockstep Compare FEE15: Flash Wrapper Diag Mode 5 Test FEE16: Flash Wrapper Diag Mode 7 Test	Diagnostic	Hardware	Continuous	No Overhead (Same clock cycle)	ESM Event	Same CPU clock cycles as data used
	FEE2A	Boot Time Check of FEE Memory Contents by Hardware CRC	FEE6: Software Readback of Written Configuration FEE13: Software Test of Hardware CRC FEE14: CRC Auto-Coverage CLK5C: External Watchdog	Diagnostic	Software - Hardware	On Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Defined	Software Dependent
	FEE2B	Periodic Check of FEE Memory Contents by Hardware CRC	FEE6: Software Readback of Written Configuration FEE13: Software Test of Hardware CRC FEE14: CRC Auto-Coverage CLK5C: External Watchdog	Diagnostic	Software - Hardware	On Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Defined	Software Dependent
	FEE3	Bit Multiplexing in FEE Array	N/A - Fault Avoidance	Diagnostic	Hardware	Continuous	N/A - Fault Avoidance	N/A - Fault Avoidance	N/A - Fault Avoidance
	FEE4	FEE Sector Protection	FEE2B: Periodic Check of FEE Memory Contents by Hardware CRC FEE12: Software Test of Flash Sector Protection Logic	Diagnostic	Hardware	Continuous	No Overhead (Same clock cycle)	Flash Programing Blocked	Software dependent based on readback of content
	FEE5	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	FEE6	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	FEE7	Flash Wrapper Address ECC	FEE2B: Periodic Check of FEE Memory Contents by Hardware CRC FEE15: Flash Wrapper Diag Mode 5 Test FEE16: Flash Wrapper Diag Mode 7 Test	Diagnostic	Hardware	Continuous	No Hardware Overhead	ESM Event	Same CPU clock cycles as data used

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Flash EEPROM Emulation (FEE)	FEE12	Software Test of Flash Sector Protection Logic	NA -This is a test of the flash sector protection logic diagnostic. It is not a diagnostic itself	Test for Diagnostic	Software	On Demand	Software-Dependent	Software Dependent	Software Dependent
	FEE13	Software Test of Hardware CRC	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	FEE14	CRC Auto-Coverage	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in CRC operation	N/A	N/A
	FEE15	Flash Wrapper Diag Mode 5 Test	NA - this is a test of a diagnostic. It is not a diagnostic itself	Test for Diagnostic	Software - Hardware	On Demand	Software Dependent Typically <1 µs overhead due to hardware	Software Dependent	Software Dependent
	FEE16	Flash Wrapper Diag Mode 7 Test	NA - this is a test of a diagnostic. It is not a diagnostic itself	Test for Diagnostic	Software - Hardware	On Demand	Software Dependent Typically <1 µs overhead due to hardware	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Primary SRAM	RAM1	RAM Data ECC	CPU1: CPU Lockstep Compare	Diagnostic	Hardware	Continuous	No Hardware Overhead	CPU Abort / ESM Event	Same CPU clock cycles as data used
	RAM2	Hard Error Cache and Livelock	CPU1: CPU Lockstep Compare	Diagnostic	Hardware	Continuous	No Hardware Overhead	Live lock / ESM Event	Typically <1us
	RAM3	Correctable ECC Profiling	RAM16: Software Test of ECC Profiler	Diagnostic	Software / Hardware	Continuous	Software Dependent	Software Dependent	Software Dependent
	RAM4	Address and Control Bus Parity	RAM11: Software Readback of Written Configuration RAM13: Software Test of Parity Logic	Diagnostic	Hardware	Continuous	No Hardware Overhead	CPU Bus Error	Same CPU clock cycles as data used
	RAM5	Redundant Address Decode	RAM17: Redundant Address Decode Self Test	Diagnostic	Hardware	Continuous	No Hardware Overhead	CPU Bus Error	Same CPU clock cycles as data used
	RAM6	Data and ECC Storage in Multiple Physical Banks	N/A - Fault Avoidance	Diagnostic	Hardware	Continuous	N/A (Fault Avoidance)	N/A (Fault Avoidance)	N/A (Fault Avoidance)
	RAM7A	Boot Time PBIST Check of Primary SRAM	RAM14: Software Test of PBIST RAM15: PBIST Auto-Coverage RAM11: Software Readback of Written Configuration CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	RAM7B	Periodic PBIST Check of Primary SRAM	RAM14: Software Test of PBIST RAM15: PBIST Auto-Coverage RAM11: Software Readback of Written Configuration CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	RAM8	Bit Multiplexing in Primary SRAM Array	N/A - Fault Avoidance	Diagnostic	Hardware	Continuous	N/A (Fault Avoidance)	N/A (Fault Avoidance)	N/A (Fault Avoidance)
	RAM9	Periodic Hardware CRC Check of Primary SRAM Contents	RAM11: Software Readback of Written Configuration RAM18: Software Test of Hardware CRC RAM19: CRC Auto-Coverage CLK5C External Watchdog	Diagnostic	Software / Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	RAM10	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	RAM11	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Primary SRAM	RAM12	Software Test of SRAM Wrapper Redundant Address Decode and ECC	N/A - This is a test of Redundant Address Decode and ECC. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	RAM13	Software Test of Parity Logic	N/A - This is a test of the parity logic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	RAM14	Software Test of PBIST	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	RAM15	PBIST Auto-Coverage	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in PBIST operation	N/A	N/A
	RAM16	Software Test of ECC Profiler	NA - This is a test of the ECC profiler diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	RAM17	Redundant Address Decode Self Test	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	No Overhead (Same clock cycle)	Software Dependent	Software Dependent
	RAM18	Software Test of Hardware CRC	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software / Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	RAM19	CRC Auto-Coverage	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in CRC operation	N/A	N/A
	RAM20	Scrubbing of SRAM to Correct Detected Single Bit Errors	N/A - Fault Avoidance	Diagnostic-Fault Avoidance	Hardware	Continuous	N/A - Fault Avoidance	N/A - Fault Avoidance	N/A - Fault Avoidance

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
CPU Interconnect Subsystem	MEM1	Error Trapping (Including Peripheral Slave Error Trapping)	MEM5A: Boot Time Software Test of Basic Functionality Including Error Tests MEM5B: Periodic Software Test of Basic Functionality Including Error Tests	Diagnostic	Hardware	Continuous	No Hardware Overhead	Bus Error	Bus master notification typically <10 clock cycles after fault detection
	MEM3	Information Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	MEM4	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	MEM5A	Boot Time Software Test of Basic Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software-Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	MEM5B	Periodic Software Test of Basic Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software-Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	MEM6	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	MEM7	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	System Dependent	System Dependent	System Dependent
	MEM8A	Boot Time Execution of Interconnect Self-Test	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic/Test for Diagnostic	Hardware	Continuous	No Hardware Overhead	ESM Error	Notification typically <5 clock cycles after fault detection
	MEM8B	Periodic Execution of Interconnect Self-Test	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic/Test for Diagnostic	Hardware	Continuous	No Hardware Overhead	ESM Error	Notification typically <5 clock cycles after fault detection

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
CPU Interconnect Subsystem	MEM9	CPU Interconnect Hardware Checker	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Continuous	No Hardware Overhead	ESM Error	Notification typically <5 clock cycles after fault detection
	MEM10	Timeout Monitoring on Bus Transactions	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Continuous	No Hardware Overhead	ESM Error	Notification typically <5 clock cycles after fault detection
	MEM11	Transaction ECC (Date Lines)	CPU1: CPU Lockstep Compare	Diagnostic	Hardware	Continuous	No Hardware Overhead	ESM Error	Notification typically <5 clock cycles after fault detection
	MEM12	Transaction Parity (Address and Control Lines)	CPU1: CPU Lockstep Compare	Diagnostic	Hardware	Continuous	No Hardware Overhead	ESM Error	Notification typically <5 clock cycles after fault detection

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Peripheral Interconnec Subsystem	PER1	Error Trapping (Including Peripheral Slave Error Trapping)	PER5A: Boot Time Software Test of Basic Functionality Including Error Tests PER5B: Periodic Software Test of Basic Functionality Including Error Tests	Diagnostic	Hardware	Continuous	No Hardware Overhead	Bus Error	Bus master notification typically <10 clock cycles after fault detection
	PER2	Peripheral Interconnect New Memory Protection Unit (NMPU)	PER5A: Boot Time Software Test of Basic Functionality Including Error Tests PER5B: Periodic Software Test of Basic Functionality Including Error Tests	Diagnostic	Hardware	Continuous	No Hardware Overhead	Bus Error	Bus master notification typically <10 clock cycles after fault detection
	PER3	Information Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	PER4	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	PER5A	Boot Time Software Test of Basic Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible.	Software Dependent	Software Dependent
	PER5B	Periodic Software Test of Basic Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible.	Software Dependent	Software Dependent
	PER6	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	PER7	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	System Dependent	System Dependent	System Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Peripheral Central Resource 1 (PCR1)	P1T1	Error Trapping (Including Peripheral Slave Error Trapping)	P1T5A: Boot Time Software Test of Basic Functionality Including Error Tests P1T5B: Periodic Software Test of Basic Functionality Including Error Tests	Diagnostic	Hardware	Continuous	No Hardware Overhead	Bus Error	Bus master notification typically <10 clock cycles after fault detection
	P1T2	PCR Access Management: Protection Mode and MasterID Filtering	P1T5A: Boot Time Software Test of Basic Functionality Including Error Tests P1T5B: Periodic Software Test of Basic Functionality Including Error Tests	Diagnostic	Hardware	Continuous	No Hardware Overhead	Bus Error	Bus master notification typically <10 clock cycles after fault detection
	P1T3	Information Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	P1T4	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	P1T5A	Boot Time Software Test of Basic Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible.	Software Dependent	Software Dependent
	P1T5B	Periodic Software Test of Basic Functionality Including Error Tests	Internal Watchdog - DWD Internal Watchdog - DWWD External Watchdog CPU Lockstep Compare Flash Data ECC Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible.	Software Dependent	Software Dependent
	P1T6	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	P1T7	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	System Dependent	System Dependent	System Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Peripheral Central Resource 2 (PCR2)	P2T1	Error Trapping (Including Peripheral Slave Error Trapping)	P2T5A: Boot Time Software Test of Basic Functionality Including Error Tests P2T5B: Periodic Software Test of Basic Functionality Including Error Tests	Diagnostic	Hardware	Continuous	No Hardware Overhead	Bus Error	Bus master notification typically <10 clock cycles after fault detection
	P2T2	PCR Access Management: Protection Mode and MasterID Filtering	P2T5A: Boot Time Software Test of Basic Functionality Including Error Tests P2T5B: Periodic Software Test of Basic Functionality Including Error Tests	Diagnostic	Hardware	Continuous	No Hardware Overhead	Bus Error	Bus master notification typically <10 clock cycles after fault detection
	P2T3	Information Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	P2T4	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	P2T5A	Boot Time Software Test of Basic Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible.	Software Dependent	Software Dependent
	P2T5B	Periodic Software Test of Basic Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible.	Software Dependent	Software Dependent
	P2T6	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	P2T7	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	System Dependent	System Dependent	System Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Peripheral Central Resource 3 (PCR3)	P3T1	Error Trapping (Including Peripheral Slave Error Trapping)	P3T5A: Boot Time Software Test of Basic Functionality Including Error Tests P3T5B: Periodic Software Test of Basic Functionality Including Error Tests	Diagnostic	Hardware	Continuous	No Hardware Overhead	Bus Error	Bus master notification typically <10 clock cycles after fault detection
	P3T2	PCR Access Management: Protection Mode and MasterID Filtering	P3T5A: Boot Time Software Test of Basic Functionality Including Error Tests P3T5B: Periodic Software Test of Basic Functionality Including Error Tests	Diagnostic	Hardware	Continuous	No Hardware Overhead	Bus Error	Bus master notification typically <10 clock cycles after fault detection
	P3T3	Information Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	P3T4	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	P3T5A	Boot Time Software Test of Basic Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible.	Software Dependent	Software Dependent
	P3T5B	Periodic Software Test of Basic Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible.	Software Dependent	Software Dependent
	P3T6	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	P3T7	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	System Dependent	System Dependent	System Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
EFuse Static Configuration	EFU1	Boot Time Autoload Self Test	EFU5: Autoload Self Test Auto-Coverage	Diagnostic	Hardware	Continuous (Every power-on reset operation)	Device Dependent (see the device-specific data sheet)	ESM Event	No Overhead (Available on 1st CPU clock cycle after release of reset)
	EFU2	E-Fuse ECC	EFU6: EFuse ECC Logic Self Test	Diagnostic	Hardware	Continuous	No Hardware Overhead	ESM Event	Same CPU clock cycle as data is used
	EFU3	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	EFU4	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	EFU5	Autoload Self Test Auto-Coverage	NA - This is a test of the Efuse autoload diagnostic. It is not a diagnostic itself	Test- for-Diagnostic	Hardware	At Boot Time	Device Dependent (see the device-specific data sheet)	ESM Event	No Overhead (Available on 1st CPU clock cycle after release of reset)
	EFU6	EFuse ECC Logic Self Test	NA - This is a test of the Efuse ECC logic through self-test diagnostic. It is not a diagnostic itself	Test-for-Diagnostic	Software - Hardware	On Demand	No Hardware Overhead	ESM Event	No Overhead

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
One Time Programmable (OTP) Flash Static Configuration	OTP1	OTP ECC	CPU1: CPU Lockstep Compare, OTP14: Flash Wrapper Diag Mode 5 Test OTP15: Flash Wrapper Diag Mode 7 Test	Diagnostic	Hardware	Continuous	No Hardware Overhead	ESM Event	Same CPU clock cycle as data used
	OTP2	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	OTP3	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	OTP4A	Boot Time Hardware CRC Check of OTP Contents	OTP3: Software Readback of Written Configuration OTP12: Software Test of Hardware CRC OTP13: CRC Auto-Coverage CLK5C: External Watchdog	Diagnostic	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	OTP4B	Periodic Hardware CRC Check of OTP Contents	OTP3: Software Readback of Written Configuration OTP12: Software Test of Hardware CRC OTP13: CRC Auto-Coverage CLK5C: External Watchdog	Diagnostic	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	OTP5	Bit Multiplexing in Flash Memory Array	N/A - Fault Avoidance	Diagnostic	Hardware	Continuous	N/A - Fault Avoidance	N/A - Fault Avoidance	N/A - Fault Avoidance
	OTP6	Flash Sector Protection	OTP11: Software Test of Flash Sector Protection Logic	Diagnostic	Hardware	Continuous	No Hardware Overhead	Flash Programming Blocked	Software Dependent
	OTP11	Software Test of Flash Sector Protection Logic	NA - This is a test of the flash sector protection logic diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	OTP12	Software Test of Hardware CRC	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	OTP13	CRC Auto-Coverage	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in CRC operation	N/A	N/A

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
One Time Programmable (OTP) Flash Static Configuration	OTP14	Flash Wrapper Diag Mode 5 Test	NA - this is a test of a diagnostic. It is not a diagnostic itself	Test for Diagnostic	Software - Hardware	On Demand	Software Dependent Typically <1 µs overhead due to hardware	Software Dependent	Software Dependent
	OTP15	Flash Wrapper Diag Mode 7 Test	NA - this is a test of a diagnostic. It is not a diagnostic itself	Test for Diagnostic	Software - Hardware	On Demand	Software Dependent Typically <1 µs overhead due to hardware	Software Dependent	Software Dependent
Input/Output (I/O) Multiplexing Module (IOMM)	IOM1	Locking Mechanism For Control Registers	N/A	Diagnostic	Hardware (Fault Avoidance)	Continuous	No Hardware Overhead	N/A (Fault Avoidance)	N/A (Fault Avoidance)
	IOM2	Master ID Filtering	N/A	Diagnostic	Hardware (Fault Avoidance)	Periodic / On-Demand	No Hardware Overhead	N/A (Fault Avoidance)	N/A (Fault Avoidance)
	IOM3	Error Trapping	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC Boot Time Software Test of Function Using I/O Loopback Including Error Tests Periodic Software Test of Function Using I/O Loopback Including Error Tests	Diagnostic	Hardware	Periodic / On-Demand	No Hardware Overhead	Bus Error	Bus master notification typically <10 clock cycles after fault detection
	IOM4	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	IOM5A	Boot Time Software Test of Function Using I/O Loopback Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	IOM5B	Periodic Software Test of Function Using I/O Loopback Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	IOM6	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Vectored Interrupt Module (VIM)	VIM1	VIM SRAM Data ECC	VIM7: Software Readback of Written Configuration VIM8: Software test of ECC Logic VIM9: PBIST Test of ECC Bit Memory	Diagnostic	Hardware	Continuous	No Overhead (Same clock cycle)	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	VIM2A	Boot Time PBIST Check of VIM SRAM	VIM7: Software Readback of Written Configuration VIM12: Software Test of PBIST VIM13: PBIST Auto-Coverage CPU1: CPU Lockstep Compare CLK5C: External Watchdog FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	VIM2B	Periodic PBIST Check of VIM SRAM	VIM7: Software Readback of Written Configuration VIM12: Software Test of PBIST VIM13: PBIST Auto-Coverage CPU1: CPU Lockstep Compare CLK5C: External Watchdog FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	VIM3	Bit Multiplexing in VIM SRAM Array	N/A	Diagnostic	Hardware	Continuous	N/A (Fault Avoidance)	N/A (Fault Avoidance)	N/A (Fault Avoidance)
	VIM4	Periodic Hardware CRC Check of VIM SRAM Contents	VIM7: Software Readback of Written Configuration VIM10: Software Test of Hardware CRC VIM11: CRC Auto-Coverage	Diagnostic	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	VIM5A	Boot Time Software Test of VIM Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software-Dependent; hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	VIM5B	Periodic Software Test of VIM Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software-Dependent; hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	VIM6	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	VIM7	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Vectored Interrupt Module (VIM)	VIM8	Software test of ECC Logic	NA - This is a test of the parity logic diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	VIM9	PBIST Test of ECC Bit Memory	NA - This is a test of the parity bit memory diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	VIM10	Software Test of Hardware CRC	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	VIM11	CRC Auto-Coverage	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in CRC operation	N/A	N/A
	VIM12	Software Test of PBIST	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	VIM13	PBIST Auto-Coverage	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in PBIST operation	N/A	N/A
	VIM14	VIM Lockstep Compare	VIM15: Lockstep Compare Self-Test	Diagnostic	Hardware	Continuous	2 VCLK Cycles	ESM Error	Typically <1 µs (implementation dependent)
	VIM15	Lockstep Compare Self-Test	NA - This is a test of the Lockstep diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
Real Time Interrupt (RTI) Operating System Timer	RTI1	1oo2 Software Voting Using Secondary Free Running Counter	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	RTI2	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	RTI3	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Direct Memory Access (DMA)	DMA1	Memory Protection Unit for Bus Master Accesses	DMA18: Software Test of MPU Functionality	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	DMA2	Non-Privileged Bus Master Access	N/A - feature is for fault avoidance	Diagnostic	Hardware	Continuous	No Hardware Overhead	N/A	N/A - Fault Avoidance
	DMA3	Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	DMA4	DMA SRAM Data ECC	DMA10: Software Readback of Written Configuration DMA12: Software test of ECC Logic DMA13: PBIST Test of ECC Bit Memory	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	DMA5A	Boot Time PBIST Check of DMA SRAM	DMA10: Software Readback of Written Configuration DMA16: Software Test of PBIST DMA17: PBIST Auto-Coverage CPU1: CPU Lockstep Compare CLK5C: External Watchdog FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	DMA5B	Periodic PBIST Check of DMA SRAM	DMA10: Software Readback of Written Configuration DMA16: Software Test of PBIST DMA17: PBIST Auto-Coverage CPU1: CPU Lockstep Compare CLK5C: External Watchdog FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	DMA6	Bit Multiplexing in DMA SRAM Array	N/A	Diagnostic	Hardware	Continuous	N/A - Fault Avoidance	N/A - Fault Avoidance	N/A - Fault Avoidance
	DMA7	Periodic Hardware CRC Check of DMA SRAM Contents	DMA10: Software Readback of Written Configuration DMA14: Software Test of Hardware CRC DMA13: CRC Auto-Coverage	Diagnostic	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	DMA8	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Direct Memory Access (DMA)	DMA9A	Boot Time Software Test of DMA MPU Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software-Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	DMA9B	Periodic Software Test of DMA MPU Functionality Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software-Dependent; hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	DMA10	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	DMA11	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	System Dependent	System Dependent	System Dependent
	DMA12	Software test of ECC Logic	NA - This is a test of the parity logic diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	DMA13	PBIST Test of ECC Bit Memory	NA - This is a test of the parity bit memory diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	DMA14	Software Test of Hardware CRC	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	DMA15	CRC Auto-Coverage	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in CRC operation	N/A	N/A
	DMA16	Software Test of PBIST	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	DMA17	PBIST Auto-Coverage	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in PBIST operation	N/A	N/A
	DMA18	Software Test of MPU Functionality	NA - This is a test of the MPU functionality diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	DMA19	Multi-Bit Keyed Self-Correctable High-Integrity Bits	N/A	Diagnostic	Hardware	Continuous	No Hardware Overhead	Control Register not Updated (Fault Avoidance)	Typically less than 5 cycles to ESM

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Direct Memory Access (DMA)	DMA20	Peripheral Interconnect New Memory Protection Unit (NMPU)	DMA18: Software Test of MPU Functionality	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to the CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
High-End Timer (N2HET) Including HET Transfer Unit (HTU)	HET1	Memory Protection Unit for HTU Bus Master Accesses	HET11: Software Readback of Written Configuration HET19: Software Test of MPU Functionality	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	HET2	Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	HET3	Use of DCC as Program Sequence Watchdog	HET11: Software Readback of Written Configuration HET20: Software Test of DCC Operation	Diagnostic	Software - Hardware	Continuous	Software Dependent	Software Dependent	Software Dependent
	HET4	Monitoring by Second N2HET	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Continuous	Software Dependent	Software Dependent	Software Dependent
	HET5A	Boot Time Software Test of Function Using I/O Loopback	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software-Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	HET5B	Periodic Software Test of Function Using I/O Loopback	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software-Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	HET6	N2HET/HTU SRAM Data Parity	HET11: Software Readback of Written Configuration HET13: Software test of Parity Logic HET14: PBIST Test of Parity Bit Memory	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	HET7A	Boot Time PBIST Check of N2HET/HTU SRAM	HET11: Software Readback of Written Configuration HET17: Software Test of PBIST HET18: PBIST Auto-Coverage	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	HET7B	Periodic PBIST Check of N2HET/HTU SRAM	HET11: Software Readback of Written Configuration HET17: Software Test of PBIST HET18: PBIST Auto-Coverage	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	HET8	Bit Multiplexing in N2HET/HTU SRAM Array	N/A - Fault Avoidance	Diagnostic	Hardware	Continuous	N/A (Fault Avoidance)	N/A (Fault Avoidance)	N/A (Fault Avoidance)

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
High-End Timer (N2HET) Including HET Transfer Unit (HTU)	HET9	Periodic Hardware CRC Check of N2HET/HTU SRAM Contents	HET11: Software Readback of Written Configuration HET15: Software Test of Hardware CRC HET16: CRC Auto-Coverage	Diagnostic	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	HET10	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software-Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	HET11	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	HET12	Transmission Redundancy (for Transfer Unit)	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	System Dependent	System Dependent	System Dependent
	HET13	Software test of Parity Logic	NA - This is a test of the parity logic diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	HET14	PBIST Test of Parity Bit Memory	NA - This is a test of the parity bit memory diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	HET15	Software Test of Hardware CRC	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Defined	Software Dependent
	HET16	CRC Auto-Coverage	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in CRC operation	N/A	N/A
	HET17	Software Test of PBIST	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	HET18	PBIST Auto-Coverage	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in PBIST operation	N/A; implicit in PBIST operation	N/A

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
High-End Timer (N2HET) Including HET Transfer Unit (HTU)	HET19	Software Test of MPU Functionality	NA - This is a test of the MPU functionality diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	HET20	Software Test of DCC Functionality	NA - This is a test of the DCC functionality diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	HET21A	Boot Time Execution of HET LBIST STC	HET22: LBIST Auto-Coverage	Diagnostic	Hardware	Periodic/ON-Demand	Device Dependent (see the device-specific data sheet)	Error Flag Asserted	Software Dependent
	HET21B	Periodic Execution of HET LBIST STC	HET22: LBIST Auto-Coverage	Diagnostic	Hardware	Periodic/ON-Demand	Device Dependent (see the device-specific data sheet)	Error Flag Asserted	Software Dependent
	HET22	LBIST Auto-Coverage	NA - This is a test of the LBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in LBIST operation	N/A	N/A
Multi-Buffered Analog to Digital Converter (MibADC)	ADC1	Boot Time Input Self-Test	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Two conversions per channel under test required Typical sample time is 1 µs/conversion but dependent on device configuration Software overhead must also be considered	Software Dependent	Software Dependent
	ADC2A	Boot Time MibADC Calibration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Four conversions per channel under test required Typical sample time is 1 µs/conversion but dependent on device configuration Software overhead must also be considered	Software Dependent	Software Dependent
	ADC2B	Periodic MibADC Calibration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Four conversions per channel under test required Typical sample time is 1 µs/conversion but dependent on device configuration Software overhead must also be considered	Software Dependent	Software Dependent
	ADC3	MibADC Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software-Dependent	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Multi-Buffered Analog to Digital Converter (MibADC)	ADC4	MibADC SRAM Data Parity	ADC9: Software Readback of Written Configuration ADC11: PBIST Test of Parity Bit Memory	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	ADC5A	Boot Time PBIST Check of MibADC SRAM	ADC9: Software Readback of Written Configuration ADC14: Software Test of PBIST ADC15: PBIST Auto-Coverage CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	ADC5B	Periodic PBIST Check of MibADC SRAM	ADC9: Software Readback of Written Configuration ADC14: Software Test of PBIST ADC15: PBIST Auto-Coverage CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	ADC6	Bit Multiplexing in MibADC SRAM Array	N/A	Diagnostic	Hardware	Continuous	N/A (Fault Avoidance)	N/A (Fault Avoidance)	N/A (Fault Avoidance)
	ADC7	Periodic Hardware CRC Check of MibADC SRAM Contents	ADC9: Software Readback of Written Configuration ADC12: Software Test of Hardware CRC ADC13: CRC Auto-Coverage	Diagnostic	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	ADC8	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	ADC9	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software-Dependent	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Multi-Buffered Analog-to-Digital Converter (MibADC)	ADC10	Software test of Parity Logic	NA - This is a test of the parity logic diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	ADC11	PBIST Test of Parity Bit Memory	NA - This is a test of the parity bit memory diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	ADC12	Software Test of Hardware CRC	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software - Hardware	Periodic / On-Demand	Depends on Size of Memory Under Test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	ADC13	CRC Auto-Coverage	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in CRC operation	N/A	N/A
	ADC14	Software Test of PBIST	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	ADC15	PBIST Auto-Coverage	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in PBIST operation	N/A	N/A

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Enhanced Pulse Width Modulators (ePWM)	PWM1A	Boot Time Software Test of Function Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	PWM1B	Periodic Software Test of Function Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	PWM2	Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	PWM3	Monitoring by eCAP or N2HET	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC CAP1A: Boot Time Software Test of eCAP Function CAP1B: Periodic Software Test of eCAP Function HET5A: Boot Time Software Test of N2HET Function Using I/O Loopback HET5B: Periodic Software Test of N2HET Function Using I/O Loopback	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	PWM4	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	PWM5	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Enhanced Capture (eCAP)	CAP1A	Boot Time Software Test of Function Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	CAP1B	Periodic Software Test of Function Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	CAP2	Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	CAP3	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	CAP4	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Enhanced Quadrature Encoder Pulse (eQEP)	QEP1A	Boot Time Software Test of Function Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	QEP1B	Periodic Software Test of Function Including Error Tests	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	QEP2	Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	QEP3	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	QEP4	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	QEP5	Quadrature Watchdog	QEP6: Software Test of Quadrature Watchdog Functionality	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	QEP6	Software Test of Quadrature Watchdog Functionality	NA - Test of quadrature watchdog functionality diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Multi-Buffered Serial Peripheral Interface (MibSPI)	MSP1A	Boot Time Software Test of Function Using I/O Loopback	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software-Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	MSP1B	Periodic Software Test of Function Using I/O Loopback	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software / Hardware	Periodic / On-Demand	Software-Dependent Hardware contribution to test execution time is negligible	Software Defined	Software-Dependent
	MSP2	Parity in Message	MSP9: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	MSP3	Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	MSP4	MibSPI SRAM ECC	MSP9: Software Readback of Written Configuration MSP16: Software test of ECC Logic MSP17: PBIST Test of ECC Bit Memory	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU (implementation dependent)
	MSP5A	Boot Time PBIST Check of MibSPI SRAM	MSP9: Software Readback of Written Configuration MSP20: Software Test of PBIST MSP21: PBIST Auto-Coverage CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	MSP5B	Periodic PBIST Check of MibSPI SRAM	MSP9: Software Readback of Written Configuration MSP20: Software Test of PBIST MSP21: PBIST Auto-Coverage CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	MSP6	Bit Multiplexing in MibSPI SRAM Array	N/A	Diagnostic	Hardware	Continuous	N/A (Fault Avoidance)	N/A (Fault Avoidance)	N/A (Fault Avoidance)

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Multi-Buffered Serial Peripheral Interface (MibSPI)	MSP7	Periodic Hardware CRC Check of MibSPI SRAM Contents	MSP9: Software Readback of Written Configuration MSP18: Software Test of Hardware CRC MSP19: CRC Auto-Coverage	Diagnostic	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	MSP8	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	MSP9	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	MSP10	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	System Dependent	System Defined	System Dependent
	MSP11	Data Overrun Error Detection	MSP9: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	MSP12	Bit Error Detection	MSP9: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	MSP13	Slave Desync Detection	MSP9: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	MSP14	Slave Timeout Detection	MSP9: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	MSP15	Data Length Error Detection	MSP9: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	MSP16	Software test of ECC Logic	NA - This is a test of the parity logic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Multi-Buffered Serial Peripheral Interface (MibSPI)	MSP17	PBIST Test of ECC Bit Memory	NA - This is a test of the parity bit memory. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	MSP18	Software Test of Hardware CRC	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	MSP19	CRC Auto-Coverage	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in CRC operation	N/A	N/A
	MSP20	Software Test of PBIST	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	MSP21	PBIST Auto-Coverage	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in PBIST operation	N/A	N/A

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Inter-Integrated Circuit (I2C)	IIC1A	Boot Time Software Test of Function Using I/O Loopback	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	IIC1B	Periodic Software Test of Function Using I/O Loopback	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	IIC2	Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	IIC3	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	IIC4	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	IIC5	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	System Dependent	System Dependent	System Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Serial Communications Interface (SCI)	SCI1A	Boot Time Software Test of Function Using I/O Loopback	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	SCI1B	Periodic Software Test of Function Using I/O Loopback	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	SCI2	Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	SCI3	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	SCI4	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	SCI5	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	System Dependent	System Dependent	System Dependent
	SCI6	Overrun Error Detection	SCI4: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	SCI7	Frame Error Detection	SCI4: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	SCI8	Bit Error Detection	SCI4: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	SCI9	Parity in Message	SCI2: Information Redundancy Techniques	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Local Interconnect Network (LIN)	LIN1A	Boot Time Software Test of Function Using I/O Loopback	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	On Demand	Software-Dependent	Software Defined	Software-Dependent
	LIN1B	Periodic Software Test of Function Using I/O Loopback	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	On Demand	Software-Dependent	Software Defined	Software-Dependent
	LIN2	Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	On Demand	Software-Dependent	Software Defined	Software-Dependent
	LIN3	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	On Demand	Software-Dependent. Typically <25 CPU clocks per 32-bit Register Read	Software Defined	Software-Dependent
	LIN4	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	On Demand	Software Dependent	Software Defined	Software-Dependent
	LIN5	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	On Demand	System Dependent	System Defined	System Dependent
	LIN6	Overrun Error Detection	LIN4: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Overhead (Same clock cycle)	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	LIN7	Frame Error Detection	LIN4: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Overhead (Same clock cycle)	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	LIN8	Physical Bus Error Detection	LIN4: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Overhead (Same clock cycle)	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	LIN9	No-Response Error Detection	LIN4: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Overhead (Same clock cycle)	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Local Interconnect Network (LIN)	LIN10	Bit Error Detection	LIN4: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Overhead (Same clock cycle)	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	LIN11	Checksum Error Detection	LIN4: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Overhead (Same clock cycle)	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	LIN12	Parity in Message	LIN4: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Overhead (Same clock cycle)	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Controller Area Network (DCAN)	CAN1A	Boot Time Software Test of Function Using I/O Loopback	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software-Hardware	On Demand	Software Dependent	Software Dependent	Software Dependent
	CAN1B	Periodic Software Test of Function Using I/O Loopback	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software-Hardware	On Demand	Software Dependent	Software Dependent	Software Dependent
	CAN2	Information Redundancy Techniques Including End to End Safing	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	On Demand	Software Dependent	Software Dependent	Software Dependent
	CAN3	DCAN SRAM Data ECC	CAN2: Information Redundancy Techniques Including End to End Safing CAN8: Software Readback of Written Configuration CAN15: Software test of ECC Logic CAN16: PBIST Test of ECC Bit Memory	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU (implementation dependent)
	CAN4A	Boot Time PBIST Check of DCAN SRAM	CAN8: Software Readback of Written Configuration CAN19: Software Test of PBIST CAN20: PBIST Auto-Coverage CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	On Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	CAN4B	Periodic PBIST Check of DCAN SRAM	CAN8: Software Readback of Written Configuration CAN19: Software Test of PBIST CAN20: PBIST Auto-Coverage CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	On Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	CAN5	Bit Multiplexing in DCAN SRAM Array	N/A - Fault Avoidance	Diagnostic	Hardware	Continuous	N/A - Fault Avoidance	N/A - Fault Avoidance	N/A - Fault Avoidance
	CAN6	Periodic Hardware CRC Check of DCAN SRAM Contents	CAN8: Software Readback of Written Configuration CAN17: Software Test of Hardware CRC CAN18: CRC Auto-Coverage	Diagnostic	Software-Hardware	On Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Controller Area Network (DCAN)	CAN7	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	CAN8	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	CAN9	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	On Demand	System Dependent	System Dependent	System Dependent
	CAN10	Stuff Error Detection	CAN8: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	CAN11	Form Error Detection	CAN8: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	CAN12	Acknowledge Error Detection	CAN8: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	CAN13	Bit Error Detection	CAN8: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	CAN14	CAN Protocol CRC in Message	CAN8: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	CAN15	Software test of ECC Logic	NA - This is a test of the parity logic diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Controller Area Network (DCAN)	CAN16	PBIST Test of ECC Bit Memory	NA - This is a test of the parity bit memory diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	CAN17	Software Test of Hardware CRC	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software-Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	CAN18	CRC Auto-Coverage	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; this is an implicit part of the CRC diagnostic	N/A	N/A
	CAN19	Software Test of PBIST	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	CAN20	PBIST Auto-Coverage	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; this is an implicit part of the PBIST diagnostic	N/A	N/A
General Purpose Input/Output (GIO)	GIO1A	Boot Time Software Test of Function Using I/O Checking In GIO Mode	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	GIO1B	Periodic Software Test of Function Using I/O Checking In GIO Mode	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	GIO2	Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	GIO3	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	GIO4	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Ethernet	ETH1	Non-Privileged Bus Master Access	N/A	Diagnostic	Hardware	Continuous	No Hardware Overhead	N/A	N/A - Fault avoidance
	ETH2A	Boot Time Software Test of Function Using I/O Loopback in PHY	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	ETH2B	Periodic Software Test of Function Using I/O Loopback in PHY	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software - Hardware	Periodic / On-Demand	Software Dependent Hardware contribution to test execution time is negligible	Software Dependent	Software Dependent
	ETH3	Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	ETH4A	Boot Time PBIST Check of Ethernet SRAM	ETH8: Software Readback of Written Configuration ETH15: Software Test of PBIST ETH16: PBIST Auto-Coverage CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	ETH4B	Periodic PBIST Check of Ethernet SRAM	ETH8: Software Readback of Written Configuration ETH15: Software Test of PBIST ETH16: PBIST Auto-Coverage CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Hardware	Periodic / On-Demand	Device Dependent (see the device-specific data sheet)	Flag Set in Error Register	Software Dependent
	ETH5	Bit Multiplexing in Ethernet SRAM Array	N/A	Diagnostic	Hardware	Continuous	N/A - Fault Avoidance	N/A - Fault Avoidance	N/A - Fault Avoidance
	ETH6	Periodic Hardware CRC Check of Ethernet SRAM Contents	ETH8: Software Readback of Written Configuration ETH13: Software Test of Hardware CRC ETH14: CRC Auto-Coverage	Diagnostic	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	ETH7	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Ethernet	ETH8	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	ETH9	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	System Dependent	System Dependent	System Dependent
	ETH10	CRC in Message	ETH8: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	ETH11	Ethernet Alignment Error Detection	ETH8: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	ETH12	Ethernet Physical Layer Fault	ETH8: Software Readback of Written Configuration	Diagnostic	Hardware	Continuous	No Hardware Overhead	Interrupt Provided to CPU	Typically <1 µS to notify CPU* *(Interrupt handling time is system load and software dependent)
	ETH13	Software Test of Hardware CRC	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	ETH14	CRC Auto-Coverage	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in CRC operation	N/A	N/A
	ETH15	Software Test of PBIST	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	ETH16	PBIST Auto-Coverage	NA - This is a test of the PBIST diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; implicit in PBIST operation	N/A	N/A
	ETH17	Peripheral Interconnect New Memory Protection Unit (NMPU)	ETH18: Software test of New Memory Protection Unit (NMPU) Function	Diagnostic	Hardware	Continuous	No Hardware Overhead	ESM Error	Typically <1 µS to notify CPU (implementation dependent)
	ETH18	Software test of New Memory Protection Unit (NMPU) Function	NA - This is a test of the NMPU diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
External Memory Interface (EMIF)	EMF1	Information Redundancy Techniques	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent	Software Dependent	Software Dependent
	EMF2A	Boot Time Hardware CRC Check of External Memory	EMF4: Software Readback of Written Configuration EMF6: Software Test of Hardware CRC EMF7: CRC Auto-Coverage	Diagnostic	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	EMF2B	Periodic Hardware CRC Check of External Memory	EMF4: Software Readback of Written Configuration EMF6: Software Test of Hardware CRC EMF7: CRC Auto-Coverage	Diagnostic	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	EMF3	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	EMF4	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	Software Dependent Typically <25 CPU clocks per 32-bit Register Read	Software Dependent	Software Dependent
	EMF5	Transmission Redundancy	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic / On-Demand	System Dependent	System Dependent	System Dependent
	EMF6	Software Test of Hardware CRC	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Software - Hardware	Periodic / On-Demand	Depends on size of memory under test. One 64-bit word per clock cycle plus overhead. Overhead is software dependent.	Software Dependent	Software Dependent
	EMF7	CRC Auto-Coverage	NA - This is a test of the hardware CRC diagnostic. It is not a diagnostic itself	Test-for-Diagnostic Only	Hardware	Periodic / On-Demand	N/A; this is an implicit part of the CRC diagnostic	N/A	N/A
Joint Technical Action Group (JTAG) Debug/Trace/ Calibration Access	JTG1	Hardware Disable of JTAG Port	N/A	Diagnostic	Hardware	Continuous	No Hardware Overhead	N/A (Fault Avoidance)	N/A (Fault Avoidance)
	JTG2	Lockout of JTAG Access Using AJSM	N/A	Diagnostic	Hardware	Continuous	No Hardware Overhead	JTAG Access Blocked	N/A (Fault Avoidance)

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Table 4. Summary of Safety Features and Diagnostics (continued)

Device Partition	Unique Identifier	Safety Feature or Diagnostic	Possible Tests for Diagnostics	Usage	Diagnostic Type	Diagnostic Operation	Text Execution Time	Action on Detected Fault	Error Reporting Time
Cortex-R5F Central Processing Unit (CPU) Debug and Trace	DBG1	Use of MPUs to Block Access to Memory-Mapped Debug	N/A	Diagnostic	Hardware	Continuous	No Hardware Overhead	Data abort	Same CPU cycle as fault detected
	DBG2	Use of CoreSight Debug Logic Key Enable Scheme	N/A	Diagnostic	Hardware	Continuous	No Hardware Overhead	Debug Access Locked	N/A (Fault Avoidance)
Data Modification Module	DMM1	Disable the DMM Pin Interface	N/A	Diagnostic - Fault Avoidance	Hardware	Continuous	No hardware overhead	No DMM operation allowed	N/A - fault avoidance
RAM Trace Port	RTP1	Disable the RTP Pin Interface	N/A	Diagnostic - Fault Avoidance	Hardware	Continuous	No hardware overhead	No RTP operation allowed	N/A - fault avoidance
Error Profiling Controller	EPC1	Periodic Software Readback of Static Configuration Registers	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic/On-Demand	Software dependent Typically <25 CPU clock cycle hardware overhead per 32b register read	Software Dependent	Software Dependent
	EPC2A	Boot Time Software Test of Error Path Reporting	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software/Hardware	Periodic/On-Demand	Software Dependent Hardware contribution to test execution time is negligible.	Software dependent	Software dependent
	EPC2B	Periodic Software Test of Error Path Reporting	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software/Hardware	Periodic/On-Demand	Software Dependent Hardware contribution to test execution time is negligible.	Software dependent	Software dependent
	EPC3	Software Readback of Written Configuration	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic	Software	Periodic/On-Demand	Software dependent Typically <25 CPU clock cycle hardware overhead per 32b register read	Software Dependent	Software Dependent
Temperature Sensor	TSN1	Redundant Temperature Sensors	CLK5A: Internal Watchdog - DWD CLK5B: Internal Watchdog - DWWD CLK5C: External Watchdog CPU1: CPU Lockstep Compare FLA1: Flash Data ECC RAM1: RAM Data ECC	Diagnostic/Test for Diagnostic	Hardware/Software	Periodic/On-Demand	Software Dependent	Software Dependent	Software Dependent

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Development Interface Agreement

A Development Interface Agreement (DIA) is intended to capture an agreement between a customer and supplier towards the management of shared responsibilities in developing a functional safety system. In custom developments, the DIA is a key document executed between customer and supplier early in the development process. As the Hercules family is a commercial, off the shelf (COTS) product, TI has prepared a standard DIA within this section that describes the support that TI can provide for customer developments. Requests for custom DIAs should be referred to your local TI sales office for disposition.

B.1 Appointment of Safety Managers

Texas Instruments has developed the Hercules MCUs with one or more development specialist safety managers in place throughout the silicon design, release to market, and release to production. Safety management after release to production is maintained by separate safety managers who specialize in production and operation issues. Safety management responsibilities are continued through product end-of-life.

B.2 Tailoring of the Safety Lifecycle

TI has tailored the safety lifecycles of IEC 61508 to best match the needs of a safety element out of context (SEooC). The tailoring activity has been executed in conjunction with input from exida and Yogitech to ensure application of state of the art techniques and measures.

Key elements of the tailored safety lifecycle are:

- Assumptions on system level design, safety concept, and requirements
- Combined qualitative and quantitative or similar safety analysis techniques comprehending the sum of silicon failure modes and diagnostic techniques known to both TI and Yogitech
- Fault estimation based on multiple industry standards as well as TI "real-world" reliability data
- Application of Yogitech's state-of-the-art fault injection methodology for validation of claimed diagnostic coverage
- Integration of lessons learned by through multiple safety critical developments to IEC 61508

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Figure 8 illustrates these activities overlaid atop TI's standard QM development flow for microcontrollers.

Phase 0 Business Opportunity Prescreen	Phase 1 Program Planning	Phase 2 Create	Phase 2.5 Validate, Sample, and Characterize	Phase 3 Qualify	Phase 4 Ramp or Sustain
Determine if safety process execution is necessary	Define SIL/ASIL capability	Execute safety design	Validate safety design in silicon	Qualification of safety design	Implement plans to support operation and production
Execute development interface agreement (DIA) with lead customers and suppliers	Generate safety plan	Qualitative analysis of design (FMEA and FTA)	Release safety manual	Release safety case report	Update safety case report (if needed)
	Initiate safety case	Incorporate findings into safety design	Release safety analysis report	Update safety manual (if needed)	Periodic confirmation measure reviews
	Analyze system to generate system level safety assumptions and requirements	Develop safety product preview	Characterization of safety design	Update safety analysis report (if needed)	
	Develop component level safety requirements	Validation of safety design at RTL level	Confirmation measure review	Confirmation measure review	
	Validate component safety requirements meet system safety requirements	Quantitative analysis of design (FMEDA)			
	Implement safety requirements in design specification	Incorporate findings into safety design			
	Validate design specification meets component safety requirements	Validation of safety design at gate/layout level			
	Confirmation measure review	Confirmation measure review			

Figure 8. Hercules Tailoring of Safety Lifecycle

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B.3 Activities Performed by TI

The TI microcontroller products covered by this DIA are hardware components developed as safety elements out of context. As such TI's safety activities focus on those related to management of functional safety and hardware component development. System level architecture, design, and safety analysis are not in scope of TI activities and are the responsibility of the TI customer.

Table 5. Activities Performed by TI vs. Performed by SEooC Customer

Safety Lifecycle Activity	TI Execution	SEooC Customer Execution
Management of functional safety	Yes	Yes
Definition of end equipment and item	No	Yes
Hazard and risk analysis of end equipment/item	No	Yes
Development of end equipment safety concept	Assumptions made to support internal development. Contact TI if support is needed	Yes
Allocation of end equipment requirements to sub-systems, hardware components, and software components	Assumptions made to support internal development. Contact TI if support is needed	Yes
Definition of MCU safety requirements	Yes	No
MCU architecture and design execution	Yes	Possible for diagnostics implemented by SEooC customer. Contact TI if support is needed
MCU level safety analysis	Yes	Possible for diagnostics implemented by SEooC customer. Contact TI if support is needed
MCU level verification and validation	V&V executed to support internal development. Contact TI if support is needed.	Possible for diagnostics implemented by SEooC customer. Contact TI if support is needed
Integration of MCU into end equipment	Support provided	Yes
Verification of MCU performance in end equipment	Support provided	Yes
Selection of Diagnostics to be Applied to MCU	Support provided	Yes
End equipment level safety analysis	No	Yes
End equipment level verification and validation	No	Yes
End equipment level safety assessment	Support provided	Yes
End equipment release to production	No	Yes
Management of safety issues in production	Support provided	Yes

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B.4 Information to be Exchanged

In a custom development, there is an expectation under IEC 61508 that all development documents related to work products are made available to the customer. In a COTS product, this approach is not sustainable. TI has summarized the most critical development items into a series of documents that can be made available to customers either publicly or under a non-disclosure agreement (NDA). NDAs are required in order to protect proprietary and sensitive information disclosed in certain safety documents.

Table 6 summarizes the product safety documentation that TI can provide to customers to assist in development of safety systems.

Table 6. Product Safety Documentation

Deliverable Name	Contents	Confidentiality	Availability
Safety Product Preview	Overview of safety considerations in product development and product architecture. Delivered ahead of public product announcement.	NDA required	Removed from circulation after release to market due to availability of Safety Manual
Safety Manual	User guide for the safety features of the product	Public, no NDA required	Available
Safety Analysis Report Summary for RM57x ARM®-Based Safety Critical Microcontrollers (SPNU578)	Summary of FIT rates and device safety metrics according to ISO 26262 and/or IEC 61508 at device level.	NDA required	Available
Detailed Safety Analysis Report for ARM®-Based Safety Critical Microcontrollers filter="filter4">(SPNU542)(SPNU579)	Full results of all available safety analysis documented in a format that allows computation of custom metrics	NDA required	Available
Safety Report (for more information, contact your TI sales representative)	Summary of the conformance of the product to the ISO 26262 and/or IEC 61508 standards	NDA required	In development

Table 7. Product Functional Documentation to be Considered in Safety-Related Design

Deliverable Name	Contents	Confidentiality	Availability
Technical Reference Manual (TRM)	User Guide for the device	Public; no NDA required	Available
Datasheet	Device-specific features and operating constraints	Public; no NDA required	Available
Errata	Lists known discrepancies between device documentation and device functionality / performance	Public; no NDA required	Available

Users may subscribe to be notified of documentation changes for any Hercules device by performing the following steps:

- Visit www.ti.com/hercules
- Select "Products"
- Choose the link for the desired device
- Click the "Product Alert" link

B.5 Parties Responsible for Safety Activities

TI applies a cross functional approach to safety related development. Safety related activities are carried out by a variety of program managers, safety managers, applications engineers, design engineers, and other development and production engineering functions.

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B.6 Communication of Target Values

As the Hercules MCU product is developed as a safety element out of context, there is no system developer involved during the MCU design who has provided target metrics for the MCU development. At start of development TI makes assumptions of plausible MCU level safety target values and designs the products to meet such targets. The *Safety Analysis Report Summary for RM57x ARM®-Based Safety Critical Microcontrollers* (SPNU578) and the *Detailed Safety Analysis Report for RM57x ARM®-Based Safety Critical Microcontrollers* (SPNU579) can be utilized to evaluate achieved safety metrics. The ultimate responsibility to determine if the TI component is suitable for use in the system rests on the system integrator.

B.7 Supporting Processes and Tools

TI uses a variety of tools and corresponding data formats for internal and external documents. The tools and data formats that are relevant to the safety related documents shared with SEooC customers are noted in Table 8.

Table 8. Product Safety Documentation Tools and Formats

Deliverable Name	Creation Tool(s)	Output Format(s)
Safety Product Preview	Microsoft® Word	Adobe™ PDF
Safety Manual	XML	Adobe PDF
Safety Analysis Report Summary for RM57x ARM®-Based Safety Critical Microcontrollers (SPNU578)	XML, Microsoft Excel®	Adobe PDF
Detailed Safety Analysis Report for RM57xARM®-Based Safety Critical Microcontrollers (SPNU579)	XML, Microsoft Excel	Adobe PDF, Microsoft Excel
Safety Case Report (for more information, contact your TI sales representative)	IBM® DOORS®, XML	Adobe PDF

B.8 Supplier Hazard and Risk Assessment

Hazard and risk assessments under IEC 61508 and ISO 26262 are targeted at the system level of abstraction. When developing a hardware component out of context, the system implementation is not known. Therefore TI has not executed a system hazard and risk analysis. Instead, TI has made assumptions on the results of hazard and risk analysis that are fed into the component design. The ultimate responsibility to determine if the TI component is suitable for use in the system rests on the system integrator.

B.9 Creation of Functional Safety Concept

The functional safety concept under IEC 61508 and ISO 26262 is targeted at the system level of abstraction. When developing a hardware component out of context, the system implementation is not known. Therefore TI cannot generate a system functional safety concept. Instead, TI has made assumptions on the output of a system functional safety concept and this data has been fed into the component design. The ultimate responsibility to determine if the TI component is suitable for use in the system rests on the system integrator.

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Revision History

This document has been revised from SPNU575 to SPNU54475A because of the following technical change(s).

Table 9. SPNU575A Revisions

Location	Additions, Deletes, and Edits
Throughout document	Changed references from "TI system basis chip" to "TI TPS6538x"
Throughout document	Corrected references to ISO 26262-10 to reflect IS version released in late 2012
Throughout document	Clarified that latent fault definition is based on ISO 26262:2011 definition of latent fault
Section 7.7	Added reference to ARM® R5/R5F TRM for instructions on enabling traps.
Throughout document	Removed all Recommendation Levels (Mandatory, Highly Recommended, Recommended, Optional) from Appendix A and throughout document
Throughout document	Corrected document to reflect analog I/O loopback drives output pins
Revision History	Fixed Typo ROM -> POM
Section 2	Added detail that this is a Type B, HFT=0 device as defined in IEC 61508
Appendix A, Table 3	Added the following new columns of information to Appendix A, Table 3: - Usage (Diagnostic or Test-for-Diagnostic only) - Diagnostic Type Diagnostic Operation - Test Execution Time - Action on Detected Fault - Error Reporting Time
Appendix A, Table 3	Changed items in "Possible Latent Diagnostics" column and added links throughout the table (Column name changed to "Possible Tests for Diagnostics")
Appendix A, Table 3 Power Supply	PWR1: Added CLK5C as test for diagnostic
	PWR2: Added CLK5C as test for diagnostic
Appendix A, Table 3 Power Mgt Module	PMM2: Tests for diagnostics changed to NA since this is a fault avoidance mechanism
	PMM3: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostics
	PMM5: Test for diagnostic changed to NA since it is a test for diagnostic itself
	PMM6: Updated diagnostic name to Power Domain Inactivity Monitor and added CLK5A, CLK5B and CLK5C as test for diagnostic
Appendix A, Table 3: Clock	CLK1 & CLK2: Removed DCC as test for diagnostic
	CLK3: Removed DCC and added CLK6 as test for diagnostic
	CLK4: Given the diagnostic is an external diagnostic, the test for diagnostic was updated as System Dependent
	CLK5A and CLK5B: Added CLK4 as a test for diagnostic.
	CLK5C:Given the diagnostic is an external diagnostic, the test for diagnostic was updated as System Dependent
	CLK6 and CLK7: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostics
	Added CLK8 - "Software test of DCC operation"
	Added CLK9 - "Software test of DWD operation"
	Added CLK10 - "Software test of DWWD operation"

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Table 9. SPNU575A Revisions (continued)

Location	Additions, Deletes, and Edits
Appendix A, Table 3: Reset	RST1: Given the diagnostic is an external diagnostic, the test for diagnostic was updated as System Dependent
	RST2, RST3, RST4, RST5: Tests for diagnostics changed to NA since this is a fault avoidance mechanism
	Removed RST6; adjust ID numbering accordingly (RST7 to RST6, RST8 to RST7)
	RST6 and RST7 (former RST7 and RST8): Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostics
	Added "RST8 - Software test for reset"
Appendix A, Table 3: System Control Module	SYS1: Tests for diagnostics changed to NA since this is a fault avoidance mechanism
	SYS2 and SYS3: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostics
	SYS4: Tests for diagnostics changed to NA since this is a fault avoidance mechanism
Appendix A, Table 3: Error Signaling Module	ESM1 and ESM2A, and ESM2B:Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostics
	ESM3: Tests for diagnostics changed to NA since this is a fault avoidance mechanism
Appendix A, Table 3: Cortex R5F CPU	CPU1: Removed CPU2A and CPU2B as a test for diagnostic
	CPU2A and CPU2B: Added CLK5C and CPU1 as test for diagnostic
	Removed CPU5A, CPU5B, and CPU5C
	Moved "Illegal operation and instruction trapping" from CPU6 to CPU5
	Moved CPU9 "Periodic software readback of static configuration registers" to CPU6
	CPU7: Added CPU2A and CPU2B as test for diagnostic
	CPU8 and CPU9: Test for diagnostics changed to NA since they are tests for diagnostics themselves
	Added CPU9 - "LBIST STC auto-coverage"
	Removed CPU10 "Information Redundancy Techniques" IDs adjusted accordingly (CPU11 becomes CPU10, etc)
	CPU10 and CPU11: Added RAM1, CPU15, CPU13, CPU1, CLK5C, and FLA as tests for diagnostics
	Added CPU13 "Software Test of PBIST" as test for diagnostic
	Added CPU14 "PBIST Auto-Coverage" as test for diagnostic
	Added CPU15 "Software Readback of Written Configuration (PBIST) as test for diagnostic
	Selection of Cache Scheme (former CPU14) removed as a test for diagnostic
Appendix A, Table 3: Primary Flash	FLA1: Added FLA10 and FLA11 as tests for diagnostic
	FLA1 and FLA2: Removed LBIST as a test for diagnostic
	FLA3: Added FLA10 and FLA11 as test for diagnostic; Removed Auto-Coverage and Software Test of ECC as tests for diagnostic
	FLA4: Tests for diagnostic updated to FLA9 and FLA12
	FLA5A and FLA5B: Added CLK5C, FLA9 and FLA14 as tests for diagnostic
	FLA6: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	FLA7: Removed CRC test and added Software Test of Sector Protection Mechanism as test for diagnostic
	FLA8 and FLA9: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added FLA10 - "Flash wrapper address diag mode 5 test"
	Added FLA11 - "Flash wrapper address diag mode 7"
	Added FLA12 - "Software test of parity logic"
	Added FLA13 - "Software test of flash sector protection logic"
	Added FLA14 - "Software test of hardware CRC"
	Added FLA15 - "CRC Auto-coverage"

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Table 9. SPNU575A Revisions (continued)

Location	Additions, Deletes, and Edits
Appendix A, Table 3: Flash EEPROM Emulation	FEE1: removed LBIST and added FEE15 and FEE16 as tests for diagnostic
	Removed former FEE2 "Hard Error Cache and Livelock; IDs adjusted accordingly
	FEE2A and FEE2B: Added FEE6, FEE13, and CLK5C as tests for diagnostic
	FEE3: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	FEE4: Added FEE12 as test for diagnostic
	FEE5 and FEE6: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	FEE7 moved from former FEE3: Added FEE2B, FEE15, and FEE16 as tests for diagnostic
	Added FEE12 - "Software test of flash sector protection logic"
	Added FEE13 - "Software Test of Hardware CRC"
	Added FEE14 - "CRC Auto-coverage"
	Added FEE15 - "Flash wrapper address diag mode 5 test"
	Added FEE16 - "Flash wrapper address diag mode 7"
Appendix A, Table 3: Primary SRAM	RAM1: Removed LBIST, ECC Auto-Coverage, and PBIST as test for diagnostic
	RAM2: Removed LBIST
	RAM3: removed CPU Lockstep and LBIST and added RAM16.
	RAM4: Removed CPULockstep, LBIST, and PBIST and added RAM11 and RAM13
	RAM5: Removed ECC and PBIST and added RAM17 as test for diagnostic
	RAM6: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	RAM7A and RAM7B: Added RAM14, CPU1, RAM11, CLK5C, FLA1, and RAM1 as tests for diagnostic
	RAM8: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	RAM9: Added RAM11, RAM18 and RAM19
	RAM10 and RAM11: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	RAM12: Test for diagnostics changed to NA since they are tests for diagnostics themselves
	Added RAM13 - "Software test of parity logic"
	Added RAM14 - "Software test of PBIST"
	Added RAM15 - "PBIST auto-coverage"
	Added RAM16 - "Software test of ECC profiler"
	Added RAM17 - "Redundant address decode self-test"
	Added RAM18 - "Software Test of Hardware CRC"
	Added RAM19 - "CRC Auto-coverage"
	RAM20: Changed ID from RAM13; Added RAM1 as test for diagnostic
Appendix A, Table 4: CPU Interconnect Subsystem	MEM2A, MEM2B, and MEM2C removed and ID numbering adjusted
	Moved "Periodic software readback of static configuration registers" from MEM7 to MEM4
	MEM5 and MEM6 moved to MEM11 and MEM12 respectively
	Moved "Software readback of written configuration" from MEM8 to MEM6
	Moved "Transmission Redundancy" from MEM6 to MEM7
	Moved MEM10 and MEM11 Boot time/Periodic Execution of interconnect self-test to MEM8A and MEM8B respectively
	MEM9 name changed from "Interconnect hardware checker" to "CPU Interconnect Hardware Checker"
	Added MEM10 "Timeout Monitoring on Bus Transactions"
	MEM3 through MEM9: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
Appendix A, Table 4: Peripheral Interconnect Subsystem	PER2A, PER2B, and PER2C removed and ID numbering adjusted
	Moved PER5 "Peripheral Interconnect New Memory Protection Unit (NMPU)" to PER2
	PER3: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic

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Table 9. SPNU575A Revisions (continued)

Location	Additions, Deletes, and Edits
	Added PER4 "Periodic Software Readback of Static Configuration Registers"
	PER5 and PER6 moved to PER11 and PER12 respectively
	Moved PER4A and PER4B "Boot Time/Periodic Software Test of Basic Functionality Including Error Tests" to PER5A and PER5B respectively; Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added PER6 "Software Readback of Written Configuration"
	Added PER7 "Transmission Redundancy"
Appendix A, Table 4: Peripheral Central Resource 1 (PCR1)	P1T2A, P1T2B, and P1T2C removed and ID numbering adjusted
	Moved and Merged "Bus master filtering (slave memory protection)" and "PCR access management" (P1T5/P1T6) to P1T2 "PCR Access Management: Protection Mode and MasterID Filtering"
	P1T3: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Moved P1T7 "Periodic Software Readback of Static Configuration Registers" to P1T4; Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Moved P1T4A and P1T4B ""Boot Time/Periodic Software Test of Basic Functionality Including Error Tests" to P1T5A and P1T5B respectively; Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	P1T6: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added P1T7 "Transmission Redundancy"
Appendix A, Table 4: Peripheral Central Resource 2 (PCR2)	P2T2A, P2T2B, and P2T2C removed and ID numbering adjusted
	Moved and Merged "Bus master filtering (slave memory protection)" and "PCR access management" (P2T5/P2T6) to P2T2 "PCR Access Management: Protection Mode and MasterID Filtering"
	P2T3: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Moved P2T7 "Periodic Software Readback of Static Configuration Registers" to P2T4; Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Moved P2T4A and P2T4B ""Boot Time/Periodic Software Test of Basic Functionality Including Error Tests" to P2T5A and P2T5B respectively; Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	P2T6: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added P2T7 "Transmission Redundancy"
Appendix A, Table 4: Peripheral Central Resource 3 (PCR3)	P3T2A, P3T2B, and P3T2C removed and ID numbering adjusted
	Moved and Merged "Bus master filtering (slave memory protection)" and "PCR access management" (P3T5/P3T6) to P3T2 "PCR Access Management: Protection Mode and MasterID Filtering"
	P3T3: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Moved P3T7 "Periodic Software Readback of Static Configuration Registers" to P3T4; Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Moved P3T4A and P3T4B ""Boot Time/Periodic Software Test of Basic Functionality Including Error Tests" to P3T5A and P3T5B respectively; Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	P3T6: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added P3T7 "Transmission Redundancy"
Appendix A, Table 3: EFuse Static Configuration	EFU2 updated test for diag to EFU6
	EFU3 and EFU4: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added EFU5 - "Autoload self-test auto-coverage"
	Added EFU6 - "EFuse ECC logic self-test"
Appendix A, Table 3: One Time Programmable Flash Static Configuration	Removed OTP auto-load (former OTP1) and adjusted IDs to accommodate new Safety Diagnostics
	OTP2 OTP ECC moved to OTP1; Added CPU1 and OTP14 and OTP15 as tests for diagnostics

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Table 9. SPNU575A Revisions (continued)

Location	Additions, Deletes, and Edits
	OTP3 "Periodic Software Readback of Static Configuration Registers" and OTP4 "Software Readback of Written Configuration" moved to OTP2 and OTP3 respectively; Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added OTP4A and OTP4B Boot Time/Periodic Hardware CRC Check of OTP Contents
	Added OTP5 "Bit Multiplexing in Flash Memory Array"
	Added OTP6 "Flash Sector Protection
	Added OTP11, OTP12, OTP13, OTP14, OTP15 as tests for diagnostics
Appendix A, Table 3: Input/Output (I/O) Multiplexing Module	IOM1 and IOM2: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	IOM3: Removed "Software Test of Function including error trapping"; Added CLK5A, CLK5B, CLK5C, CPU1, FLA1, and RAM1 as tests for diagnostic
	IOM4, IOM5, and IOM6: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
Appendix A, Table 3: Vectored Interrupt Module	VIM1: Removed PBIST and added VIM7, VIM8, and VIM9 as tests for diagnostic
	VIM2A and VIM2B: Added VIM7, VIM12, CPU1, RAM1 and FLA1 as tests for diagnostic
	VIM3: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	VIM4: Removed PBIST; Added VIM7, VIM10, and VIM11 as tests for diagnostic
	VIM5A ,VIM5B:, VIM6 and VIM7: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Removed VIM8A, VIM8B, and VIM8C
	Added VIM8 - "Software test of ECC logic"
	Added VIM9 - "PBIST test of ECC bit memory"
	Added VIM10 - "Software test of hardware CRC"
	Added VIM11 - "CRC auto-coverage"
	Added VIM12 - "Software test of PBIST"
	Added VIM13 - "PBIST auto-coverage"
	VIM14 changed to "VIM Lockstep Compare" from !"oo2 Comparison of VIM
	Added VIM15 - "Lockstep Compare Self-Test"
Appendix A, Table 3: Real Time Interrupt Operating System Timer	RTI1: Removed PMU cycle counter as a test for diagnostic
	Removed RTI2A, RTI2B, and RTI2C
	Moved "Periodic software readback of static configuration registers" from RTI3 to RTI2
	Moved "Software readback of written configuration" from RTI4 to RTI3
	RTi2 and RTI3: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
Appendix A, Table 3: Direct Memory Access	DMA2: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	DMA3: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	DMA4 Added DMA10 and DMA12 as tests for diagnostic
	DMA5A and DMA5B: Added DMA10, DMA16, CPU1, CLK5C, FLA1, and RAM1 as tests for diagnostic
	DMA6: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	DMA7: Removed PBIST; Added DMA10, DMA14, and DMA13 as tests for diagnostic
	DMA8, DMA9A, DMA9B, DMA10: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	DMA12 "Peripheral Interconnect New Memory Protection Unit (NMPU)" moved to DMA20
	Added DMA11 - "Transmission Redundancy"
	Added DMA12 - "Software test of parity logic"
	Added DMA13 - "PBIST test of parity bit memory"
	Added DMA14 - "Software test of hardware CRC"

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Table 9. SPNU575A Revisions (continued)

Location	Additions, Deletes, and Edits
	Added DMA15 - "CRC auto-coverage"
	Added DMA16 - "Software test of PBIST"
	Added DMA17 - "PBIST auto-coverage"
	Added DMA18 - "Software test of MPU functionality"
	DMA19: Test for diagnostic changed to NA since this is a fault avoidance mechanism
Appendix A, Table 3: High-End Timer	HET2: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	HET3: Removed DC auto-coverage and added HET20 and HET11 as tests for diagnostic
	HET4, HET5A, and HET5B: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	HET6: Added HET11 and HET13 as tests for diagnostics
	HEt7A and HET7B: Added HET11 and HET17 as tests for diagnostics
	HET8: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	HET9: Remove PBIST; Added HET11, HET5, and HET16 as tests for diagnostic
	HET10 and HET11: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	HET12A and HET12B moved to HEt21A and HEt21B respectively. Name changed to Boot Time/Periodic Execution of HET LBIST STC
	Added HET12 - "Transmission redundancy for transfer unit"
	Added HET13 - "Software test of parity logic"
	Added HET14 - "PBIST test of parity bit memory"
	Added HET15 - "Software test of hardware CRC"
	Added HET16 - "CRC auto-coverage"
	Added HET17 - "Software test of PBIST"
	Added HET18 - "PBIST auto-coverage"
	Added HET19 - "Software test of MPU functionality"
	Added HET20 - "Software test of DCC functionality"
Appendix A, Table 3: Multi-Buffered Analog to Digital Converter	ADC1, ADC2A, ADC2B: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	ADC3: Removed ADC Calibration and Self-Test; Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	ADC4: Added ADC9 as a test for diagnostic
	ADC5A and ADC5B: Added ADC9, ADC14, ADC15, CLK5C, CPU1, RAm1, and FLA1
	ADC6: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	ADC7: Removed PBIST; added ADC9, ADC12, and ADC13 as tests for diagnostic
	ADC8 and ADC9: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added ADC10 - "Software test of parity logic"
	Added ADC11 - "PBIST test of parity bit memory"
	Added ADC12 - "Software test of hardware CRC"
	Added ADC13 - "CRC auto-coverage"
	Added ADC14 - "Software test of PBIST"
	Added ADC15 - "PBIST auto-coverage"
Appendix A, Table 3: Enhanced Pulse Width Modulators	PWM1A, PWM1B, PWM2: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	PWM3: Added CLK5A, CLK5B, CLK5C, FLA1, RAM1, CAP1A, CAP1B, HET5A, and HET5B as tests for diagnostic
	PWM4 and PWM5: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
Appendix A, Table 3: Enhanced Capture	CAP1A, CAP1B, CAP2, CAP3, and CAP4: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic

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Table 9. SPNU575A Revisions (continued)

Location	Additions, Deletes, and Edits
Appendix A, Table 3: Enhanced Quadrature Encoder Pulse	QEP1A, QEP1B, QEP2, QEP3, and QEP4: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added QEP5 "Quadrature Watchdog"
	Added QEP6 "QEP6 Software Test of Quadrature Watchdog Functionality"
Appendix A, Table 3: Multi-Buffered Serial Peripheral Interface	MSP1A and MSP1B: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	MSP2: Removed CPu1 and added MSP9 as test for diagnostic
	MSP3:Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	MSP4: Added MSP9 and MSP14 as tests for diagnostic
	MSP5A and MSP5B:Added MSP9, MSP20, CLK5C, CPU1, FLA1, and RAM1 as tests for diagnostic
	MSP6: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	MSP7: Removed PBIST; Added MSP9, MSP18 and MSP19 as tests for diagnostic
	MSP8 and MSP9: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added MSP10 - "Transmission redundancy"
	Added MSP11 - "Data overrun detection"
	Added MSP12 - "Bit error detection"
	Added MSP13 - "Slave desync detection"
	Added MSP14 - "Slave timeout detection"
	Added MSP15 - "Data length error detection"
	Added MSP16 - "Software test of parity logic"
	Added MSP17 - "PBIST test of parity bit memory"
	Added MSP18 - "Software test of Hardware CRC"
	Added MSP19 - "CRC auto-coverage"
	Added MSP20 - "Software test of PBIST"
	Added MSP21 - "PBIST auto-coverage"
Appendix A, Table 3: Inter-Integrated Circuit	IIC1A, IIC1B, IIC2, IIC3, and IIC4: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added IIC5 - "Transmission Redundancy"
Appendix A, Table 3: Serial Communications Interface	SCI1A, SCI1B, SCI2, SCI3, and SCI4: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added SCI5 - "Transmission redundancy"
	Added SCI6 - "Overrun Error Detection"
	Added SCI7 - "Frame Error Detection"
	Added SCI8 - "Bit Error Detection"
	Added SCI9 - "Parity in message"
Appendix A, Table 3: Local Interconnect Network	LIN1A, LIN1B, LIN2, LIN3, and LIN4: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added LIN6 - "Overrun Error Detection"
	Added LIN7 - "Frame Error Detection"
	Added LIN8 - "Physical Bus Error Detection"
	Added LIN9 - "No-Response Error Detection"
	Added LIN10 - "Bit Error Detection"
	Added LIN11 - "Checksum Error Detection"
	Added LIN12 - "Parity in Message"
Appendix A, Table 3: Controller Area Network	CAN1A, CAN1B, and CAN2: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	CAN3: Added CAN8 and CAN15 as tests for diagnostic

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Table 9. SPNU575A Revisions (continued)

Location	Additions, Deletes, and Edits
	CAN4A and CAN4B: Added CAN8, CAN19, CLK5C, CPU1, FLA1, and RAM1 as tests for diagnostic
	CAN5: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	CAN6: Removed PBIST; Added CAN8, CAN17, and CAN18 as tests for diagnostic
	CAN7 and CAN8: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added CAN9 - "Transmission redundancy"
	Added CAN10 - "Stuff error detection"
	Added CAN11 - "Form error detection"
	Added CAN12 - "Acknowledge Error Detection"
	Added CAN13 - "Bit error detection"
	Added CAN14 - "CAN protocol CRC in message"
	Added CAN15 - "Software test of parity logic"
	Added CAN16 - "PBIST test of parity bit memory"
	Added CAN17 - "Software test of hardware CRC"
	Added CAN18 - "CRC auto-coverage"
	Added CAN19 - "Software test of PBIST"
	Added CAN20 - "PBIST auto-coverage"
Appendix A, Table 3: General Purpose Input/Output	GIO1A, GIO1B, GIO2, GIO3, and GIO4: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
Appendix A, Table 3: Ethernet	ETH1: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	ETH2A, ETH2B, and ETH3: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	ETH4A and ETH4B: Added ETH8, ETH15, CPU1, RAM1, and FLA1 as tests for diagnostic
	ETH5: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	ETH6: removed PBIST; Added ETH8, ETH13 and ETH14 as tests for diagnostic
	ETH7 and ETH8: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	ETH9 "Peripheral Interconnect New Memory Protection Unit (NMPU)" moved to ETH17
	Added ETH9 - "Transmission Redundancy"
	Added ETH10 - "CRC in message"
	Added ETH11 - "Alignment Error Detection"
	Added ETH12 - "Physical Layer Fault"
	Added ETH13 - "Software test of hardware CRC"
	Added ETH14 - "CRC auto-coverage"
	Added ETH15 - Software test of PBIST"
	Added ETH16 - "PBIST auto-coverage"
	Added ETH18 - "Software test of New Memory Protection Unit (NMPU) Function"
Appendix A, Table 3: External Memory Interface	EMF1: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	EMF2A and EMF2B: Added EMF4 and EMF6 as tests for diagnostic
	EMF3 and EMF4: Added CLK5A, CLK5B, CLK5C, FLA1, and RAM1 as tests for diagnostic
	Added EMF5 - "Transmission Redundancy"
	Added EMF6 - "Software Test of Hardware CRC"
	Added EMF7 - "CRC Auto-coverage"
Appendix A, Table 3: Joint Technical Action Group Debug/Trace/Calibration	JTG1 and JTG2: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	Removed JTG3A - "Internal Watchdog - DWD"
	Removed JTG3B - "Internal Watchdog - DWWD"
	Removed JTG3C - "External Watchdog"

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Table 9. SPNU575A Revisions (continued)

Location	Additions, Deletes, and Edits
Appendix A, Table 3: Cortex-R5F Central Processing Unit Debug and Trace	Removed DBG1 "Hardware disable of JTAG port"
	Removed DBG2 "Lockout of JTAG access using AJSM"
	DBG3
	Moved DBG3 - "Use MPUs to block access to memory-mapped debug" to DBG1
	Moved DBG4 - "Use of CoreSight debug logic key enable scheme" to DBG2
	DBG1 and DBG2: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	Removed DBG5A - "Internal Watchdog - DWD"
	Removed DBG5B - "Internal Watchdog - DWWD"
	Removed DBG5C - "External Watchdog"
Appendix A, Table 3: Data Modification Module	Removed DMM1 "Hardware disable of JTAG port"
	Removed DMM2 "Lockout of JTAG access using AJSM"
	Removed DMM3 "Use of MPUs to Block Access to Memory-Mapped Debug"
	DMM4 "Disable DMM PIN Interface" renumbered DMM1
	DMM1: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	Removed DMM5A - "Internal Watchdog - DWD"
	Removed DMM5B - "Internal Watchdog - DWWD"
	Removed DMM5C - "External Watchdog"
Appendix A, Table 3: RAM Trace Port	Removed RTP1 "Hardware disable of JTAG port"
	Removed RTP2 "Lockout of JTAG access using AJSM"
	Removed RTP3 "Use of MPUs to Block Access to Memory-Mapped Debug"
	RTP4 "Disable RTP PIN Interface" renumbered RTP1
	RTP1: Test for diagnostic changed to NA since this is a fault avoidance mechanism
	Removed RTP5A - "Internal Watchdog - DWD"
	Removed RTP5B - "Internal Watchdog - DWWD"
	Removed RTP5C - "External Watchdog"
Appendix A, Table 3	Added Device Partitions for "Error Profiling Controller (EPC)" and "Temperature Sensor" and associated table entries
Appendix A, Table 3: Parameter Overlay Module	- This device partition was removed from the safety measures table in its entirety.
	Removed POM1 - "Hardware disable of JTAG port"
	Removed POM2 - "Lockout of JTAG access using AJSM"
	Removed POM3 - "Use MPUs to block access to memory-mapped debug"
Section 4.1	Changed title of Section 4.1
Section 5	Changed formatting to simplify diagnostic lists
Throughout document	Added clarifications and updated formatting in various sections
Throughout document	Added various additional informational sections to support existing information
Draft Updates From Assessor Review - June 2016 Revision	
Throughout document	Updated naming of interconnect subsystems/bridges for consistency and clarity. The following naming convention will be used through out the document: CPU Interconnect Subsystem Peripheral Interconnect Subsystem PCR1 PCR2 PCR3 Reference Architecture section for additional definition of each of these elements.

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Table 9. SPNU575A Revisions (continued)

Location	Additions, Deletes, and Edits
Appendix A, Table 3: Input/Output (I/O) Multiplexing Module	IOM3: Added IOM5A and IOM5B as tests for diagnostics.
Section 6.18 Section 7.121 Appendix A, Table 3: Input/Output (I/O) Multiplexing Module	Updated the Safety Feature/Diagnostic References/Names to the Boot Time and Periodic Software Test of Function Using I/O Loopback by adding "Including Error Test" in the IOMM list of Safety Mechanisms.
Section 7.121	Updated description of the safety diagnostic to include test of error trapping as a tested feature of the IOMM module such that it can serve as a test for diagnostic for the Error Trapping Safety Diagnostic within the module.
Draft Updates From Assessor Review - September 2016 Revision	
Throughout	Updates to Safety Feature/Diagnostic names to better align with the FMEDA document.
	Updated link to correctly point to the ARM Cortex-R5F TRM located on the ARM website http://infocenter.arm.com/help/topic/com.arm.doc.ddi0460d/index.html
Figure 5	Removed the block "Network Peripheral" from the diagram.
Section 6.41	Removes Online Profiling Using PMU, Illegal Operation and Instruction Trapping from the list of Safety Features/Diagnostics. Moved Flash ECC into Safety Features/Diagnostic list. Duplicated Lockstep Compare, Internal and External Watchdogs, and Flash and RAM ECC diagnostics under latent fault detection as these are also tests for diagnostics for the temperature sensor feature.
Appendix A, Table 3: Primary SRAM Element	RAM20 test for diagnostics, usage, Test Execution Time, Action on detected Fault, Error Reporting Time updated to reflect a fault avoidance mechanism rather than a Diagnostic.
Appendix A, Table 3: High-End Timer (N2HET) Including HET Transfer Unit (HTU) Element	HET21A and HET21B Possible Tests for Diagnostics updated to remove CLK5A, CLK5B, CLK5C, CPU1, FLA1 and RAM1 and replace all of these with LBIST Auto-Coverage (HET22 newly defined).
Appendix A, Table 3: High-End Timer (N2HET) Including HET Transfer Unit (HTU) Element	Added HEt22 LBIST Auto-Coverage
Appendix A, Table 3: Serial Communication Interface (SCI) Element	Updated SCI9 Possible Tests for Diagnostics to SCI2 Information Redundancy Techniques
Appendix A, Table 3: Controller Area Network (DCAN) Element	CAN3 - Added CAN2 Information Redundancy Including End to End Safing as Possible Test for Diagnostic

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